UC1843B-SP total ionizing dose (TID) radiation report

ABSTRACT

This report discusses the results of the Total Ionizing Dose (TID) testing for the QML Class V certified Texas Instruments UC1843B-SP. These tests are done to determine TID effects under low dose rate (LDR) up to 100 krad(Si). The results show that all samples are fully functional after being exposed up to 100 krad(Si).

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1 Device Information

1.1 Product Description

The UC1843B-SP control IC is a pin-for-pin compatible improved version of the UC1843A-SP. This device has improved features providing the necessary characteristics to control current-mode switched-mode power supplies. Start-up current is specified to be less than 0.5 mA and oscillator discharge is trimmed to 8.3 mA. During UVLO, the output stage can sink at least 10 mA at less than 1.2 V for VCC over 5 V. The devices are specified over the extended operating temperature range of –55°C to 125°C and are offered in an 10-pin CFP package.

1.2 Device Details

Table 1 lists the device information used in the initial TID LDR characterization.

Table 1. Device and Exposure Details

TID LDR DETAILS: UP TO 100 krad(Si)	
TI Device Number	UC1843B-SP
Package	HKU
Technology	JI1
Quantity Tested	67
Lot Accept/Reject	Devices functional up to 100 krad(Si)
LDR Radiation Facility	VPT Rad and Cobham
LDR Dose Level	3 krad(Si), 10 krad(Si), 30 krad(Si), 50 krad(Si), 100 krad(Si)
LDR Dose Rate	0.01 rad(Si)/s
LDR Radiation Source	^{60}Co gamma cell

2 Total Dose Test Setup

2.1 Test Overview

The UC1843B-SP is tested according to MIL-STD-883, Test Method 1019.9. For this testing, Condition D is used. For this test, the product is irradiated up to the target radiation level and then put through full electrical parametric testing on the production Automated Test Equipment (ATE). The device is functional and passes all parametric tests.

2.2 Test Description and Facilities

The UC1843B-SP LDR exposure is performed on biased and unbiased devices in a ^{60}Co gamma cell under a 10-mrad(Si)/s exposure rate. The dose rate of the irradiator used in the exposure ranges from < 10 mrad(Si)/s to a maximum of approximately 65 rad(Si)/s, determined by the distance from the source. For the LDR (10 mrad(Si)/s) exposure, the test box is positioned approximately 2 m from the source. The exposure boards are housed in a lead-aluminum box (as specified in MIL-STD-883 TM 1019.9) to harden the gamma spectrum and minimize dose enhancement effects. The irradiator calibration is maintained by Logmire Laboratories using Thermoluminescence Dosimeters (TLDs) traceable to the National Institute of Standards and Technology (NIST) and the dosimetry is verified using TLDs prior to the radiation exposures. After exposure, the devices are returned to TI Dallas for a full post radiation electrical evaluation using Texas Instruments production Automated Test Equipment (ATE). ATE guard band test limits are set within SMD electrical limits to ensure a minimum Cpk and test error margin based on initial qualification and characterization data.

2.3 Test Setup Details

The devices under LDR exposure are tested in both biased and unbiased conditions as described in the following two sections.

2.3.1 Unbiased

For the unbiased LDR conditions, the exposure is performed with all pins grounded.

2.3.2 Biased

Figure 1 shows the bias diagram used in biased LDR testing.

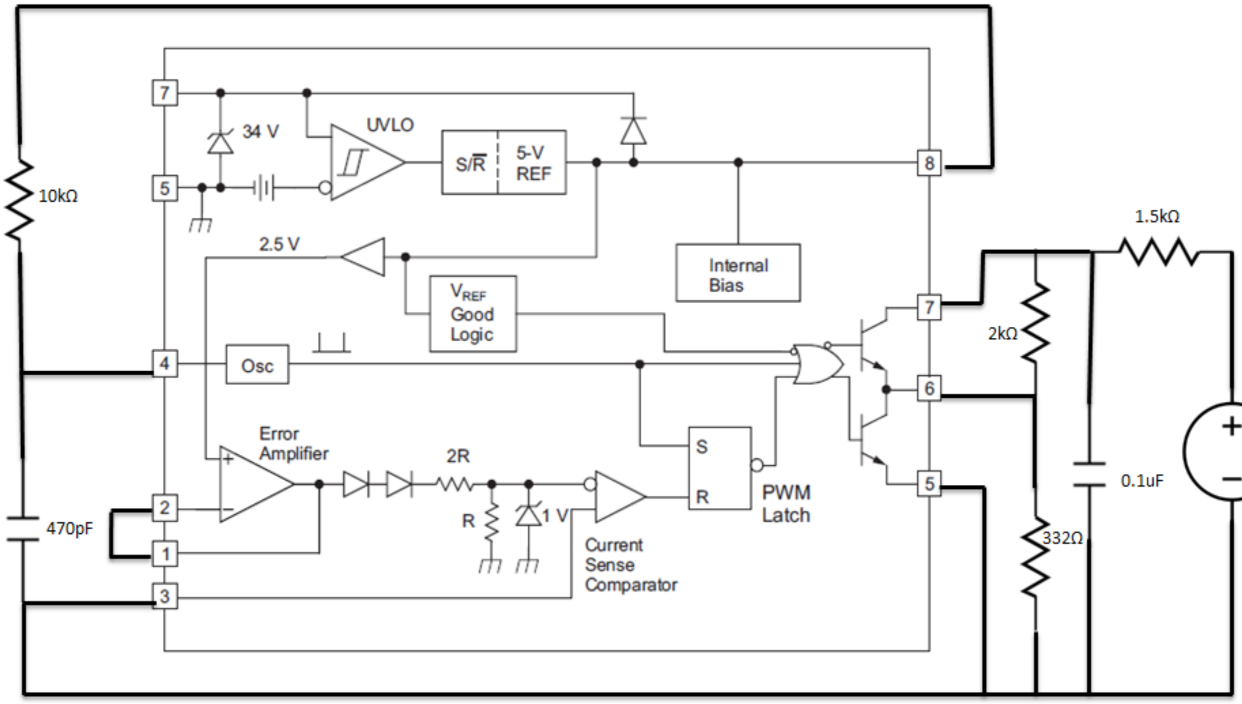


Figure 1. Bias Diagram

2.4 Test Configuration and Conditions

LDR devices are stressed at 3 krad(Si) ,10 krad(Si) ,30 krad(Si) ,50 krad(Si) and 100 krad(Si).

LDR UNBIASED DEVICE INFORMATION				
3 krad(Si)	**10 krad(Si)**	**30 krad(Si)**	**50 krad(Si)**	**100 krad(Si)**
1, 2, 3, 5, 7	8, 11, 14, 15, 19	22, 23, 31, 37, 42	43, 45, 48, 49, 50	69, 70, 71, 74, 76, 81, 82, 85, 94, 95, 99, 103, 109, 110, 112, 115, 117, 118, 122, 125, 126, 129

LDR BIASED DEVICE INFORMATION				
3 krad(Si)	**10 krad(Si)**	**30 krad(Si)**	**50 krad(Si)**	**100 krad(Si)**
135, 135, 138, 139, 143	144, 145, 146, 149, 150	151, 153, 154, 155, 156	173, 174, 175, 183, 187	191, 195, 199, 203, 207

3 TID Characterization Results

Devices are functional after being exposed to 100 krad(Si). Table 2 lists the full results.

3.1 Device Spec Table

Table 2 lists the device data sheet along with the corresponding ATE test that accompanies it.

Table 2. UC1843B-SP Spec Table

PARAMETER	TEST CONDITION	MIN	TYP	MAX	UNIT	TEST NUMBER
REFERENCE						
Output voltage	T_J = 25°C, I_O = 1 mA	4.9	5	5.1	V	1010.1, 1010.2
Line regulation	V_{IN} = 12 to 25 V		6	20	mV	1010.3
Load regulation	I_O = 1 to 20 mA		6	25	mV	1010.4
Short-circuit output current		–30	–100	–180	mA	1010.6
OSCILLATOR						
Initial accuracy	T_J = 25°C	47	52	57	kHz	1015.1, 1015.2
Voltage stability	V_{CC} = 12 to 25 V		0.2%	1%		1015.3
Discharge current	V pin 4 = 2 V	7.5		8.8	mA	1015.7
ERROR AMPLIFIER						
Input voltage	V_{Comp} = 2.5 V	2.45	2.50	2.55	V	1020.1
Input bias current			–0.3	–1	µA	1020.6, 1020.7, 1020.8
Open-loop voltage gain	V_O = 2 to 4 V	65	90		dB	1020.9
PSRR	V_{CC} = 12 to 25 V	60	70		dB	1020.10
Output sink current	V_{FB} = 2.7 V, V_{Comp} = 1.1 V	2	6		mA	1020.5
Output source current	V_{FB} = 2.3 V, V_{Comp} = 5 V	–0.5	–0.8		mA	1020.4
High-level output voltage	V_{FB} = 2.3 V, R_L = 15 kΩ to ground	5	6		V	1020.2
Low-level output voltage	V_{FB} = 2.7 V, R_L = 15 kΩ to V_{REF}		0.7	1.1	V	1020.3
CURRENT SENSE						
Gain		2.85	3	3.15	V/V	1025.2
Maximum input signal	V_{Comp} = 5 V	0.9	1	1.1	V	1025.3
Input bias current			–2	–10	µA	1025.1
Delay to output	V_{ISENSE} = 0 to 2 V		150	300	ns	1025.4
OUTPUT						
Output low-level voltage	I_{SINK} = 20 mA		0.1	0.4	V	1030.6
	I_{SINK} = 200 mA		1.5	2.2		1030.7
Output high-level voltage	I_{SOURCE} = –20 mA	13	13.5		V	1030.1
	I_{SOURCE} = –200 mA	12	13.5			1030.2
Rise time	C_L = 1 nF, T_J = 25°C		50	150	ns	1030.9
Fall time	C_L = 1 nF, T_J = 25°C		50	150	ns	1030.10
UVLO saturation	V_{CC} = 5 V, I_{SINK} = 10 mA		0.7	1.2	V	1030.5
UNDERVOLTAGE LOCKOUT						
Start threshold		7.8	8.4	9	V	1035.1
Minimum operation voltage after turn on		7	7.6	8.2	V	1035.2
PWM						
Maximum duty cycle		94%	96%	100%		1030.11, 1030.12
Minimum duty cycle				0%		1030.13
TOTAL STANDBY CURRENT						
Start-up current			0.3	0.5	mA	1005.1

Table 2. UC1843B-SP Spec Table (continued)

PARAMETER	TEST CONDITION	MIN	TYP	MAX	UNIT	TEST NUMBER
Operating supply current	$V_{FB} = V_{ISENSE} = 0$ V		11	17	mA	1005.2, 1005.3
V_{CC} Zener voltage	$I_{CC} = 25$ mA	30	34		V	1035.4

4 Applicable and Reference Documents

4.1 Applicable Documents

Texas Instruments, *UC1843B-SP radiation hardened, Current-Mode PWM Controller data sheet*

Texas Instruments, *Single-event effects test report for UC1843B-SP current sense amplifier radiation report*

4.2 Reference Documents

Texas Instruments total ionizing dose radiation (total dose) test procedure follows the standards put forth in MIL-STD-883 TM 1019. The document can be found at the DLA website.

UC1843B-SP (5962R8670412V9A/5962R8670412VYC) radiation report

UC1843B-SP QML Class V, Radiation Hardened Current-Mode PWM Controller

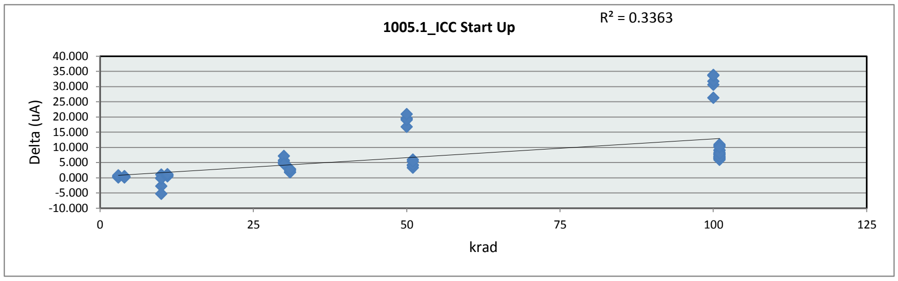
The UC1843B-SP control IC is a radiation hardened pin-for-pin compatible version of the UC1843A-SP. Providing the necessary characteristics to control current-mode switched-mode power supplies, this device has improved features. Start-up current is specified to be less than 0.5 mA and oscillator discharge is trimmed to 8.3 mA. During UVLO, the output stage can sink at least 10 mA at less than 1.2 V for VCC over 5 V.

Full Device Name:	**5962R8670412VYC/5962R8670709VYC**
Fablot:	**8068288**
Technology:	**J1 Bipolar**
Wafer#	**#9**
Assy Lot	**8005414**
LDR plan	**Sample size and details below**

TID Report
Device Name

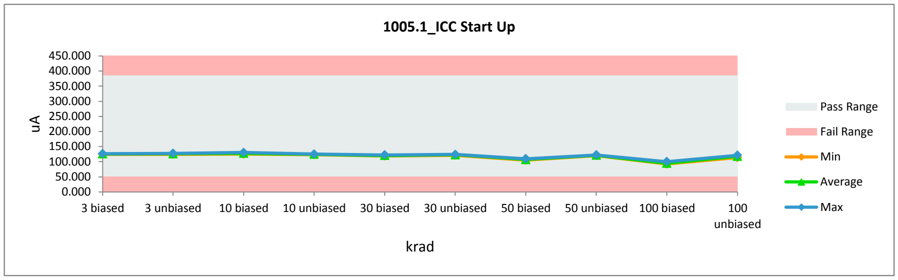
	1005.1_ICC Start Up	
Test Site	1	
Tester	ETS	
Test Number	1	
Unit	uA	uA
Max Limit	384	384
Min Limit	50	50

krad	Serial #	Pre	Post	Delta
3	135	127.162	126.720	0.442
3	136	124.768	124.441	0.326
3	138	126.611	126.164	0.447
3	139	124.984	124.921	0.063
3	143	126.128	125.377	0.751
4	1	124.896	124.710	0.187
4	2	126.391	126.087	0.304
4	3	124.874	124.378	0.496
4	5	127.768	127.598	0.170
4	7	127.376	127.288	0.088
10	144	124.965	127.752	-2.787
10	145	125.042	130.346	-5.305
10	146	126.317	126.405	-0.088
10	149	126.419	125.420	0.998
10	150	127.340	127.576	-0.236
11	8	125.706	125.028	0.677
11	11	124.444	123.500	0.944
11	14	125.426	125.006	0.420
11	15	124.534	123.725	0.809
11	19	125.722	124.614	1.108
30	151	126.128	121.025	5.103
30	153	125.066	120.088	4.979
30	154	124.713	119.001	5.711
30	155	126.847	119.734	7.113
30	156	127.011	122.455	4.557
31	22	125.086	122.730	2.356
31	23	124.411	122.650	1.761
31	31	126.869	124.008	2.861
31	37	125.368	123.511	1.857
31	42	124.172	121.471	2.702
50	173	126.386	109.662	16.724
50	174	126.962	107.577	19.385
50	175	125.782	106.258	19.525
50	183	124.825	105.789	19.036
50	187	125.621	104.727	20.893
51	43	126.410	122.430	3.981
51	45	126.608	120.669	5.939
51	48	125.154	121.870	3.284
51	49	125.174	120.965	4.208
51	50	125.807	120.408	5.399
100	191	126.386	100.086	26.300
100	195	126.962	93.138	33.823
100	199	125.782	95.201	30.581
100	203	124.825	93.097	31.728
100	207	125.621	91.995	33.626
101	69	125.700	116.812	8.888
101	70	123.432	115.814	7.618
101	71	125.648	115.092	10.556
101	74	124.466	117.786	6.680
101	76	123.893	115.635	8.257
101	81	124.669	117.684	6.984
101	82	125.431	116.313	9.118
101	85	127.475	121.236	6.238
101	94	125.516	118.543	6.974
101	95	125.656	118.943	6.713
101	99	126.243	119.832	6.411
101	103	124.392	114.009	10.383
101	109	124.578	116.576	8.002
101	110	125.856	114.947	10.910
101	112	126.413	118.784	7.629
101	115	125.171	117.687	7.484
101	117	124.142	117.780	6.362
101	118	123.629	117.457	6.173
101	122	124.290	118.389	5.901
101	125	126.314	119.462	6.853
101	126	127.236	119.256	7.980
101	129	125.977	115.948	10.029
	Max	127.768	130.346	33.823
	Average	125.627	118.382	7.245
	Min	123.432	91.995	-5.305
	Std Dev	1.019	8.672	8.666



	1005.1_ICC Start Up	
Test Site	1	
Tester	ETS	
Test Number	1	
Max Limit	384	uA
Min Limit	50	uA

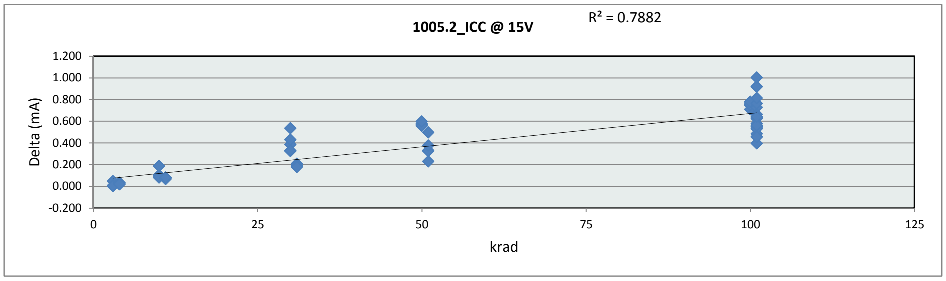
krad	3 biased	3 unbiased	10 biased	10 unbiased	30 biased	30 unbiased	50 biased	50 unbiased	100 biased	100 unbiased
LL	50.000	50.000	50.000	50.000	50.000	50.000	50.000	50.000	50.000	50.000
Min	124.441	124.378	125.420	123.500	119.001	121.471	104.727	120.408	91.995	114.009
Average	125.525	126.012	127.500	124.375	120.461	122.874	106.803	121.269	94.703	117.454
Max	126.721	127.598	130.347	125.028	122.455	124.008	109.662	122.430	100.086	121.236
UL	384.000	384.000	384.000	384.000	384.000	384.000	384.000	384.000	384.000	384.000



TID Report
Device Name

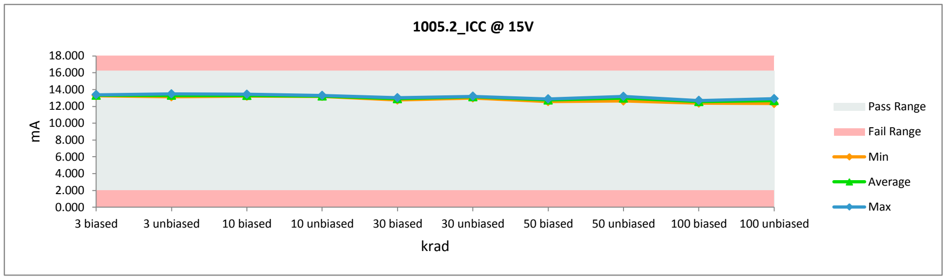
	1005.2_ICC @ 15V	
Test Site		
Tester		
Test Number		
Unit	mA	mA
Max Limit	16.2	16.2
Min Limit	2	2

krad	Serial #	Pre	Post	Delta
3	135	13.304	13.301	0.003
3	136	13.291	13.291	0.000
3	138	13.436	13.390	0.046
3	139	13.275	13.270	0.005
3	143	13.363	13.360	0.003
4	1	13.366	13.345	0.021
4	2	13.330	13.297	0.033
4	3	13.494	13.477	0.017
4	5	13.165	13.135	0.030
4	7	13.337	13.318	0.019
10	144	13.396	13.293	0.103
10	145	13.402	13.310	0.092
10	146	13.521	13.441	0.080
10	149	13.346	13.259	0.087
10	150	13.396	13.210	0.186
11	8	13.317	13.240	0.077
11	11	13.287	13.208	0.079
11	14	13.376	13.301	0.075
11	15	13.249	13.183	0.066
11	19	13.297	13.217	0.081
30	151	13.233	12.908	0.324
30	153	13.406	13.023	0.384
30	154	13.403	12.976	0.428
30	155	13.289	12.755	0.534
30	156	13.193	12.864	0.328
31	22	13.215	13.008	0.207
31	23	13.384	13.198	0.186
31	31	13.355	13.172	0.183
31	37	13.362	13.170	0.193
31	42	13.330	13.153	0.177
50	173	13.252	12.688	0.564
50	174	13.373	12.798	0.575
50	175	13.418	12.852	0.566
50	183	13.450	12.894	0.557
50	187	13.159	12.563	0.596
51	43	13.398	13.069	0.329
51	45	13.132	12.637	0.496
51	48	13.423	13.195	0.228
51	49	13.461	13.137	0.324
51	50	13.261	12.885	0.376
100	191	13.252	12.545	0.708
100	195	13.373	12.606	0.767
100	199	13.418	12.673	0.745
100	203	13.450	12.698	0.753
100	207	13.159	12.380	0.779
101	69	13.418	12.690	0.728
101	70	13.156	12.611	0.545
101	71	13.294	12.376	0.919
101	74	13.280	12.733	0.547
101	76	13.273	12.610	0.663
101	81	13.324	12.841	0.483
101	82	13.274	12.510	0.764
101	85	13.284	12.749	0.535
101	94	13.318	12.695	0.624
101	95	13.416	12.863	0.552
101	99	13.346	12.769	0.576
101	103	13.448	12.531	0.917
101	109	13.345	12.708	0.637
101	110	13.348	12.346	1.002
101	112	13.225	12.594	0.630
101	115	13.361	12.830	0.530
101	117	13.189	12.793	0.395
101	118	13.282	12.826	0.456
101	122	13.369	12.915	0.453
101	125	13.344	12.783	0.561
101	126	13.323	12.683	0.640
101	129	13.387	12.574	0.813
	Max	13.521	13.477	1.002
	Average	13.330	12.936	0.394
	Min	13.132	12.346	0.000
	Std Dev	0.087	0.301	0.282



	1005.2_ICC @ 15V	
Test Site		
Tester		
Test Number		
Max Limit	16.2	mA
Min Limit	2	mA

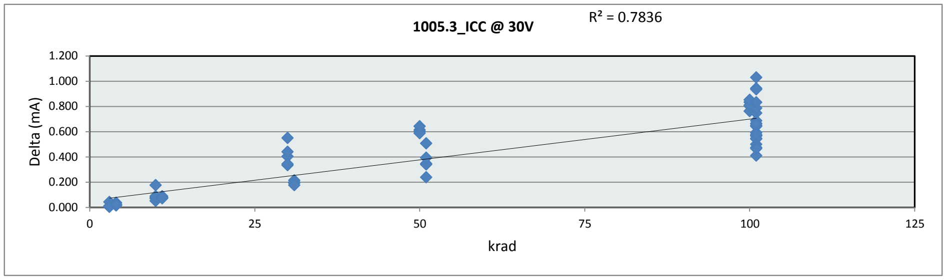
krad	3 biased	3 unbiased	10 biased	10 unbiased	30 biased	30 unbiased	50 biased	50 unbiased	100 biased	100 unbiased
LL	2.000	2.000	2.000	2.000	2.000	2.000	2.000	2.000	2.000	2.000
Min	13.270	13.135	13.210	13.183	12.755	13.008	12.563	12.637	12.380	12.346
Average	13.322	13.314	13.303	13.230	12.905	13.140	12.759	12.985	12.580	12.683
Max	13.390	13.477	13.441	13.301	13.023	13.198	12.894	13.195	12.698	12.915
UL	16.200	16.200	16.200	16.200	16.200	16.200	16.200	16.200	16.200	16.200



TID Report
Device Name

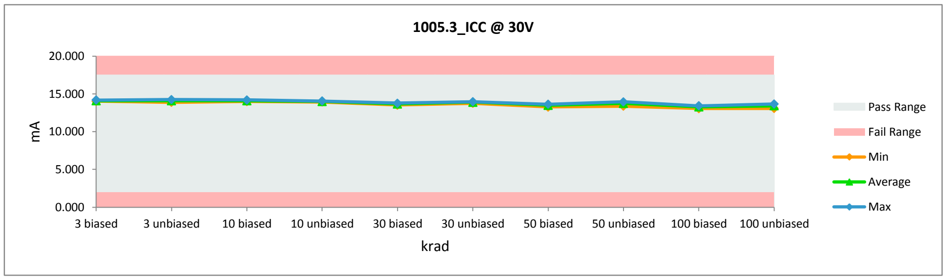
	1005.3_ICC @ 30V	
Test Site		
Tester		
Test Number		
Unit	mA	mA
Max Limit	17.5	17.5
Min Limit	2	2

krad	Serial #	Pre	Post	Delta
3	135	14.070	14.061	0.009
3	136	14.043	14.038	0.005
3	138	14.222	14.179	0.043
3	139	14.028	14.023	0.006
3	143	14.134	14.123	0.011
4	1	14.147	14.131	0.016
4	2	14.097	14.060	0.037
4	3	14.267	14.250	0.016
4	5	13.907	13.883	0.025
4	7	14.104	14.080	0.024
10	144	14.167	14.097	0.070
10	145	14.164	14.111	0.053
10	146	14.278	14.200	0.078
10	149	14.101	14.013	0.088
10	150	14.174	13.998	0.176
11	8	14.079	13.991	0.088
11	11	14.036	13.958	0.078
11	14	14.130	14.053	0.078
11	15	14.003	13.932	0.072
11	19	14.040	13.963	0.077
30	151	13.980	13.645	0.335
30	153	14.174	13.769	0.405
30	154	14.173	13.732	0.440
30	155	14.067	13.517	0.550
30	156	13.950	13.607	0.342
31	22	13.976	13.762	0.214
31	23	14.145	13.951	0.194
31	31	14.119	13.925	0.194
31	37	14.114	13.916	0.198
31	42	14.105	13.928	0.176
50	173	13.997	13.396	0.601
50	174	14.148	13.535	0.614
50	175	14.181	13.581	0.600
50	183	14.227	13.640	0.587
50	187	13.902	13.260	0.642
51	43	14.177	13.831	0.346
51	45	13.876	13.369	0.507
51	48	14.178	13.939	0.239
51	49	14.221	13.881	0.340
51	50	14.010	13.617	0.393
100	191	13.997	13.235	0.762
100	195	14.148	13.315	0.833
100	199	14.181	13.379	0.802
100	203	14.227	13.419	0.808
100	207	13.902	13.051	0.851
101	69	14.198	13.451	0.747
101	70	13.905	13.338	0.567
101	71	14.044	13.102	0.942
101	74	14.044	13.477	0.567
101	76	14.032	13.347	0.686
101	81	14.074	13.575	0.499
101	82	14.029	13.242	0.786
101	85	14.045	13.503	0.542
101	94	14.080	13.439	0.641
101	95	14.189	13.618	0.571
101	99	14.115	13.524	0.591
101	103	14.218	13.283	0.935
101	109	14.093	13.430	0.663
101	110	14.110	13.081	1.029
101	112	13.987	13.339	0.648
101	115	14.107	13.560	0.547
101	117	13.929	13.520	0.409
101	118	14.026	13.552	0.474
101	122	14.132	13.666	0.465
101	125	14.108	13.533	0.576
101	126	14.084	13.421	0.663
101	129	14.150	13.319	0.831
	Max	14.278	14.250	1.029
	Average	14.091	13.682	0.409
	Min	13.876	13.051	0.005
	Std Dev	0.095	0.318	0.296



	1005.3_ICC @ 30V	
Test Site		
Tester		
Test Number		
Max Limit	17.5	mA
Min Limit	2	mA

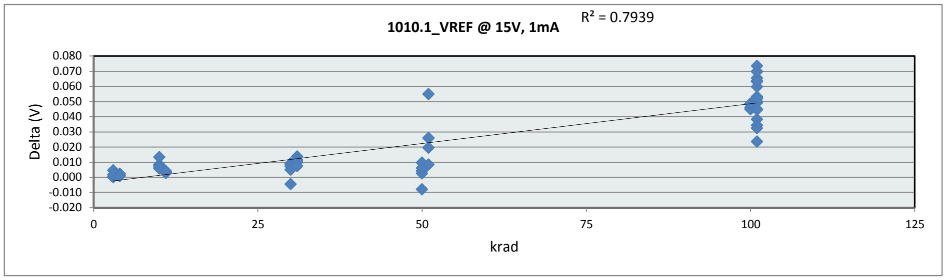
krad	3 biased	3 unbiased	10 biased	10 unbiased	30 biased	30 unbiased	50 biased	50 unbiased	100 biased	100 unbiased
LL	2.000	2.000	2.000	2.000	2.000	2.000	2.000	2.000	2.000	2.000
Min	14.023	13.883	13.998	13.932	13.518	13.762	13.261	13.369	13.051	13.081
Average	14.085	14.081	14.084	13.979	13.654	13.897	13.482	13.727	13.280	13.424
Max	14.179	14.251	14.200	14.053	13.770	13.952	13.640	13.939	13.419	13.666
UL	17.500	17.500	17.500	17.500	17.500	17.500	17.500	17.500	17.500	17.500



TID Report
Device Name

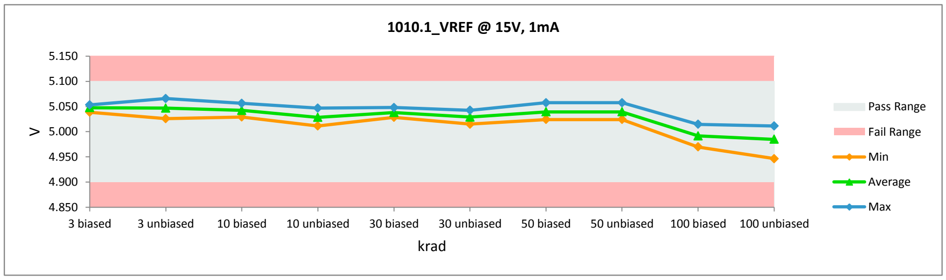
	1010.1_VREF @ 15V, 1	
Test Site		
Tester		
Test Number		
Unit	V	V
Max Limit	5.1	5.1
Min Limit	4.9	4.9

krad	Serial #	Pre	Post	Delta
3	135	5.054	5.053	0.000
3	136	5.050	5.050	0.000
3	138	5.043	5.039	0.005
3	139	5.049	5.049	0.000
3	143	5.050	5.048	0.002
4	1	5.027	5.026	0.001
4	2	5.044	5.042	0.002
4	3	5.067	5.066	0.001
4	5	5.049	5.048	0.001
4	7	5.053	5.052	0.001
10	144	5.057	5.049	0.008
10	145	5.064	5.056	0.008
10	146	5.048	5.041	0.007
10	149	5.035	5.029	0.006
10	150	5.049	5.036	0.013
11	8	5.030	5.026	0.004
11	11	5.032	5.029	0.003
11	14	5.050	5.047	0.003
11	15	5.014	5.011	0.003
11	19	5.032	5.029	0.003
30	151	5.043	5.048	-0.005
30	153	5.037	5.028	0.009
30	154	5.044	5.036	0.008
30	155	5.042	5.035	0.007
30	156	5.048	5.043	0.005
31	22	5.029	5.015	0.014
31	23	5.045	5.035	0.010
31	31	5.053	5.043	0.010
31	37	5.042	5.030	0.011
31	42	5.029	5.022	0.007
50	173	5.048	5.039	0.010
50	174	5.044	5.040	0.004
50	175	5.039	5.037	0.003
50	183	5.050	5.058	-0.008
50	187	5.030	5.024	0.006
51	43	5.057	5.031	0.026
51	45	5.035	4.980	0.055
51	48	5.053	5.045	0.008
51	49	5.053	5.034	0.020
51	50	5.025	4.999	0.026
100	191	5.018	4.970	0.048
100	195	5.044	4.998	0.046
100	199	5.039	4.995	0.045
100	203	5.060	5.015	0.045
100	207	5.030	4.982	0.049
101	69	5.031	4.958	0.073
101	70	5.000	4.956	0.045
101	71	5.044	4.991	0.053
101	74	5.030	4.981	0.049
101	76	5.010	4.946	0.064
101	81	5.035	4.997	0.038
101	82	5.043	4.993	0.050
101	85	5.042	4.990	0.052
101	94	5.047	4.981	0.066
101	95	5.032	4.983	0.049
101	99	5.037	4.977	0.060
101	103	5.044	4.999	0.044
101	109	5.044	4.981	0.063
101	110	5.044	4.991	0.053
101	112	5.025	4.955	0.070
101	115	5.043	4.999	0.045
101	117	5.020	4.997	0.023
101	118	5.031	4.997	0.034
101	122	5.044	5.012	0.032
101	125	5.059	5.006	0.053
101	126	5.052	4.982	0.070
101	129	5.051	4.999	0.052
	Max	5.067	5.066	0.073
	Average	5.041	5.016	0.025
	Min	5.000	4.946	-0.008
	Std Dev	0.013	0.030	0.024



	1010.1_VREF @ 15V, 1mA	
Test Site		
Tester		
Test Number		
Max Limit	5.1	V
Min Limit	4.9	V

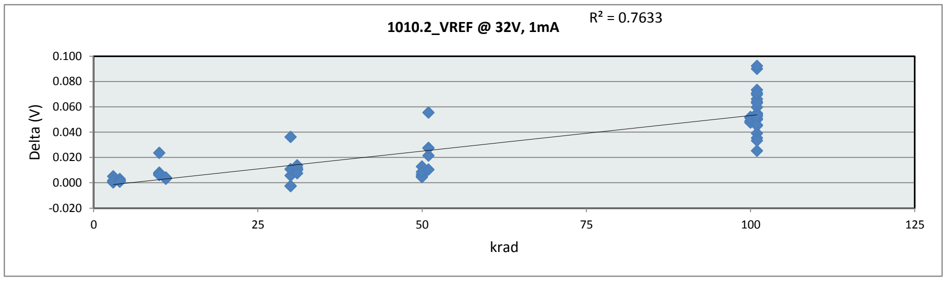
krad	3 biased	3 unbiased	10 biased	10 unbiased	30 biased	30 unbiased	50 biased	50 unbiased	100 biased	100 unbiased
LL	4.900	4.900	4.900	4.900	4.900	4.900	4.900	4.900	4.900	4.900
Min	5.039	5.026	5.029	5.011	5.028	5.015	5.024	5.024	4.970	4.946
Average	5.048	5.047	5.042	5.028	5.038	5.029	5.039	5.039	4.992	4.985
Max	5.053	5.066	5.056	5.047	5.048	5.043	5.058	5.058	5.015	5.012
UL	5.100	5.100	5.100	5.100	5.100	5.100	5.100	5.100	5.100	5.100



TID Report
Device Name

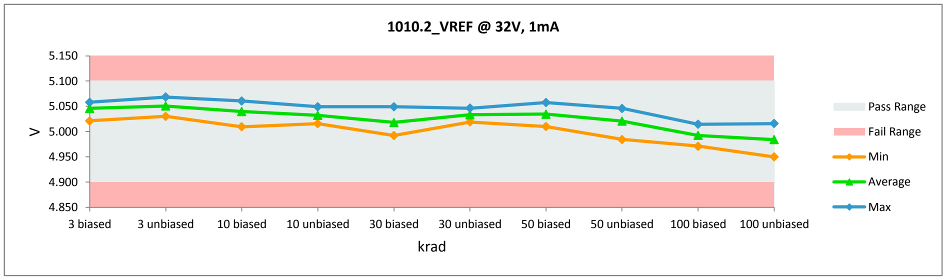
	1010.2_VREF @ 32V, 1	
Test Site		
Tester		
Test Number		
Unit	V	V
Max Limit	5.1	5.1
Min Limit	4.9	4.9

krad	Serial #	Pre	Post	Delta
3	135	5.059	5.058	0.001
3	136	5.057	5.056	0.001
3	138	5.048	5.043	0.005
3	139	5.052	5.051	0.000
3	143	5.023	5.021	0.002
4	1	5.032	5.030	0.002
4	2	5.049	5.046	0.003
4	3	5.069	5.069	0.001
4	5	5.053	5.051	0.001
4	7	5.058	5.057	0.001
10	144	5.060	5.052	0.008
10	145	5.068	5.061	0.007
10	146	5.051	5.044	0.007
10	149	5.038	5.032	0.006
10	150	5.033	5.010	0.024
11	8	5.034	5.030	0.004
11	11	5.036	5.033	0.003
11	14	5.052	5.049	0.003
11	15	5.019	5.016	0.003
11	19	5.036	5.032	0.004
30	151	5.047	5.049	-0.003
30	153	5.041	5.035	0.006
30	154	5.009	4.998	0.011
30	155	5.028	4.992	0.036
30	156	5.013	5.016	-0.003
31	22	5.033	5.019	0.014
31	23	5.050	5.040	0.010
31	31	5.057	5.046	0.010
31	37	5.045	5.034	0.012
31	42	5.034	5.027	0.008
50	173	5.023	5.010	0.013
50	174	5.047	5.041	0.007
50	175	5.044	5.039	0.005
50	183	5.062	5.058	0.004
50	187	5.034	5.025	0.009
51	43	5.063	5.035	0.027
51	45	5.040	4.984	0.055
51	48	5.056	5.046	0.010
51	49	5.057	5.036	0.021
51	50	5.030	5.002	0.028
100	191	5.023	4.971	0.052
100	195	5.047	4.998	0.049
100	199	5.044	4.996	0.048
100	203	5.062	5.015	0.047
100	207	5.034	4.983	0.051
101	69	5.035	4.962	0.073
101	70	5.004	4.959	0.045
101	71	5.049	4.995	0.054
101	74	5.034	4.984	0.050
101	76	5.014	4.950	0.064
101	81	5.038	4.999	0.039
101	82	5.047	4.957	0.090
101	85	5.045	4.993	0.053
101	94	5.052	4.986	0.066
101	95	5.037	4.986	0.051
101	99	5.040	4.980	0.060
101	103	5.047	4.992	0.055
101	109	5.048	4.985	0.063
101	110	5.051	4.996	0.054
101	112	5.029	4.959	0.070
101	115	5.047	5.001	0.045
101	117	5.024	4.999	0.025
101	118	5.035	5.000	0.035
101	122	5.049	5.016	0.033
101	125	5.061	5.008	0.053
101	126	5.055	4.985	0.071
101	129	5.054	4.962	0.092
	Max	5.069	5.069	0.092
	Average	5.042	5.015	0.028
	Min	5.004	4.950	-0.003
	Std Dev	0.014	0.031	0.026



	1010.2_VREF @ 32V, 1mA	
Test Site		
Tester		
Test Number		
Max Limit	5.1	V
Min Limit	4.9	V

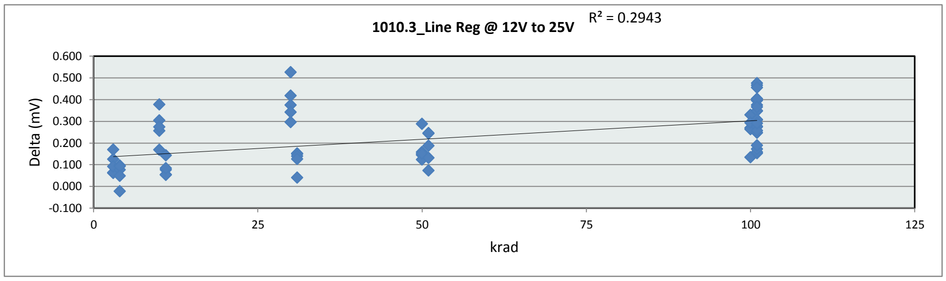
krad	3 biased	3 unbiased	10 biased	10 unbiased	30 biased	30 unbiased	50 biased	50 unbiased	100 biased	100 unbiased
LL	4.900	4.900	4.900	4.900	4.900	4.900	4.900	4.900	4.900	4.900
Min	5.021	5.030	5.010	5.016	4.992	5.019	5.010	4.984	4.971	4.950
Average	5.046	5.051	5.040	5.032	5.018	5.033	5.034	5.021	4.993	4.984
Max	5.058	5.069	5.061	5.049	5.049	5.046	5.058	5.046	5.015	5.016
UL	5.100	5.100	5.100	5.100	5.100	5.100	5.100	5.100	5.100	5.100



TID Report
Device Name

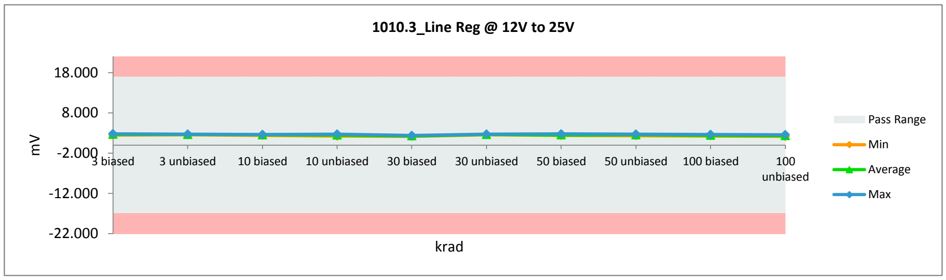
	1010.3_Line Reg @ 12	
Test Site		
Tester		
Test Number		
Unit	mV	mV
Max Limit	16.9	16.9
Min Limit	-16.9	-16.9

krad	Serial #	Pre	Post	Delta
3	135	2.699	2.638	0.062
3	136	2.867	2.803	0.064
3	138	2.918	2.793	0.125
3	139	2.654	2.562	0.092
3	143	2.633	2.463	0.170
4	1	2.691	2.614	0.077
4	2	2.728	2.632	0.097
4	3	2.533	2.555	-0.022
4	5	2.700	2.607	0.093
4	7	2.780	2.731	0.049
10	144	2.782	2.477	0.304
10	145	2.800	2.632	0.169
10	146	2.827	2.571	0.257
10	149	2.690	2.415	0.275
10	150	2.980	2.602	0.378
11	8	2.651	2.573	0.077
11	11	2.781	2.726	0.055
11	14	2.555	2.502	0.053
11	15	2.631	2.487	0.143
11	19	2.280	2.196	0.084
30	151	2.428	2.132	0.296
30	153	2.708	2.182	0.527
30	154	2.803	2.384	0.419
30	155	2.644	2.269	0.375
30	156	2.731	2.388	0.342
31	22	2.752	2.600	0.153
31	23	2.741	2.700	0.041
31	31	2.726	2.576	0.150
31	37	2.729	2.589	0.140
31	42	2.730	2.603	0.126
50	173	2.782	2.494	0.288
50	174	2.625	2.480	0.145
50	175	2.892	2.768	0.124
50	183	2.561	2.403	0.158
50	187	2.536	2.385	0.152
51	43	2.639	2.395	0.244
51	45	2.573	2.328	0.246
51	48	2.630	2.499	0.132
51	49	2.918	2.730	0.188
51	50	2.695	2.622	0.073
100	191	2.782	2.452	0.330
100	195	2.625	2.355	0.270
100	199	2.892	2.628	0.264
100	203	2.561	2.267	0.294
100	207	2.536	2.402	0.135
101	69	2.806	2.499	0.307
101	70	2.378	2.225	0.153
101	71	2.963	2.497	0.467
101	74	2.343	2.184	0.159
101	76	2.709	2.312	0.397
101	81	2.433	2.156	0.277
101	82	2.641	2.293	0.348
101	85	2.747	2.398	0.348
101	94	2.780	2.472	0.308
101	95	2.809	2.561	0.248
101	99	2.562	2.187	0.375
101	103	2.780	2.304	0.476
101	109	2.471	2.196	0.274
101	110	2.681	2.226	0.456
101	112	2.763	2.360	0.404
101	115	2.666	2.494	0.172
101	117	2.722	2.533	0.190
101	118	2.530	2.282	0.248
101	122	2.656	2.399	0.258
101	125	2.600	2.197	0.404
101	126	2.633	2.267	0.366
101	129	2.630	2.339	0.291
	Max	2.980	2.803	0.527
	Average	2.682	2.456	0.226
	Min	2.280	2.132	-0.022
	Std Dev	0.141	0.174	0.128



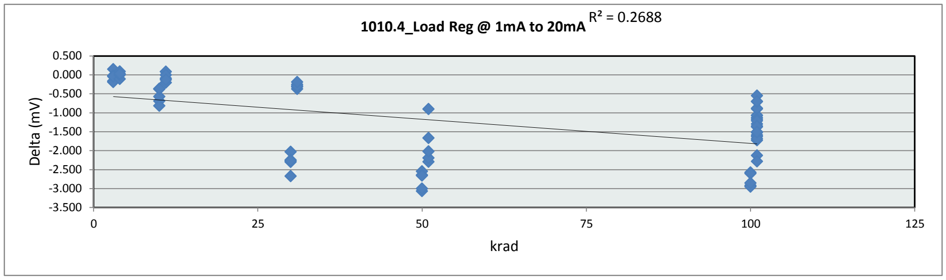
	1010.3_Line Reg @ 12V to 25V	
Test Site		
Tester		
Test Number		
Max Limit	16.9	mV
Min Limit	-16.9	mV

krad	3 biased	3 unbiased	10 biased	10 unbiased	30 biased	30 unbiased	50 biased	50 unbiased	100 biased	100 unbiased
LL	-16.900	-16.900	-16.900	-16.900	-16.900	-16.900	-16.900	-16.900	-16.900	-16.900
Min	2.463	2.555	2.415	2.196	2.132	2.576	2.385	2.328	2.267	2.156
Average	2.652	2.628	2.539	2.497	2.271	2.614	2.506	2.515	2.421	2.335
Max	2.803	2.731	2.632	2.726	2.388	2.700	2.768	2.730	2.628	2.561
UL	16.900	16.900	16.900	16.900	16.900	16.900	16.900	16.900	16.900	16.900

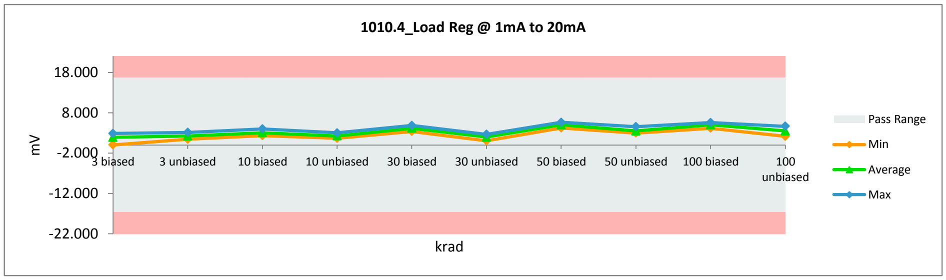


TID Report
Device Name

		1010.4_Load Reg @ 1		
Test Site				
Tester				
Test Number				
Unit		mV	mV	
Max Limit		16.6	16.6	
Min Limit		-16.6	-16.6	
krad	Serial #	Pre	Post	Delta
3	135	1.713	1.881	-0.167
3	136	0.187	0.039	0.148
3	138	1.729	1.921	-0.192
3	139	2.821	2.847	-0.026
3	143	2.655	2.701	-0.046
4	1	1.301	1.415	-0.113
4	2	2.307	2.309	-0.002
4	3	3.214	3.130	0.084
4	5	2.922	2.922	0.000
4	7	1.481	1.459	0.022
10	144	3.281	3.976	-0.695
10	145	2.090	2.670	-0.579
10	146	1.926	2.306	-0.380
10	149	2.755	3.123	-0.368
10	150	2.207	3.027	-0.820
11	8	1.758	1.969	-0.210
11	11	1.752	1.671	0.081
11	14	2.644	2.742	-0.099
11	15	1.898	1.902	-0.004
11	19	2.872	3.003	-0.131
30	151	2.821	4.855	-2.033
30	153	2.578	4.826	-2.248
30	154	1.078	3.381	-2.303
30	155	1.439	4.115	-2.676
30	156	1.441	3.713	-2.272
31	22	1.979	2.353	-0.374
31	23	0.783	1.042	-0.259
31	31	2.317	2.635	-0.318
31	37	2.368	2.666	-0.298
31	42	0.919	1.115	-0.196
50	173	2.138	5.209	-3.071
50	174	2.930	5.481	-2.551
50	175	1.217	4.219	-3.002
50	183	2.973	5.618	-2.645
50	187	1.838	4.497	-2.659
51	43	1.372	3.043	-1.670
51	45	2.081	2.988	-0.907
51	48	2.248	4.544	-2.296
51	49	1.562	3.759	-2.197
51	50	1.057	3.079	-2.023
100	191	2.138	5.062	-2.923
100	195	2.930	5.506	-2.577
100	199	1.217	4.170	-2.953
100	203	2.973	5.578	-2.605
100	207	1.838	4.694	-2.856
101	69	2.096	2.997	-0.901
101	70	1.843	2.914	-1.071
101	71	2.192	3.567	-1.374
101	74	2.477	3.778	-1.301
101	76	1.840	2.975	-1.135
101	81	3.006	4.516	-1.510
101	82	2.506	3.580	-1.074
101	85	2.704	3.879	-1.175
101	94	1.636	2.850	-1.214
101	95	1.347	2.871	-1.524
101	99	2.277	3.160	-0.883
101	103	3.189	4.542	-1.353
101	109	1.933	2.640	-0.707
101	110	0.295	2.424	-2.129
101	112	2.441	2.994	-0.553
101	115	2.252	3.845	-1.593
101	117	1.518	3.802	-2.284
101	118	2.305	4.034	-1.729
101	122	0.503	2.133	-1.629
101	125	3.589	4.291	-0.701
101	126	2.957	4.644	-1.687
101	129	2.564	4.075	-1.511
	Max	3.589	5.618	0.148
	Average	2.078	3.309	-1.231
	Min	0.187	0.039	-3.071
	Std Dev	0.742	1.197	0.999



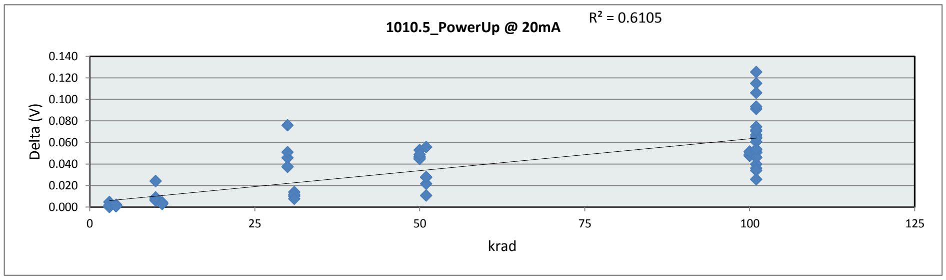
	1010.4_Load Reg @ 1mA to 20mA									
Test Site										
Tester										
Test Number										
Max Limit	16.6 mV									
Min Limit	-16.6 mV									
krad	3 biased	3 unbiased	10 biased	10 unbiased	30 biased	30 unbiased	50 biased	50 unbiased	100 biased	100 unbiased
LL	-16.600	-16.600	-16.600	-16.600	-16.600	-16.600	-16.600	-16.600	-16.600	-16.600
Min	0.039	1.415	2.306	1.671	3.381	1.042	4.219	2.988	4.170	2.133
Average	1.878	2.247	3.020	2.257	4.178	1.962	5.005	3.482	5.002	3.478
Max	2.847	3.130	3.976	3.003	4.855	2.666	5.618	4.544	5.578	4.644
UL	16.600	16.600	16.600	16.600	16.600	16.600	16.600	16.600	16.600	16.600



TID Report
Device Name

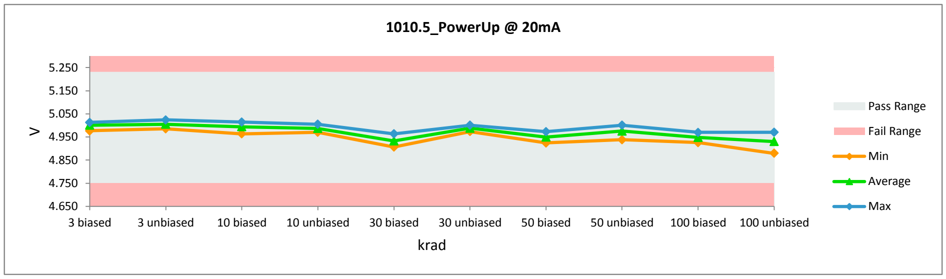
	1010.5_PowerUp @ 20	
Test Site		
Tester		
Test Number		
Unit	V	V
Max Limit	5.23	5.23
Min Limit	4.75	4.75

krad	Serial #	Pre	Post	Delta
3	135	5.013	5.012	0.001
3	136	5.011	5.011	0.000
3	138	5.002	4.998	0.005
3	139	5.007	5.007	0.000
3	143	4.978	4.976	0.002
4	1	4.987	4.985	0.001
4	2	5.003	5.001	0.002
4	3	5.024	5.024	0.001
4	5	5.007	5.006	0.001
4	7	5.012	5.011	0.001
10	144	5.015	5.006	0.009
10	145	5.023	5.015	0.008
10	146	5.006	4.999	0.007
10	149	4.993	4.987	0.006
10	150	4.988	4.964	0.024
11	8	4.989	4.984	0.004
11	11	4.991	4.988	0.003
11	14	5.008	5.005	0.003
11	15	4.973	4.970	0.003
11	19	4.990	4.987	0.004
30	151	5.001	4.964	0.038
30	153	4.996	4.950	0.046
30	154	4.964	4.913	0.051
30	155	4.982	4.906	0.076
30	156	4.968	4.930	0.037
31	22	4.987	4.973	0.014
31	23	5.005	4.995	0.010
31	31	5.011	5.001	0.010
31	37	5.000	4.989	0.012
31	42	4.989	4.981	0.008
50	173	4.977	4.924	0.053
50	174	5.002	4.955	0.047
50	175	4.999	4.953	0.046
50	183	5.017	4.973	0.045
50	187	4.989	4.940	0.049
51	43	5.017	4.989	0.028
51	45	4.994	4.938	0.056
51	48	5.011	5.001	0.011
51	49	5.013	4.991	0.022
51	50	4.985	4.957	0.028
100	191	4.977	4.925	0.052
100	195	5.002	4.953	0.049
100	199	4.999	4.951	0.048
100	203	5.017	4.970	0.048
100	207	4.989	4.938	0.051
101	69	4.990	4.916	0.075
101	70	4.959	4.913	0.046
101	71	5.003	4.888	0.115
101	74	4.989	4.938	0.051
101	76	4.969	4.904	0.065
101	81	4.993	4.953	0.040
101	82	5.001	4.910	0.091
101	85	5.000	4.947	0.053
101	94	5.006	4.939	0.067
101	95	4.991	4.940	0.051
101	99	4.995	4.934	0.061
101	103	5.001	4.895	0.106
101	109	5.003	4.939	0.064
101	110	5.005	4.879	0.125
101	112	4.983	4.913	0.070
101	115	5.002	4.956	0.046
101	117	4.979	4.954	0.026
101	118	4.990	4.954	0.036
101	122	5.004	4.970	0.034
101	125	5.016	4.962	0.054
101	126	5.010	4.938	0.071
101	129	5.009	4.916	0.093
	Max	5.024	5.024	0.125
	Average	4.997	4.961	0.037
	Min	4.959	4.879	0.000
	Std Dev	0.014	0.035	0.031



	1010.5_PowerUp @ 20mA	
Test Site		
Tester		
Test Number		
Max Limit	5.23	V
Min Limit	4.75	V

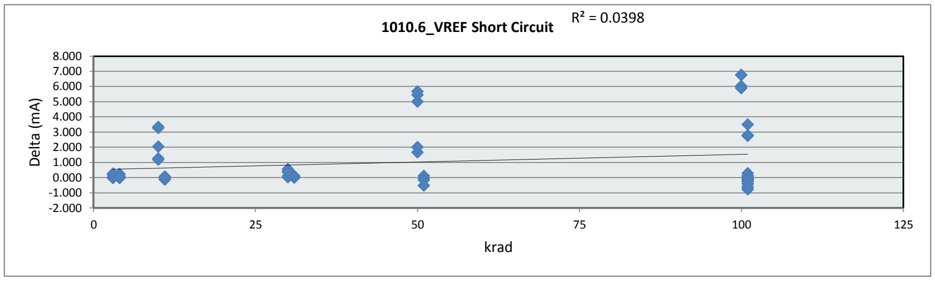
krad	3 biased	3 unbiased	10 biased	10 unbiased	30 biased	30 unbiased	50 biased	50 unbiased	100 biased	100 unbiased
LL	4.750	4.750	4.750	4.750	4.750	4.750	4.750	4.750	4.750	4.750
Min	4.976	4.985	4.964	4.970	4.906	4.973	4.924	4.938	4.925	4.879
Average	5.001	5.005	4.994	4.987	4.933	4.988	4.949	4.975	4.947	4.930
Max	5.012	5.024	5.015	5.005	4.964	5.001	4.973	5.001	4.970	4.970
UL	5.230	5.230	5.230	5.230	5.230	5.230	5.230	5.230	5.230	5.230



TID Report
Device Name

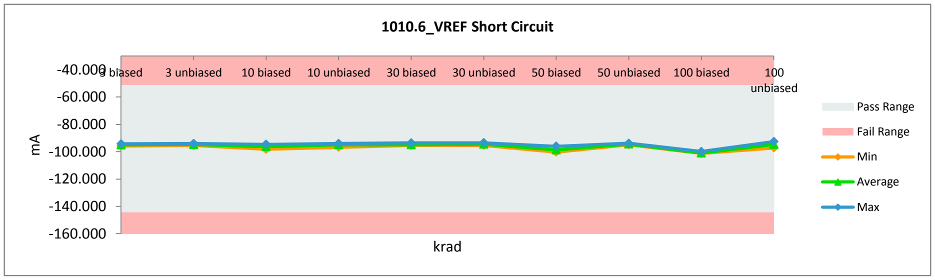
	1010.6_VREF Short Ci	
Test Site		
Tester		
Test Number		
Unit	mA	mA
Max Limit	-51	-51
Min Limit	-144	-144

krad	Serial #	Pre	Post	Delta
3	135	-95.224	-95.200	-0.024
3	136	-94.506	-94.690	0.184
3	138	-94.261	-94.308	0.047
3	139	-95.598	-95.863	0.265
3	143	-94.288	-94.534	0.246
4	1	-94.067	-94.043	-0.024
4	2	-95.366	-95.445	0.079
4	3	-94.186	-94.427	0.241
4	5	-94.253	-94.383	0.131
4	7	-95.462	-95.488	0.026
10	144	-94.489	-97.762	3.273
10	145	-94.824	-98.159	3.335
10	146	-93.374	-94.635	1.261
10	149	-93.449	-94.643	1.194
10	150	-94.259	-96.303	2.044
11	8	-96.801	-96.710	-0.091
11	11	-94.109	-93.985	-0.124
11	14	-94.554	-94.605	0.051
11	15	-94.078	-94.152	0.075
11	19	-94.709	-94.699	-0.010
30	151	-94.875	-95.431	0.556
30	153	-94.898	-94.994	0.096
30	154	-94.781	-95.178	0.397
30	155	-93.543	-93.568	0.024
30	156	-94.853	-95.221	0.368
31	22	-94.678	-94.795	0.117
31	23	-94.443	-94.448	0.005
31	31	-95.277	-95.315	0.038
31	37	-94.037	-94.068	0.032
31	42	-93.329	-93.416	0.086
50	173	-95.182	-100.189	5.007
50	174	-93.982	-95.994	2.012
50	175	-94.417	-99.864	5.447
50	183	-94.520	-100.188	5.667
50	187	-95.084	-96.756	1.672
51	43	-94.244	-94.202	-0.042
51	45	-94.148	-94.257	0.109
51	48	-94.571	-94.546	-0.025
51	49	-93.958	-93.806	-0.152
51	50	-95.388	-94.865	-0.524
100	191	-95.182	-101.204	6.022
100	195	-93.982	-99.872	5.890
100	199	-94.417	-101.183	6.766
100	203	-94.520	-101.285	6.764
100	207	-95.084	-101.022	5.938
101	69	-94.778	-94.004	-0.774
101	70	-94.260	-93.843	-0.417
101	71	-94.317	-97.084	2.767
101	74	-95.330	-95.289	-0.041
101	76	-94.956	-94.757	-0.199
101	81	-92.528	-92.650	0.121
101	82	-95.511	-95.255	-0.256
101	85	-94.421	-94.708	0.288
101	94	-95.233	-94.992	-0.242
101	95	-94.246	-94.352	0.106
101	99	-93.648	-97.145	3.497
101	103	-93.760	-93.159	-0.600
101	109	-94.563	-94.437	-0.125
101	110	-93.328	-96.080	2.751
101	112	-94.603	-94.480	-0.123
101	115	-93.480	-93.431	-0.050
101	117	-93.064	-92.885	-0.179
101	118	-93.293	-92.920	-0.374
101	122	-93.905	-93.799	-0.106
101	125	-95.075	-94.994	-0.081
101	126	-93.928	-96.719	2.792
101	129	-94.890	-94.245	-0.644
	Max	-92.528	-92.650	6.766
	Average	-94.453	-95.536	1.083
	Min	-96.801	-101.285	-0.774
	Std Dev	0.717	2.183	2.061



	1010.6_VREF Short Circuit
Test Site	
Tester	
Test Number	
Max Limit	-51 mA
Min Limit	-144 mA

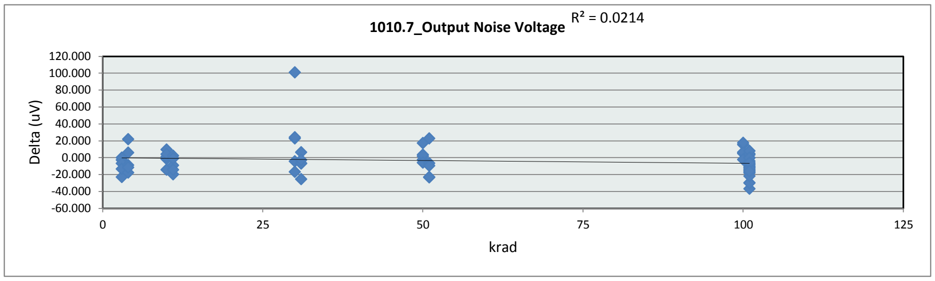
krad	3 biased	3 unbiased	10 biased	10 unbiased	30 biased	30 unbiased	50 biased	50 unbiased	100 biased	100 unbiased
LL	-144.000	-144.000	-144.000	-144.000	-144.000	-144.000	-144.000	-144.000	-144.000	-144.000
Min	-95.863	-95.488	-98.159	-96.710	-95.431	-95.315	-100.189	-94.865	-101.285	-97.145
Average	-94.919	-94.757	-96.300	-94.830	-94.878	-94.408	-98.598	-94.335	-100.913	-94.601
Max	-94.308	-94.043	-94.635	-93.985	-93.568	-93.416	-95.994	-93.806	-99.872	-92.650
UL	-51.000	-51.000	-51.000	-51.000	-51.000	-51.000	-51.000	-51.000	-51.000	-51.000



TID Report
Device Name

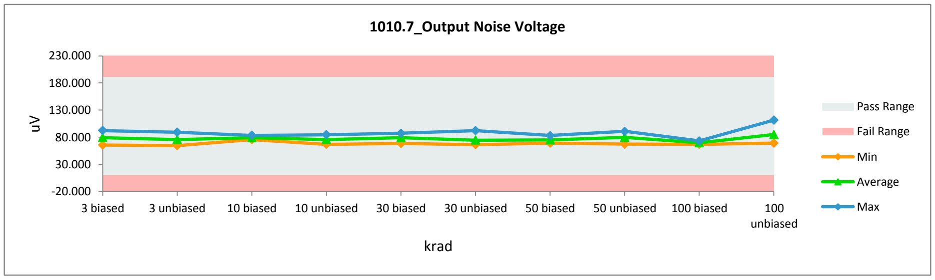
	1010.7_Output Noise	
Test Site		
Tester		
Test Number		
Unit	uV	uV
Max Limit	190	190
Min Limit	10	10

krad	Serial #	Pre	Post	Delta
3	135	67.744	90.921	-23.177
3	136	62.796	65.740	-2.944
3	138	68.501	68.632	-0.131
3	139	85.590	92.551	-6.961
3	143	65.677	79.255	-13.578
4	1	71.482	89.260	-17.778
4	2	70.414	64.706	5.707
4	3	69.721	78.761	-9.040
4	5	66.951	78.619	-11.669
4	7	89.599	67.931	21.668
10	144	93.154	83.681	9.474
10	145	65.035	79.589	-14.554
10	146	76.364	78.013	-1.648
10	149	79.373	78.616	0.757
10	150	79.533	75.549	3.984
11	8	64.685	73.985	-9.300
11	11	64.881	84.796	-19.915
11	14	74.582	72.400	2.183
11	15	66.158	67.093	-0.934
11	19	66.610	81.132	-14.522
30	151	75.242	79.651	-4.409
30	153	104.448	81.851	22.597
30	154	92.722	68.680	24.042
30	155	179.141	78.309	100.832
30	156	70.451	87.392	-16.941
31	22	68.106	75.230	-7.124
31	23	72.853	66.541	6.312
31	31	66.515	92.097	-25.582
31	37	66.898	73.560	-6.662
31	42	64.240	67.175	-2.935
50	173	86.521	69.251	17.271
50	174	73.595	76.234	-2.639
50	175	73.364	71.918	1.446
50	183	86.414	83.194	3.220
50	187	70.798	76.748	-5.950
51	43	66.475	90.093	-23.619
51	45	70.156	76.769	-6.613
51	48	67.976	90.980	-23.004
51	49	89.987	67.307	22.681
51	50	64.671	74.323	-9.652
100	191	86.521	71.193	15.328
100	195	73.595	68.717	4.878
100	199	73.364	67.181	6.183
100	203	86.414	69.053	17.361
100	207	70.798	73.262	-2.464
101	69	84.968	81.732	3.236
101	70	70.918	71.248	-0.330
101	71	77.732	73.357	4.375
101	74	69.567	81.581	-12.014
101	76	74.822	111.722	-36.900
101	81	68.147	86.438	-18.290
101	82	76.060	91.256	-15.197
101	85	71.759	89.191	-17.431
101	94	73.955	88.272	-14.317
101	95	67.644	75.526	-7.882
101	99	67.347	97.225	-29.878
101	103	70.308	100.541	-30.233
101	109	73.982	82.072	-8.090
101	110	75.013	96.909	-21.896
101	112	72.578	76.828	-4.250
101	115	71.415	82.498	-11.083
101	117	73.005	83.016	-10.011
101	118	82.491	74.615	7.876
101	122	68.965	69.216	-0.252
101	125	74.235	86.860	-12.626
101	126	72.850	79.065	-6.215
101	129	74.782	91.014	-16.232
	Max	179.141	111.722	100.832
	Average	75.562	79.375	-3.813
	Min	62.796	64.706	-36.900
	Std Dev	15.304	9.630	18.548



	1010.7_Output Noise Voltage	
Test Site		
Tester		
Test Number		
Max Limit	190	uV
Min Limit	10	uV

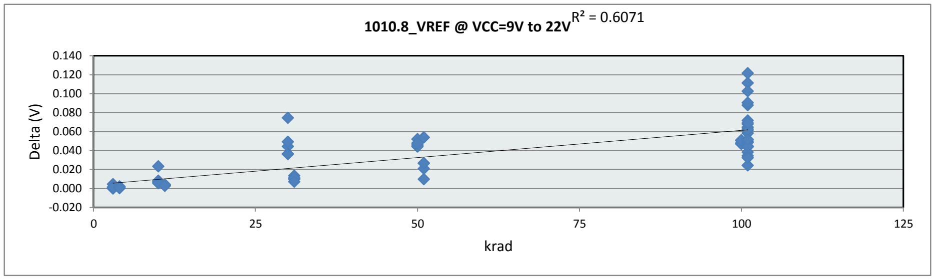
krad	3 biased	3 unbiased	10 biased	10 unbiased	30 biased	30 unbiased	50 biased	50 unbiased	100 biased	100 unbiased
LL	10.000	10.000	10.000	10.000	10.000	10.000	10.000	10.000	10.000	10.000
Min	65.740	64.706	75.549	67.093	68.680	66.541	69.251	67.307	67.181	69.216
Average	79.420	75.856	79.089	75.881	79.177	74.920	75.469	79.894	69.881	85.008
Max	92.551	89.260	83.681	84.796	87.392	92.097	83.194	90.980	73.263	111.722
UL	190.000	190.000	190.000	190.000	190.000	190.000	190.000	190.000	190.000	190.000



TID Report
Device Name

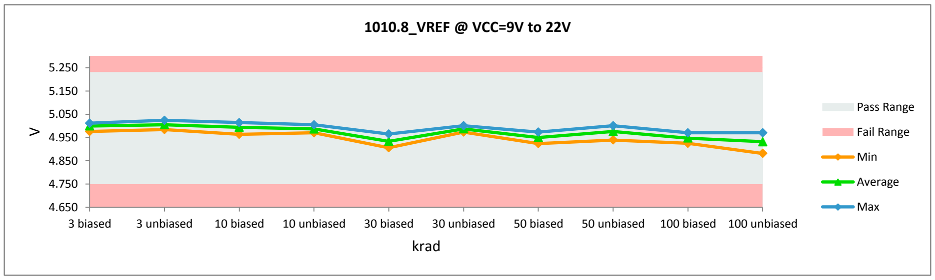
	1010.8_VREF @ VCC=	
Test Site		
Tester		
Test Number		
Unit	V	V
Max Limit	5.23	5.23
Min Limit	4.75	4.75

krad	Serial #	Pre	Post	Delta
3	135	5.012	5.011	0.001
3	136	5.010	5.009	0.001
3	138	5.001	4.997	0.004
3	139	5.006	5.006	0.000
3	143	4.978	4.976	0.002
4	1	4.986	4.984	0.001
4	2	5.002	5.000	0.002
4	3	5.024	5.024	0.000
4	5	5.007	5.005	0.001
4	7	5.011	5.010	0.001
10	144	5.014	5.006	0.008
10	145	5.022	5.014	0.007
10	146	5.006	4.999	0.007
10	149	4.993	4.987	0.006
10	150	4.987	4.964	0.023
11	8	4.988	4.984	0.004
11	11	4.990	4.987	0.003
11	14	5.009	5.005	0.003
11	15	4.973	4.970	0.003
11	19	4.991	4.988	0.003
30	151	5.001	4.965	0.036
30	153	4.995	4.951	0.044
30	154	4.962	4.913	0.049
30	155	4.981	4.906	0.075
30	156	4.967	4.930	0.036
31	22	4.987	4.973	0.013
31	23	5.003	4.994	0.010
31	31	5.011	5.001	0.010
31	37	5.000	4.989	0.011
31	42	4.988	4.981	0.007
50	173	4.976	4.924	0.052
50	174	5.002	4.956	0.046
50	175	4.998	4.953	0.045
50	183	5.017	4.973	0.044
50	187	4.989	4.941	0.048
51	43	5.016	4.990	0.027
51	45	4.994	4.940	0.054
51	48	5.011	5.001	0.010
51	49	5.011	4.991	0.021
51	50	4.984	4.957	0.027
100	191	4.976	4.925	0.051
100	195	5.002	4.954	0.048
100	199	4.998	4.951	0.047
100	203	5.017	4.970	0.047
100	207	4.989	4.938	0.051
101	69	4.990	4.918	0.072
101	70	4.959	4.915	0.044
101	71	5.002	4.891	0.111
101	74	4.988	4.940	0.049
101	76	4.968	4.906	0.063
101	81	4.993	4.955	0.038
101	82	5.001	4.913	0.088
101	85	4.999	4.948	0.051
101	94	5.005	4.941	0.065
101	95	4.990	4.941	0.049
101	99	4.995	4.937	0.058
101	103	5.002	4.899	0.102
101	109	5.002	4.941	0.062
101	110	5.003	4.882	0.122
101	112	4.983	4.915	0.068
101	115	5.001	4.957	0.045
101	117	4.979	4.954	0.024
101	118	4.990	4.955	0.034
101	122	5.003	4.970	0.032
101	125	5.016	4.965	0.052
101	126	5.010	4.940	0.069
101	129	5.009	4.919	0.090
	Max	5.024	5.024	0.122
	Average	4.997	4.961	0.035
	Min	4.959	4.882	0.000
	Std Dev	0.014	0.035	0.030



	1010.8_VREF @ VCC=9V to 22V	
Test Site		
Tester		
Test Number		
Max Limit	5.23	V
Min Limit	4.75	V

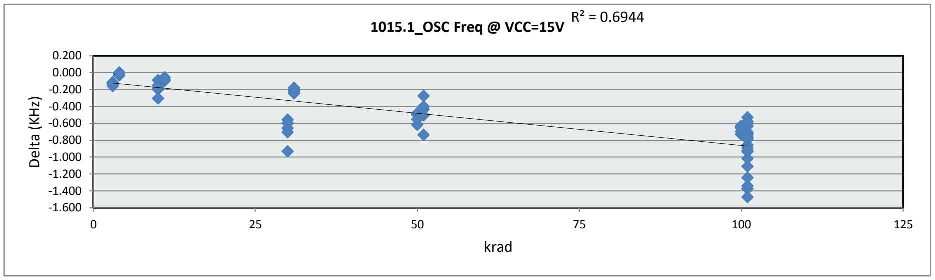
krad	3 biased	3 unbiased	10 biased	10 unbiased	30 biased	30 unbiased	50 biased	50 unbiased	100 biased	100 unbiased
LL	4.750	4.750	4.750	4.750	4.750	4.750	4.750	4.750	4.750	4.750
Min	4.976	4.984	4.964	4.970	4.906	4.973	4.924	4.940	4.925	4.882
Average	5.000	5.005	4.994	4.987	4.933	4.987	4.950	4.976	4.948	4.932
Max	5.011	5.024	5.014	5.005	4.965	5.001	4.973	5.001	4.971	4.971
UL	5.230	5.230	5.230	5.230	5.230	5.230	5.230	5.230	5.230	5.230



TID Report
Device Name

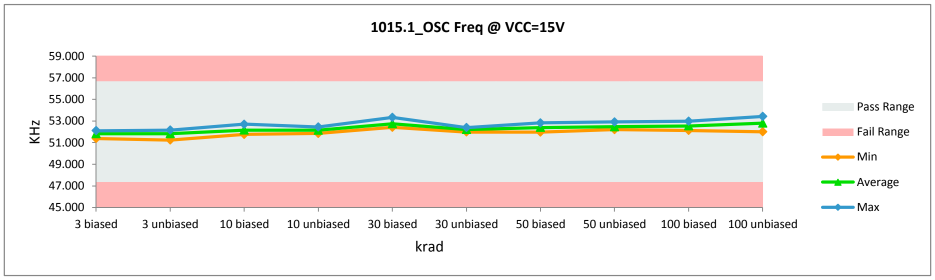
	1015.1_OSC Freq @ V	
Test Site		
Tester		
Test Number		
Unit	KHz	KHz
Max Limit	56.65	56.65
Min Limit	47.35	47.35

krad	Serial #	Pre	Post	Delta
3	135	51.922	52.063	-0.140
3	136	51.257	51.376	-0.120
3	138	51.945	52.104	-0.159
3	139	51.507	51.622	-0.115
3	143	51.870	51.997	-0.127
4	1	51.235	51.233	0.002
4	2	51.772	51.795	-0.022
4	3	52.062	52.078	-0.016
4	5	52.128	52.160	-0.032
4	7	51.863	51.875	-0.011
10	144	51.681	51.834	-0.153
10	145	51.667	51.757	-0.090
10	146	52.061	52.260	-0.199
10	149	52.036	52.220	-0.183
10	150	52.396	52.701	-0.304
11	8	52.360	52.447	-0.087
11	11	52.091	52.189	-0.098
11	14	51.790	51.848	-0.058
11	15	52.109	52.166	-0.057
11	19	52.012	52.091	-0.079
30	151	52.054	52.612	-0.557
30	153	51.751	52.408	-0.657
30	154	51.946	52.652	-0.706
30	155	52.403	53.334	-0.932
30	156	52.115	52.713	-0.598
31	22	52.018	52.264	-0.246
31	23	51.866	52.071	-0.205
31	31	52.181	52.397	-0.216
31	37	52.151	52.388	-0.236
31	42	51.796	51.976	-0.180
50	173	52.061	52.680	-0.618
50	174	52.328	52.824	-0.495
50	175	51.604	52.099	-0.495
50	183	51.492	51.974	-0.482
50	187	51.882	52.436	-0.554
51	43	52.064	52.499	-0.435
51	45	52.176	52.913	-0.737
51	48	51.924	52.201	-0.277
51	49	52.057	52.458	-0.401
51	50	51.783	52.288	-0.505
100	191	52.061	52.792	-0.730
100	195	52.328	52.977	-0.648
100	199	51.604	52.259	-0.655
100	203	51.492	52.122	-0.630
100	207	51.882	52.579	-0.698
101	69	51.844	52.862	-1.018
101	70	52.105	52.872	-0.767
101	71	51.859	53.235	-1.375
101	74	51.916	52.642	-0.726
101	76	51.959	52.893	-0.934
101	81	51.859	52.493	-0.635
101	82	51.784	52.893	-1.110
101	85	51.865	52.571	-0.706
101	94	51.749	52.608	-0.859
101	95	51.863	52.625	-0.762
101	99	52.201	52.991	-0.790
101	103	52.086	53.429	-1.343
101	109	52.005	52.939	-0.935
101	110	51.897	53.370	-1.473
101	112	52.225	53.117	-0.892
101	115	51.812	52.548	-0.736
101	117	51.846	52.376	-0.530
101	118	51.789	52.395	-0.606
101	122	51.427	52.007	-0.581
101	125	52.172	52.940	-0.768
101	126	51.924	52.852	-0.927
101	129	51.647	52.891	-1.244
	Max	52.403	53.429	0.002
	Average	51.920	52.437	-0.517
	Min	51.235	51.233	-1.473
	Std Dev	0.249	0.464	0.372



	1015.1_OSC Freq @ VCC=15V	
Test Site		
Tester		
Test Number		
Max Limit	56.65	KHz
Min Limit	47.35	KHz

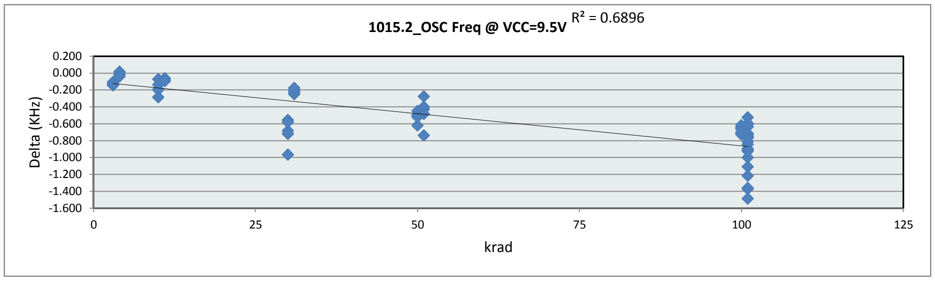
krad	3 biased	3 unbiased	10 biased	10 unbiased	30 biased	30 unbiased	50 biased	50 unbiased	100 biased	100 unbiased
LL	47.350	47.350	47.350	47.350	47.350	47.350	47.350	47.350	47.350	47.350
Min	51.376	51.233	51.757	51.848	52.408	51.976	51.974	52.201	52.122	52.007
Average	51.832	51.828	52.154	52.148	52.744	52.219	52.402	52.472	52.546	52.798
Max	52.104	52.160	52.701	52.447	53.335	52.397	52.824	52.913	52.977	53.429
UL	56.650	56.650	56.650	56.650	56.650	56.650	56.650	56.650	56.650	56.650



TID Report
Device Name

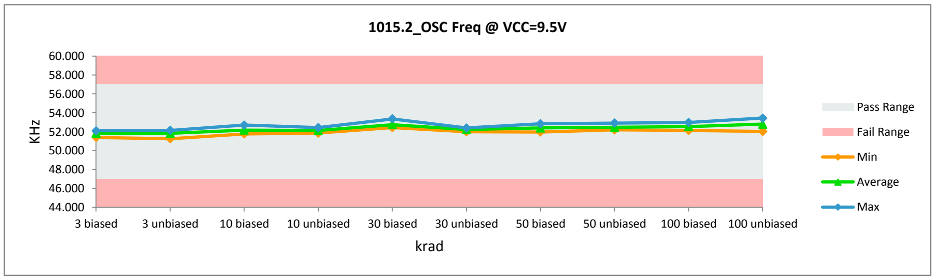
	1015.2_OSC Freq @ V	
Test Site		
Tester		
Test Number		
Unit	KHz	KHz
Max Limit	57	57
Min Limit	47	47

krad	Serial #	Pre	Post	Delta
3	135	51.943	52.071	-0.128
3	136	51.255	51.398	-0.142
3	138	51.954	52.099	-0.145
3	139	51.518	51.625	-0.107
3	143	51.868	52.006	-0.138
4	1	51.245	51.263	-0.018
4	2	51.778	51.795	-0.017
4	3	52.075	52.059	0.015
4	5	52.145	52.147	-0.002
4	7	51.853	51.895	-0.042
10	144	51.706	51.845	-0.140
10	145	51.694	51.767	-0.074
10	146	52.075	52.273	-0.199
10	149	52.043	52.238	-0.195
10	150	52.418	52.705	-0.287
11	8	52.371	52.442	-0.071
11	11	52.092	52.189	-0.096
11	14	51.792	51.856	-0.064
11	15	52.100	52.164	-0.063
11	19	52.012	52.101	-0.089
30	151	52.062	52.619	-0.558
30	153	51.751	52.435	-0.684
30	154	51.940	52.662	-0.722
30	155	52.403	53.369	-0.966
30	156	52.130	52.713	-0.583
31	22	52.026	52.278	-0.251
31	23	51.866	52.084	-0.219
31	31	52.200	52.399	-0.199
31	37	52.153	52.384	-0.231
31	42	51.813	51.991	-0.178
50	173	52.070	52.692	-0.622
50	174	52.338	52.834	-0.496
50	175	51.602	52.107	-0.505
50	183	51.513	51.964	-0.451
50	187	51.895	52.417	-0.522
51	43	52.064	52.495	-0.431
51	45	52.177	52.918	-0.741
51	48	51.919	52.195	-0.277
51	49	52.063	52.463	-0.400
51	50	51.796	52.281	-0.485
100	191	52.070	52.795	-0.725
100	195	52.338	52.987	-0.649
100	199	51.602	52.263	-0.661
100	203	51.513	52.133	-0.620
100	207	51.895	52.602	-0.706
101	69	51.860	52.862	-1.001
101	70	52.104	52.865	-0.762
101	71	51.868	53.243	-1.375
101	74	51.905	52.653	-0.748
101	76	51.966	52.892	-0.926
101	81	51.872	52.510	-0.638
101	82	51.789	52.899	-1.110
101	85	51.870	52.598	-0.728
101	94	51.764	52.610	-0.846
101	95	51.869	52.617	-0.748
101	99	52.191	53.003	-0.811
101	103	52.076	53.437	-1.362
101	109	52.037	52.936	-0.899
101	110	51.903	53.391	-1.488
101	112	52.227	53.130	-0.904
101	115	51.829	52.547	-0.718
101	117	51.853	52.378	-0.526
101	118	51.804	52.412	-0.608
101	122	51.433	52.029	-0.596
101	125	52.181	52.951	-0.770
101	126	51.930	52.851	-0.921
101	129	51.660	52.877	-1.216
	Max	52.418	53.437	0.015
	Average	51.927	52.443	-0.516
	Min	51.245	51.263	-1.488
	Std Dev	0.248	0.464	0.374



	1015.2_OSC Freq @ VCC=9.5V	
Test Site		
Tester		
Test Number		
Max Limit	57	KHz
Min Limit	47	KHz

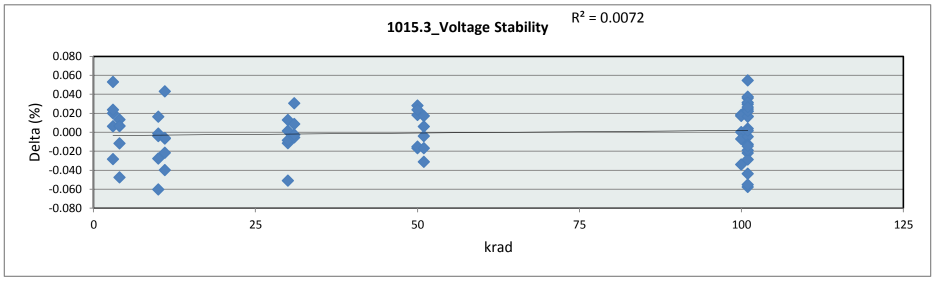
krad	3 biased	3 unbiased	10 biased	10 unbiased	30 biased	30 unbiased	50 biased	50 unbiased	100 biased	100 unbiased
LL	47.000	47.000	47.000	47.000	47.000	47.000	47.000	47.000	47.000	47.000
Min	51.398	51.263	51.767	51.856	52.435	51.991	51.964	52.196	52.133	52.029
Average	51.840	51.832	52.166	52.150	52.760	52.227	52.403	52.471	52.556	52.804
Max	52.099	52.147	52.705	52.442	53.369	52.399	52.834	52.918	52.988	53.437
UL	57.000	57.000	57.000	57.000	57.000	57.000	57.000	57.000	57.000	57.000



TID Report
Device Name

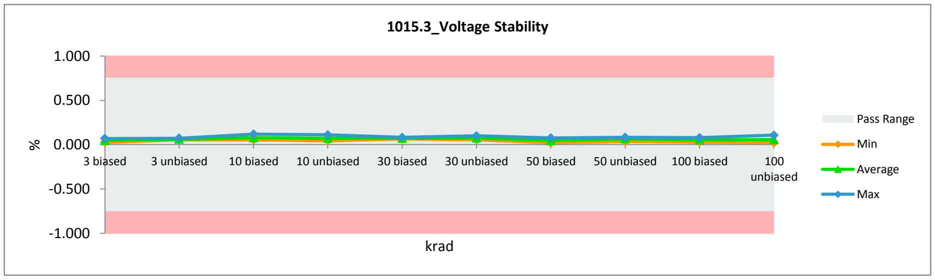
	1015.3_Voltage Stabil	
Test Site		
Tester		
Test Number		
Unit	%	%
Max Limit	0.75	0.75
Min Limit	-0.75	-0.75

krad	Serial #	Pre	Post	Delta
3	135	0.079	0.026	0.053
3	136	0.074	0.068	0.006
3	138	0.089	0.069	0.020
3	139	0.020	0.048	-0.028
3	143	0.056	0.032	0.024
4	1	0.043	0.054	-0.012
4	2	0.065	0.059	0.006
4	3	0.077	0.064	0.013
4	5	0.067	0.060	0.006
4	7	0.026	0.073	-0.047
10	144	0.038	0.066	-0.028
10	145	0.070	0.053	0.016
10	146	0.059	0.119	-0.060
10	149	0.061	0.062	-0.001
10	150	0.082	0.086	-0.004
11	8	0.066	0.073	-0.007
11	11	0.044	0.050	-0.006
11	14	0.071	0.111	-0.040
11	15	0.067	0.089	-0.022
11	19	0.087	0.045	0.043
30	151	0.052	0.064	-0.012
30	153	0.068	0.076	-0.009
30	154	0.084	0.082	0.001
30	155	0.023	0.074	-0.051
30	156	0.078	0.065	0.013
31	22	0.099	0.091	0.009
31	23	0.049	0.055	-0.006
31	31	0.063	0.066	-0.003
31	37	0.096	0.099	-0.003
31	42	0.096	0.065	0.030
50	173	0.078	0.060	0.018
50	174	0.048	0.020	0.028
50	175	0.059	0.076	-0.017
50	183	0.043	0.020	0.024
50	187	0.042	0.057	-0.015
51	43	0.041	0.058	-0.017
51	45	0.080	0.074	0.006
51	48	0.054	0.037	0.017
51	49	0.052	0.083	-0.031
51	50	0.068	0.072	-0.004
100	191	0.078	0.077	0.000
100	195	0.048	0.030	0.018
100	199	0.059	0.042	0.017
100	203	0.043	0.050	-0.007
100	207	0.042	0.076	-0.034
101	69	0.031	0.052	-0.022
101	70	0.070	0.053	0.016
101	71	0.073	0.044	0.029
101	74	0.072	0.051	0.022
101	76	0.063	0.107	-0.044
101	81	0.039	0.043	-0.005
101	82	0.102	0.078	0.024
101	85	0.124	0.069	0.054
101	94	0.010	0.068	-0.058
101	95	0.078	0.042	0.036
101	99	0.025	0.054	-0.029
101	103	0.066	0.050	0.017
101	109	0.026	0.022	0.004
101	110	0.071	0.083	-0.013
101	112	0.091	0.069	0.022
101	115	0.063	0.026	0.037
101	117	0.037	0.035	0.002
101	118	0.025	0.044	-0.019
101	122	0.078	0.047	0.031
101	125	0.029	0.084	-0.055
101	126	0.041	0.056	-0.015
101	129	0.094	0.067	0.026
	Max	0.124	0.119	0.054
	Average	0.061	0.062	0.000
	Min	0.010	0.020	-0.060
	Std Dev	0.023	0.021	0.026



	1015.3_Voltage Stability	
Test Site		
Tester		
Test Number		
Max Limit	0.75	%
Min Limit	-0.75	%

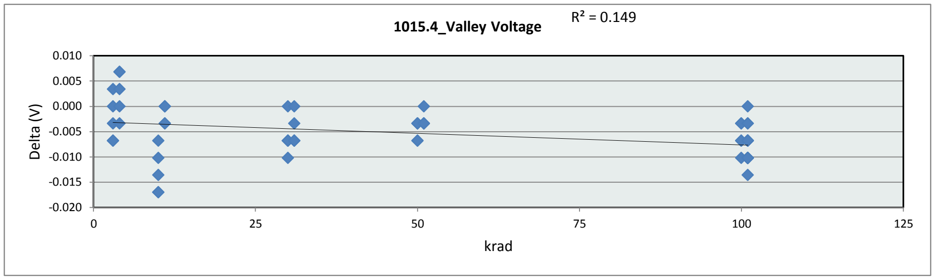
krad	3 biased	3 unbiased	10 biased	10 unbiased	30 biased	30 unbiased	50 biased	50 unbiased	100 biased	100 unbiased
LL	-0.750	-0.750	-0.750	-0.750	-0.750	-0.750	-0.750	-0.750	-0.750	-0.750
Min	0.026	0.055	0.053	0.045	0.064	0.055	0.020	0.037	0.030	0.022
Average	0.049	0.062	0.077	0.074	0.072	0.075	0.046	0.065	0.055	0.057
Max	0.069	0.074	0.119	0.111	0.082	0.099	0.076	0.083	0.077	0.107
UL	0.750	0.750	0.750	0.750	0.750	0.750	0.750	0.750	0.750	0.750



TID Report
Device Name

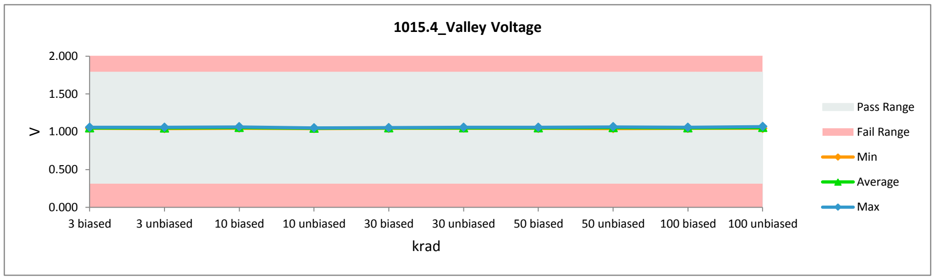
	1015.4_Valley Voltage	
Test Site		
Tester		
Test Number		
Unit	V	V
Max Limit	1.789	1.789
Min Limit	0.311	0.311

krad	Serial #	Pre	Post	Delta
3	135	1.041	1.048	-0.007
3	136	1.059	1.059	0.000
3	138	1.055	1.052	0.003
3	139	1.052	1.059	-0.007
3	143	1.041	1.045	-0.003
4	1	1.055	1.052	0.003
4	2	1.055	1.059	-0.003
4	3	1.041	1.041	0.000
4	5	1.059	1.052	0.007
4	7	1.052	1.045	0.007
10	144	1.048	1.065	-0.017
10	145	1.045	1.062	-0.017
10	146	1.038	1.048	-0.010
10	149	1.045	1.059	-0.014
10	150	1.041	1.048	-0.007
11	8	1.041	1.045	-0.003
11	11	1.041	1.041	0.000
11	14	1.048	1.052	-0.003
11	15	1.045	1.045	0.000
11	19	1.045	1.045	0.000
30	151	1.041	1.052	-0.010
30	153	1.048	1.055	-0.007
30	154	1.045	1.052	-0.007
30	155	1.045	1.045	0.000
30	156	1.045	1.052	-0.007
31	22	1.052	1.059	-0.007
31	23	1.052	1.052	0.000
31	31	1.045	1.048	-0.003
31	37	1.041	1.048	-0.007
31	42	1.041	1.048	-0.007
50	173	1.041	1.045	-0.003
50	174	1.045	1.048	-0.003
50	175	1.048	1.052	-0.003
50	183	1.041	1.048	-0.007
50	187	1.052	1.059	-0.007
51	43	1.055	1.059	-0.003
51	45	1.062	1.065	-0.003
51	48	1.045	1.048	-0.003
51	49	1.041	1.041	0.000
51	50	1.048	1.052	-0.003
100	191	1.041	1.045	-0.003
100	195	1.045	1.048	-0.003
100	199	1.048	1.059	-0.010
100	203	1.041	1.048	-0.007
100	207	1.052	1.059	-0.007
101	69	1.052	1.055	-0.003
101	70	1.035	1.045	-0.010
101	71	1.052	1.062	-0.010
101	74	1.055	1.055	0.000
101	76	1.048	1.055	-0.007
101	81	1.045	1.055	-0.010
101	82	1.052	1.062	-0.010
101	85	1.048	1.059	-0.010
101	94	1.045	1.052	-0.007
101	95	1.048	1.055	-0.007
101	99	1.048	1.059	-0.010
101	103	1.038	1.048	-0.010
101	109	1.041	1.052	-0.010
101	110	1.062	1.069	-0.007
101	112	1.045	1.052	-0.007
101	115	1.052	1.062	-0.010
101	117	1.038	1.052	-0.014
101	118	1.045	1.052	-0.007
101	122	1.052	1.062	-0.010
101	125	1.041	1.048	-0.007
101	126	1.048	1.052	-0.003
101	129	1.052	1.062	-0.010
	Max	1.062	1.069	0.007
	Average	1.047	1.053	-0.006
	Min	1.035	1.041	-0.017
	Std Dev	0.006	0.006	0.005



	1015.4_Valley Voltage	
Test Site		
Tester		
Test Number		
Max Limit	1.789	V
Min Limit	0.311	V

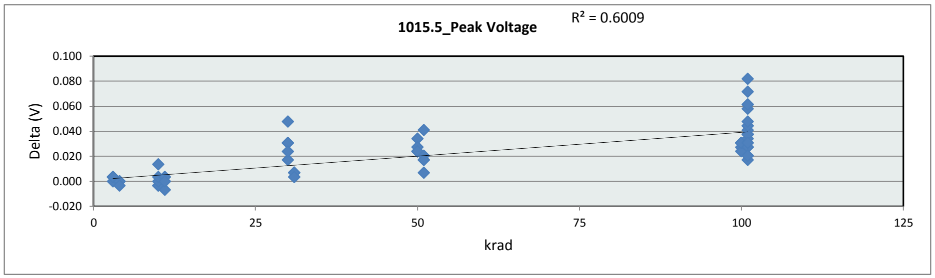
krad	3 biased	3 unbiased	10 biased	10 unbiased	30 biased	30 unbiased	50 biased	50 unbiased	100 biased	100 unbiased
LL	0.311	0.311	0.311	0.311	0.311	0.311	0.311	0.311	0.311	0.311
Min	1.045	1.042	1.048	1.042	1.045	1.048	1.045	1.042	1.045	1.045
Average	1.052	1.050	1.056	1.046	1.051	1.051	1.050	1.053	1.052	1.056
Max	1.059	1.059	1.065	1.052	1.055	1.059	1.059	1.065	1.059	1.069
UL	1.789	1.789	1.789	1.789	1.789	1.789	1.789	1.789	1.789	1.789



TID Report
Device Name

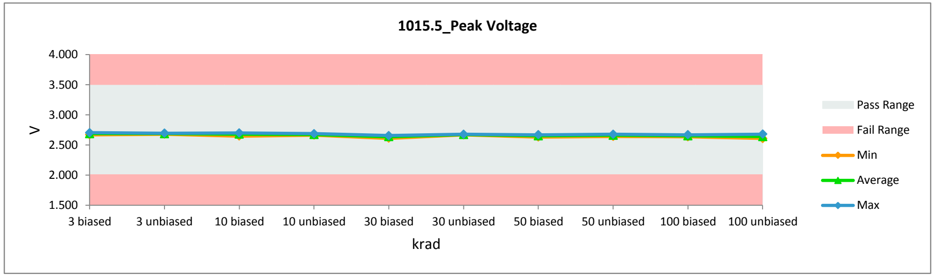
	1015.5_Peak Voltage	
Test Site		
Tester		
Test Number		
Unit	V	V
Max Limit	3.489	3.489
Min Limit	2.011	2.011

krad	Serial #	Pre	Post	Delta
3	135	2.684	2.680	0.003
3	136	2.704	2.704	0.000
3	138	2.687	2.684	0.003
3	139	2.701	2.697	0.003
3	143	2.673	2.670	0.003
4	1	2.697	2.697	0.000
4	2	2.687	2.687	0.000
4	3	2.687	2.687	0.000
4	5	2.680	2.680	0.000
4	7	2.687	2.690	-0.003
10	144	2.694	2.697	-0.003
10	145	2.697	2.701	-0.003
10	146	2.677	2.677	0.000
10	149	2.677	2.673	0.003
10	150	2.663	2.649	0.014
11	8	2.663	2.663	0.000
11	11	2.670	2.667	0.003
11	14	2.690	2.687	0.003
11	15	2.663	2.670	-0.007
11	19	2.677	2.677	0.000
30	151	2.673	2.656	0.017
30	153	2.687	2.656	0.031
30	154	2.663	2.632	0.031
30	155	2.660	2.612	0.048
30	156	2.660	2.636	0.024
31	22	2.677	2.670	0.007
31	23	2.684	2.677	0.007
31	31	2.680	2.677	0.003
31	37	2.673	2.667	0.007
31	42	2.677	2.673	0.003
50	173	2.667	2.632	0.034
50	174	2.667	2.643	0.024
50	175	2.690	2.663	0.027
50	183	2.694	2.670	0.024
50	187	2.680	2.656	0.024
51	43	2.690	2.670	0.020
51	45	2.684	2.643	0.041
51	48	2.684	2.677	0.007
51	49	2.680	2.663	0.017
51	50	2.673	2.656	0.017
100	191	2.667	2.636	0.031
100	195	2.667	2.639	0.027
100	199	2.690	2.660	0.031
100	203	2.694	2.670	0.024
100	207	2.680	2.649	0.031
101	69	2.680	2.636	0.044
101	70	2.656	2.622	0.034
101	71	2.687	2.615	0.072
101	74	2.677	2.646	0.031
101	76	2.667	2.626	0.041
101	81	2.680	2.653	0.027
101	82	2.694	2.636	0.058
101	85	2.690	2.653	0.037
101	94	2.687	2.649	0.038
101	95	2.677	2.649	0.027
101	99	2.673	2.636	0.037
101	103	2.673	2.612	0.061
101	109	2.673	2.636	0.037
101	110	2.690	2.609	0.082
101	112	2.667	2.622	0.044
101	115	2.684	2.656	0.027
101	117	2.670	2.653	0.017
101	118	2.680	2.660	0.021
101	122	2.701	2.680	0.020
101	125	2.680	2.649	0.031
101	126	2.687	2.639	0.048
101	129	2.694	2.632	0.061
	Max	2.704	2.704	0.082
	Average	2.680	2.658	0.022
	Min	2.656	2.609	-0.007
	Std Dev	0.011	0.023	0.020



	1015.5_Peak Voltage	
Test Site		
Tester		
Test Number		
Max Limit	3.489	V
Min Limit	2.011	V

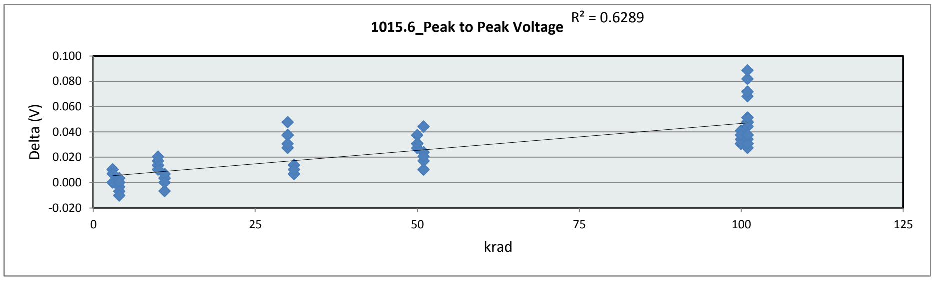
krad	3 biased	3 unbiased	10 biased	10 unbiased	30 biased	30 unbiased	50 biased	50 unbiased	100 biased	100 unbiased
LL	2.011	2.011	2.011	2.011	2.011	2.011	2.011	2.011	2.011	2.011
Min	2.670	2.680	2.650	2.663	2.612	2.667	2.633	2.643	2.636	2.609
Average	2.687	2.688	2.679	2.673	2.639	2.673	2.653	2.662	2.651	2.640
Max	2.704	2.697	2.701	2.687	2.656	2.677	2.670	2.677	2.670	2.680
UL	3.489	3.489	3.489	3.489	3.489	3.489	3.489	3.489	3.489	3.489



TID Report
Device Name

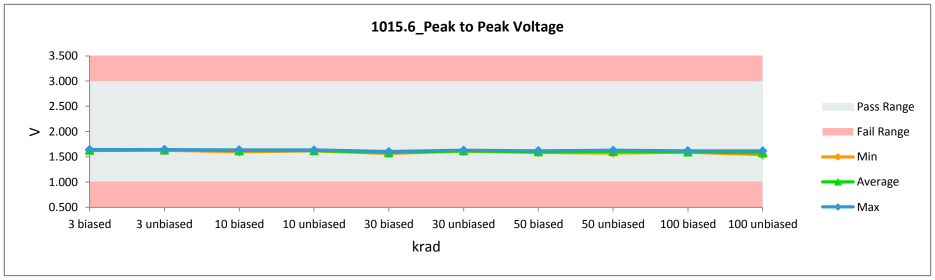
	1015.6_Peak to Peak	
Test Site		
Tester		
Test Number		
Unit	V	V
Max Limit	2.989	2.989
Min Limit	1.011	1.011

krad	Serial #	Pre	Post	Delta
3	135	1.642	1.632	0.010
3	136	1.645	1.645	0.000
3	138	1.632	1.632	0.000
3	139	1.649	1.639	0.010
3	143	1.632	1.625	0.007
4	1	1.642	1.645	-0.003
4	2	1.632	1.628	0.003
4	3	1.645	1.645	0.000
4	5	1.622	1.628	-0.007
4	7	1.635	1.645	-0.010
10	144	1.645	1.632	0.014
10	145	1.652	1.639	0.014
10	146	1.639	1.628	0.010
10	149	1.632	1.615	0.017
10	150	1.622	1.601	0.020
11	8	1.622	1.618	0.003
11	11	1.628	1.625	0.003
11	14	1.642	1.635	0.007
11	15	1.618	1.625	-0.007
11	19	1.632	1.632	0.000
30	151	1.632	1.605	0.027
30	153	1.639	1.601	0.038
30	154	1.618	1.581	0.037
30	155	1.615	1.567	0.048
30	156	1.615	1.584	0.031
31	22	1.625	1.611	0.014
31	23	1.632	1.625	0.007
31	31	1.635	1.628	0.007
31	37	1.632	1.618	0.014
31	42	1.635	1.625	0.010
50	173	1.625	1.588	0.037
50	174	1.622	1.594	0.027
50	175	1.642	1.611	0.031
50	183	1.652	1.622	0.031
50	187	1.628	1.598	0.031
51	43	1.635	1.611	0.024
51	45	1.622	1.577	0.044
51	48	1.639	1.628	0.010
51	49	1.639	1.622	0.017
51	50	1.625	1.605	0.021
100	191	1.625	1.591	0.034
100	195	1.622	1.591	0.031
100	199	1.642	1.601	0.041
100	203	1.652	1.622	0.031
100	207	1.628	1.591	0.038
101	69	1.628	1.581	0.048
101	70	1.622	1.577	0.044
101	71	1.635	1.554	0.082
101	74	1.622	1.591	0.031
101	76	1.618	1.571	0.048
101	81	1.635	1.598	0.038
101	82	1.642	1.574	0.068
101	85	1.642	1.594	0.048
101	94	1.642	1.598	0.044
101	95	1.628	1.594	0.034
101	99	1.625	1.577	0.048
101	103	1.635	1.564	0.072
101	109	1.632	1.584	0.048
101	110	1.628	1.540	0.089
101	112	1.622	1.571	0.051
101	115	1.632	1.594	0.037
101	117	1.632	1.601	0.031
101	118	1.635	1.608	0.027
101	122	1.649	1.618	0.031
101	125	1.639	1.601	0.038
101	126	1.639	1.588	0.051
101	129	1.642	1.571	0.072
	Max	1.652	1.645	0.089
	Average	1.633	1.605	0.028
	Min	1.615	1.540	-0.010
	Std Dev	0.010	0.025	0.022



	1015.6_Peak to Peak Voltage	
Test Site		
Tester		
Test Number		
Max Limit	2.989	V
Min Limit	1.011	V

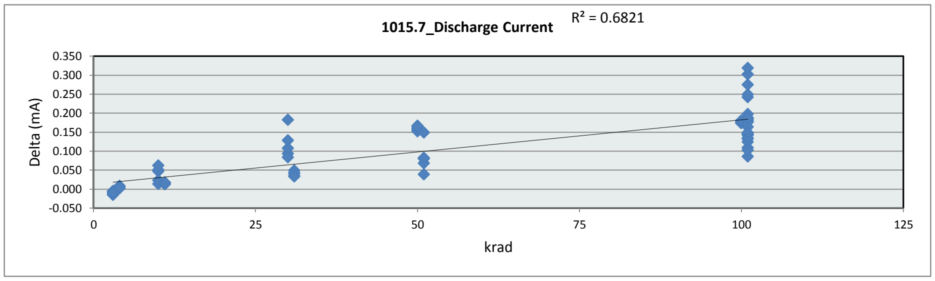
krad	3 biased	3 unbiased	10 biased	10 unbiased	30 biased	30 unbiased	50 biased	50 unbiased	100 biased	100 unbiased
LL	1.011	1.011	1.011	1.011	1.011	1.011	1.011	1.011	1.011	1.011
Min	1.625	1.629	1.601	1.618	1.567	1.611	1.588	1.577	1.591	1.540
Average	1.635	1.639	1.623	1.627	1.588	1.622	1.603	1.609	1.599	1.584
Max	1.646	1.646	1.639	1.635	1.605	1.629	1.622	1.629	1.622	1.618
UL	2.989	2.989	2.989	2.989	2.989	2.989	2.989	2.989	2.989	2.989



TID Report
Device Name

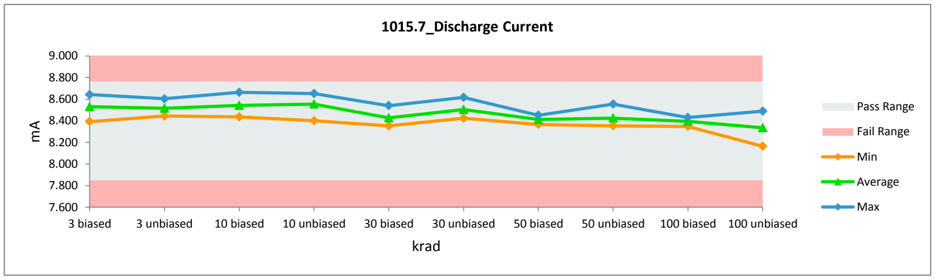
	1015.7_Discharge Cur	
Test Site		
Tester		
Test Number		
Unit	mA	mA
Max Limit	8.76	8.76
Min Limit	7.85	7.85

krad	Serial #	Pre	Post	Delta
3	135	8.629	8.642	-0.013
3	136	8.527	8.532	-0.005
3	138	8.386	8.393	-0.007
3	139	8.465	8.480	-0.015
3	143	8.592	8.601	-0.010
4	1	8.515	8.513	0.002
4	2	8.452	8.444	0.009
4	3	8.610	8.603	0.007
4	5	8.541	8.534	0.007
4	7	8.491	8.487	0.004
10	144	8.557	8.510	0.047
10	145	8.566	8.515	0.051
10	146	8.686	8.663	0.023
10	149	8.599	8.585	0.014
10	150	8.499	8.437	0.062
11	8	8.637	8.620	0.017
11	11	8.415	8.401	0.015
11	14	8.671	8.653	0.018
11	15	8.619	8.606	0.013
11	19	8.513	8.496	0.017
30	151	8.635	8.541	0.094
30	153	8.540	8.433	0.108
30	154	8.506	8.378	0.128
30	155	8.614	8.431	0.182
30	156	8.437	8.353	0.084
31	22	8.486	8.437	0.049
31	23	8.458	8.423	0.035
31	31	8.504	8.463	0.041
31	37	8.621	8.578	0.042
31	42	8.651	8.617	0.034
50	173	8.575	8.408	0.167
50	174	8.523	8.366	0.157
50	175	8.604	8.452	0.152
50	183	8.575	8.415	0.160
50	187	8.582	8.417	0.165
51	43	8.435	8.354	0.080
51	45	8.593	8.444	0.149
51	48	8.594	8.555	0.039
51	49	8.469	8.400	0.068
51	50	8.457	8.375	0.082
100	191	8.575	8.401	0.174
100	195	8.523	8.348	0.174
100	199	8.604	8.430	0.174
100	203	8.575	8.397	0.177
100	207	8.582	8.402	0.181
101	69	8.524	8.326	0.198
101	70	8.423	8.290	0.133
101	71	8.655	8.353	0.302
101	74	8.525	8.382	0.143
101	76	8.543	8.365	0.179
101	81	8.527	8.402	0.125
101	82	8.639	8.397	0.242
101	85	8.374	8.232	0.142
101	94	8.519	8.337	0.182
101	95	8.531	8.384	0.147
101	99	8.394	8.230	0.164
101	103	8.440	8.165	0.275
101	109	8.533	8.356	0.176
101	110	8.497	8.177	0.319
101	112	8.401	8.215	0.186
101	115	8.547	8.412	0.135
101	117	8.504	8.418	0.086
101	118	8.526	8.417	0.109
101	122	8.357	8.254	0.103
101	125	8.637	8.488	0.149
101	126	8.570	8.381	0.188
101	129	8.630	8.380	0.249
	Max	8.686	8.663	0.319
	Average	8.537	8.431	0.106
	Min	8.357	8.165	-0.015
	Std Dev	0.078	0.112	0.084



	1015.7_Discharge Current	
Test Site		
Tester		
Test Number		
Max Limit	8.76	mA
Min Limit	7.85	mA

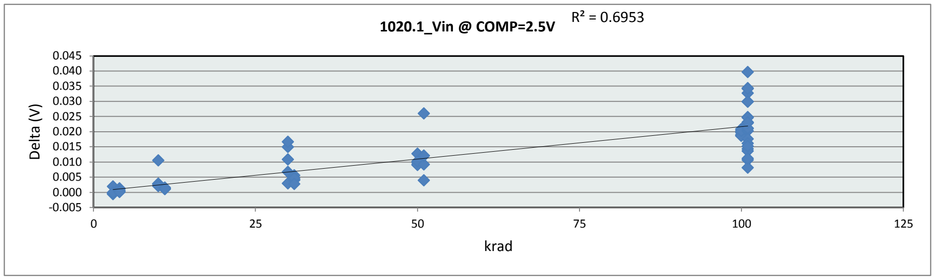
krad	3 biased	3 unbiased	10 biased	10 unbiased	30 biased	30 unbiased	50 biased	50 unbiased	100 biased	100 unbiased
LL	7.850	7.850	7.850	7.850	7.850	7.850	7.850	7.850	7.850	7.850
Min	8.393	8.444	8.437	8.401	8.353	8.423	8.366	8.354	8.349	8.165
Average	8.530	8.516	8.542	8.555	8.427	8.504	8.411	8.426	8.396	8.335
Max	8.642	8.603	8.663	8.653	8.541	8.617	8.452	8.555	8.430	8.488
UL	8.760	8.760	8.760	8.760	8.760	8.760	8.760	8.760	8.760	8.760



TID Report
Device Name

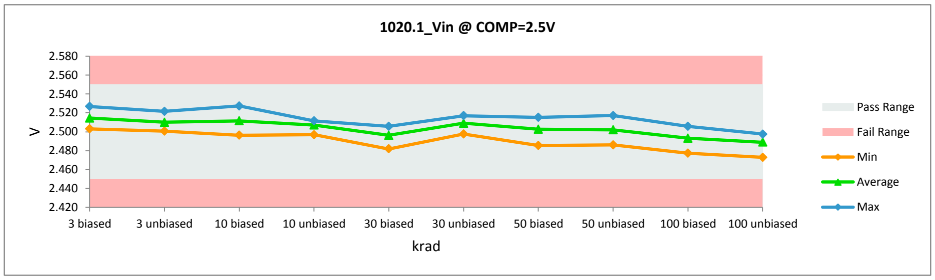
	1020.1_Vin @ COMP=	
Test Site		
Tester		
Test Number		
Unit	V	V
Max Limit	2.54	2.54
Min Limit	2.48	2.48

krad	Serial #	Pre	Post	Delta
3	135	2.516	2.516	0.000
3	136	2.526	2.527	-0.001
3	138	2.513	2.511	0.002
3	139	2.514	2.515	0.000
3	143	2.503	2.503	0.000
4	1	2.502	2.501	0.001
4	2	2.508	2.507	0.001
4	3	2.522	2.522	0.000
4	5	2.503	2.503	0.000
4	7	2.519	2.518	0.000
10	144	2.530	2.527	0.003
10	145	2.521	2.518	0.003
10	146	2.510	2.507	0.003
10	149	2.511	2.509	0.002
10	150	2.507	2.496	0.010
11	8	2.512	2.511	0.001
11	11	2.511	2.510	0.001
11	14	2.508	2.506	0.001
11	15	2.498	2.497	0.001
11	19	2.513	2.512	0.001
30	151	2.511	2.504	0.007
30	153	2.517	2.506	0.011
30	154	2.502	2.499	0.003
30	155	2.505	2.490	0.015
30	156	2.499	2.482	0.017
31	22	2.503	2.498	0.006
31	23	2.521	2.517	0.004
31	31	2.516	2.511	0.004
31	37	2.512	2.507	0.005
31	42	2.515	2.512	0.003
50	173	2.498	2.486	0.013
50	174	2.509	2.499	0.010
50	175	2.520	2.511	0.009
50	183	2.524	2.515	0.009
50	187	2.513	2.502	0.010
51	43	2.528	2.516	0.012
51	45	2.512	2.486	0.026
51	48	2.521	2.517	0.004
51	49	2.515	2.506	0.009
51	50	2.498	2.486	0.012
100	191	2.498	2.477	0.021
100	195	2.509	2.489	0.020
100	199	2.520	2.501	0.019
100	203	2.524	2.506	0.019
100	207	2.513	2.492	0.020
101	69	2.511	2.487	0.025
101	70	2.498	2.487	0.011
101	71	2.512	2.478	0.034
101	74	2.516	2.493	0.023
101	76	2.501	2.481	0.020
101	81	2.503	2.495	0.008
101	82	2.506	2.473	0.033
101	85	2.503	2.489	0.014
101	94	2.513	2.492	0.021
101	95	2.511	2.497	0.014
101	99	2.507	2.489	0.018
101	103	2.509	2.480	0.030
101	109	2.525	2.495	0.030
101	110	2.521	2.481	0.040
101	112	2.504	2.481	0.023
101	115	2.511	2.490	0.021
101	117	2.508	2.497	0.011
101	118	2.511	2.495	0.016
101	122	2.513	2.497	0.015
101	125	2.521	2.496	0.025
101	126	2.515	2.492	0.023
101	129	2.527	2.493	0.034
	Max	2.530	2.527	0.040
	Average	2.512	2.500	0.012
	Min	2.498	2.473	-0.001
	Std Dev	0.008	0.013	0.010



	1020.1_Vin @ COMP=2.5V	
Test Site		
Tester		
Test Number		
Max Limit	2.54	V
Min Limit	2.48	V

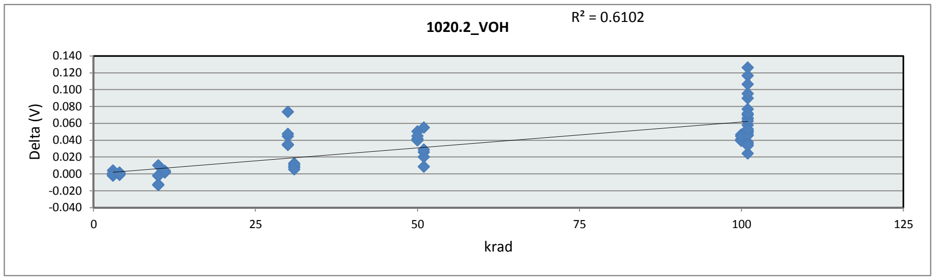
krad	3 biased	3 unbiased	10 biased	10 unbiased	30 biased	30 unbiased	50 biased	50 unbiased	100 biased	100 unbiased
LL	2.450	2.450	2.450	2.450	2.450	2.450	2.450	2.450	2.450	2.450
Min	2.503	2.501	2.496	2.497	2.482	2.498	2.486	2.486	2.477	2.473
Average	2.515	2.510	2.512	2.507	2.496	2.509	2.503	2.502	2.493	2.489
Max	2.527	2.522	2.527	2.512	2.506	2.517	2.515	2.517	2.506	2.497
UL	2.550	2.550	2.550	2.550	2.550	2.550	2.550	2.550	2.550	2.550



TID Report
Device Name

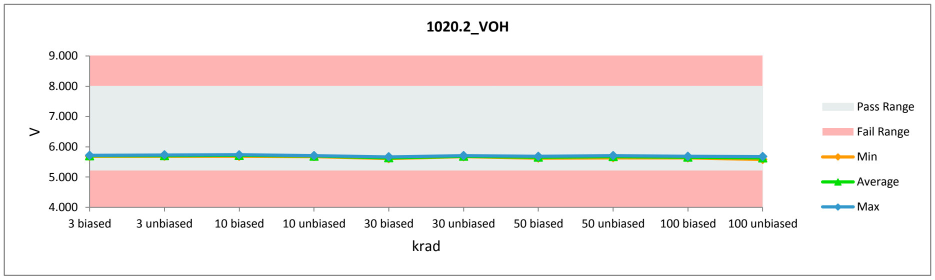
	1020.2_VOH		
Test Site			
Tester			
Test Number			
Unit	V	V	
Max Limit	8	8	
Min Limit	5.224	5.224	

krad	Serial #	Pre	Post	Delta
3	135	5.713	5.713	0.000
3	136	5.709	5.710	-0.001
3	138	5.703	5.699	0.004
3	139	5.707	5.709	-0.002
3	143	5.681	5.681	0.000
4	1	5.688	5.687	0.001
4	2	5.706	5.705	0.001
4	3	5.729	5.730	-0.001
4	5	5.704	5.704	0.000
4	7	5.714	5.714	0.000
10	144	5.716	5.729	-0.013
10	145	5.721	5.734	-0.013
10	146	5.718	5.721	-0.003
10	149	5.694	5.696	-0.002
10	150	5.691	5.680	0.010
11	8	5.693	5.690	0.004
11	11	5.691	5.688	0.003
11	14	5.711	5.709	0.002
11	15	5.678	5.676	0.002
11	19	5.696	5.693	0.003
30	151	5.702	5.668	0.034
30	153	5.698	5.653	0.045
30	154	5.672	5.625	0.047
30	155	5.680	5.607	0.074
30	156	5.668	5.633	0.035
31	22	5.683	5.670	0.012
31	23	5.708	5.700	0.008
31	31	5.713	5.705	0.008
31	37	5.701	5.690	0.010
31	42	5.692	5.687	0.005
50	173	5.677	5.626	0.050
50	174	5.701	5.659	0.041
50	175	5.703	5.662	0.041
50	183	5.720	5.681	0.040
50	187	5.689	5.644	0.045
51	43	5.715	5.689	0.026
51	45	5.690	5.635	0.055
51	48	5.715	5.707	0.008
51	49	5.715	5.695	0.020
51	50	5.690	5.661	0.029
100	191	5.677	5.630	0.047
100	195	5.701	5.660	0.041
100	199	5.703	5.664	0.039
100	203	5.720	5.680	0.040
100	207	5.689	5.644	0.045
101	69	5.695	5.618	0.077
101	70	5.660	5.614	0.046
101	71	5.704	5.588	0.116
101	74	5.691	5.640	0.050
101	76	5.669	5.604	0.065
101	81	5.697	5.660	0.038
101	82	5.699	5.610	0.090
101	85	5.696	5.645	0.051
101	94	5.703	5.637	0.066
101	95	5.693	5.644	0.049
101	99	5.694	5.636	0.058
101	103	5.706	5.600	0.106
101	109	5.703	5.641	0.063
101	110	5.708	5.582	0.126
101	112	5.681	5.611	0.070
101	115	5.707	5.662	0.046
101	117	5.681	5.656	0.024
101	118	5.693	5.657	0.036
101	122	5.708	5.675	0.034
101	125	5.715	5.662	0.053
101	126	5.710	5.638	0.072
101	129	5.710	5.615	0.095
	Max	5.729	5.734	0.126
	Average	5.699	5.665	0.034
	Min	5.660	5.582	-0.013
	Std Dev	0.014	0.037	0.032



	1020.2_VOH	
Test Site		
Tester		
Test Number		
Max Limit	8	V
Min Limit	5.224	V

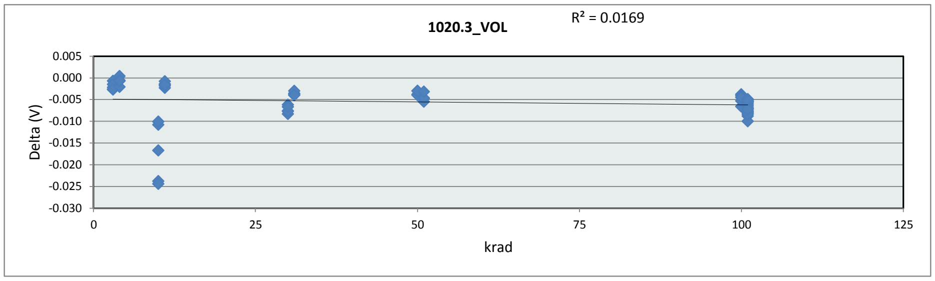
krad	3 biased	3 unbiased	10 biased	10 unbiased	30 biased	30 unbiased	50 biased	50 unbiased	100 biased	100 unbiased
LL	5.224	5.224	5.224	5.224	5.224	5.224	5.224	5.224	5.224	5.224
Min	5.681	5.687	5.680	5.676	5.607	5.671	5.626	5.635	5.630	5.582
Average	5.702	5.708	5.712	5.691	5.637	5.690	5.655	5.677	5.656	5.632
Max	5.713	5.730	5.735	5.710	5.668	5.705	5.681	5.707	5.680	5.675
UL	8.000	8.000	8.000	8.000	8.000	8.000	8.000	8.000	8.000	8.000



TID Report
Device Name

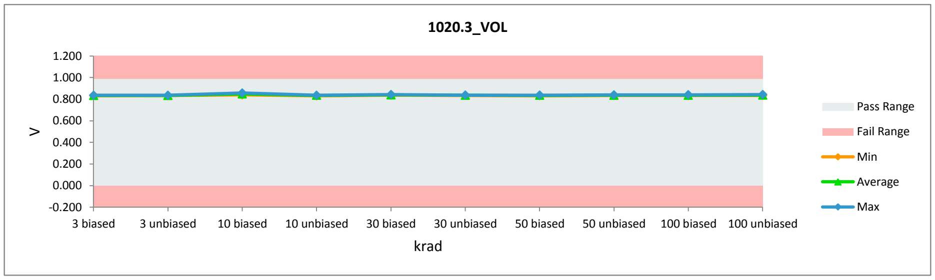
	1020.3_VOL	
Test Site		
Tester		
Test Number		
Unit	V	V
Max Limit	0.984	0.984
Min Limit	0	0

krad	Serial #	Pre	Post	Delta
3	135	0.831	0.832	-0.001
3	136	0.832	0.835	-0.002
3	138	0.832	0.834	-0.002
3	139	0.834	0.836	-0.003
3	143	0.830	0.833	-0.003
4	1	0.834	0.834	0.000
4	2	0.836	0.836	-0.001
4	3	0.831	0.833	-0.002
4	5	0.832	0.833	-0.001
4	7	0.833	0.833	-0.001
10	144	0.833	0.857	-0.024
10	145	0.829	0.853	-0.024
10	146	0.833	0.844	-0.011
10	149	0.830	0.840	-0.010
10	150	0.832	0.849	-0.017
11	8	0.836	0.837	-0.001
11	11	0.830	0.831	-0.001
11	14	0.835	0.837	-0.002
11	15	0.833	0.835	-0.002
11	19	0.835	0.837	-0.002
30	151	0.830	0.838	-0.008
30	153	0.832	0.839	-0.006
30	154	0.835	0.844	-0.008
30	155	0.836	0.843	-0.008
30	156	0.831	0.838	-0.007
31	22	0.834	0.837	-0.004
31	23	0.833	0.836	-0.004
31	31	0.830	0.834	-0.004
31	37	0.831	0.834	-0.003
31	42	0.832	0.836	-0.004
50	173	0.830	0.833	-0.003
50	174	0.830	0.834	-0.004
50	175	0.835	0.838	-0.004
50	183	0.831	0.835	-0.004
50	187	0.834	0.837	-0.003
51	43	0.831	0.836	-0.005
51	45	0.831	0.837	-0.006
51	48	0.831	0.835	-0.005
51	49	0.832	0.837	-0.005
51	50	0.836	0.839	-0.003
100	191	0.830	0.833	-0.004
100	195	0.830	0.835	-0.004
100	199	0.835	0.841	-0.007
100	203	0.831	0.837	-0.005
100	207	0.834	0.839	-0.004
101	69	0.832	0.838	-0.005
101	70	0.832	0.837	-0.006
101	71	0.835	0.843	-0.008
101	74	0.835	0.840	-0.005
101	76	0.832	0.840	-0.007
101	81	0.832	0.839	-0.007
101	82	0.833	0.842	-0.009
101	85	0.829	0.836	-0.007
101	94	0.832	0.839	-0.007
101	95	0.829	0.837	-0.008
101	99	0.829	0.837	-0.008
101	103	0.831	0.841	-0.010
101	109	0.829	0.837	-0.008
101	110	0.834	0.842	-0.008
101	112	0.830	0.836	-0.006
101	115	0.833	0.839	-0.006
101	117	0.831	0.836	-0.005
101	118	0.832	0.837	-0.005
101	122	0.832	0.837	-0.005
101	125	0.829	0.835	-0.005
101	126	0.832	0.837	-0.005
101	129	0.830	0.837	-0.007
	Max	0.836	0.857	0.000
	Average	0.832	0.838	-0.006
	Min	0.829	0.831	-0.024
	Std Dev	0.002	0.004	0.004



	1020.3_VOL	
Test Site		
Tester		
Test Number		
Max Limit	0.984	V
Min Limit	0	V

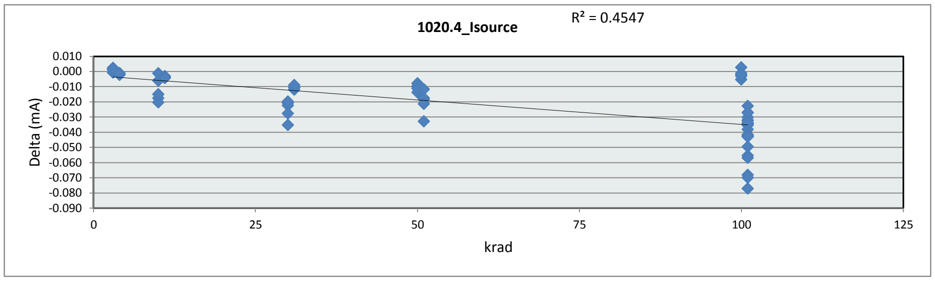
krad	3 biased	3 unbiased	10 biased	10 unbiased	30 biased	30 unbiased	50 biased	50 unbiased	100 biased	100 unbiased
LL	0.000	0.000	0.000	0.000	0.000	0.000	0.000	0.000	0.000	0.000
Min	0.832	0.833	0.840	0.831	0.838	0.834	0.833	0.835	0.833	0.835
Average	0.834	0.834	0.849	0.835	0.840	0.836	0.836	0.837	0.837	0.838
Max	0.836	0.837	0.857	0.837	0.844	0.837	0.838	0.839	0.841	0.843
UL	0.984	0.984	0.984	0.984	0.984	0.984	0.984	0.984	0.984	0.984



TID Report
Device Name

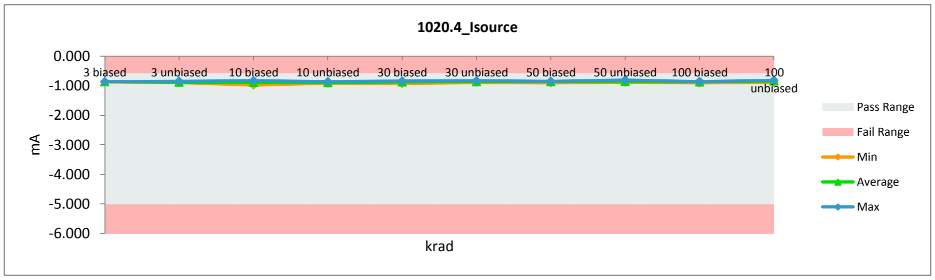
	1020.4_Isource	
Test Site		
Tester		
Test Number		
Unit	mA	mA
Max Limit	-0.565	-0.565
Min Limit	-5	-5

krad	Serial #	Pre	Post	Delta
3	135	-0.862	-0.864	0.002
3	136	-0.853	-0.855	0.002
3	138	-0.870	-0.870	-0.001
3	139	-0.859	-0.860	0.001
3	143	-0.872	-0.874	0.001
4	1	-0.864	-0.863	-0.001
4	2	-0.898	-0.896	-0.002
4	3	-0.890	-0.888	-0.002
4	5	-0.849	-0.847	-0.002
4	7	-0.894	-0.893	-0.001
10	144	-0.876	-0.859	-0.018
10	145	-0.848	-0.828	-0.020
10	146	-0.975	-0.974	-0.001
10	149	-0.876	-0.870	-0.006
10	150	-0.902	-0.887	-0.015
11	8	-0.898	-0.893	-0.004
11	11	-0.860	-0.857	-0.003
11	14	-0.892	-0.887	-0.004
11	15	-0.892	-0.889	-0.003
11	19	-0.917	-0.913	-0.004
30	151	-0.884	-0.863	-0.021
30	153	-0.890	-0.868	-0.022
30	154	-0.952	-0.924	-0.028
30	155	-0.872	-0.837	-0.035
30	156	-0.869	-0.849	-0.020
31	22	-0.844	-0.832	-0.012
31	23	-0.897	-0.886	-0.010
31	31	-0.880	-0.870	-0.010
31	37	-0.868	-0.857	-0.011
31	42	-0.886	-0.877	-0.009
50	173	-0.866	-0.852	-0.014
50	174	-0.861	-0.853	-0.008
50	175	-0.910	-0.900	-0.010
50	183	-0.881	-0.872	-0.010
50	187	-0.857	-0.845	-0.011
51	43	-0.856	-0.838	-0.018
51	45	-0.839	-0.806	-0.033
51	48	-0.892	-0.880	-0.012
51	49	-0.895	-0.877	-0.017
51	50	-0.900	-0.879	-0.021
100	191	-0.866	-0.860	-0.005
100	195	-0.861	-0.863	0.003
100	199	-0.910	-0.907	-0.003
100	203	-0.881	-0.880	-0.001
100	207	-0.857	-0.854	-0.002
101	69	-0.893	-0.843	-0.049
101	70	-0.854	-0.822	-0.032
101	71	-0.887	-0.818	-0.068
101	74	-0.886	-0.852	-0.034
101	76	-0.869	-0.826	-0.043
101	81	-0.911	-0.881	-0.030
101	82	-0.884	-0.829	-0.055
101	85	-0.861	-0.828	-0.032
101	94	-0.864	-0.822	-0.042
101	95	-0.892	-0.856	-0.035
101	99	-0.882	-0.844	-0.038
101	103	-0.916	-0.846	-0.070
101	109	-0.880	-0.837	-0.043
101	110	-0.926	-0.849	-0.077
101	112	-0.854	-0.812	-0.042
101	115	-0.913	-0.878	-0.035
101	117	-0.866	-0.843	-0.023
101	118	-0.879	-0.851	-0.027
101	122	-0.905	-0.878	-0.027
101	125	-0.859	-0.825	-0.034
101	126	-0.883	-0.840	-0.043
101	129	-0.871	-0.815	-0.057
	Max	-0.839	-0.806	0.003
	Average	-0.881	-0.861	-0.020
	Min	-0.975	-0.974	-0.077
	Std Dev	0.025	0.029	0.019



	1020.4_Isource	
Test Site		
Tester		
Test Number		
Max Limit	-0.565	mA
Min Limit	-5	mA

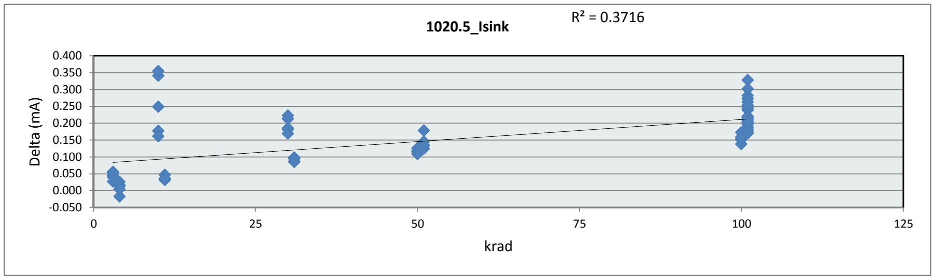
krad	3 biased	3 unbiased	10 biased	10 unbiased	30 biased	30 unbiased	50 biased	50 unbiased	100 biased	100 unbiased
LL	-5.000	-5.000	-5.000	-5.000	-5.000	-5.000	-5.000	-5.000	-5.000	-5.000
Min	-0.874	-0.897	-0.974	-0.913	-0.924	-0.886	-0.900	-0.880	-0.907	-0.881
Average	-0.865	-0.877	-0.883	-0.888	-0.868	-0.864	-0.864	-0.856	-0.873	-0.841
Max	-0.856	-0.847	-0.828	-0.857	-0.837	-0.832	-0.846	-0.806	-0.855	-0.812
UL	-0.565	-0.565	-0.565	-0.565	-0.565	-0.565	-0.565	-0.565	-0.565	-0.565



TID Report
Device Name

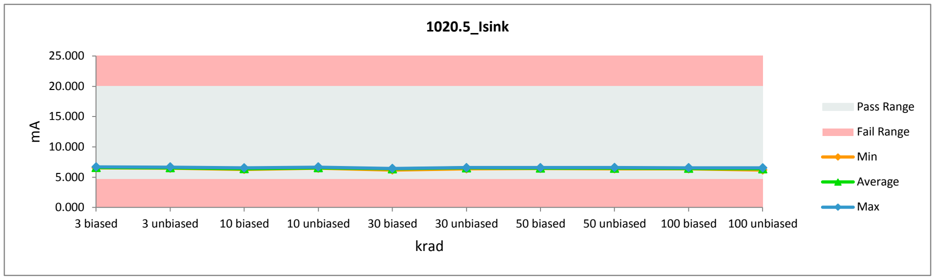
	1020.5_Isink	
Test Site		
Tester		
Test Number		
Unit	mA	mA
Max Limit	20	20
Min Limit	4.7	4.7

krad	Serial #	Pre	Post	Delta
3	135	6.620	6.593	0.027
3	136	6.656	6.611	0.045
3	138	6.552	6.511	0.040
3	139	6.566	6.511	0.055
3	143	6.727	6.674	0.053
4	1	6.616	6.633	-0.017
4	2	6.462	6.459	0.003
4	3	6.688	6.662	0.026
4	5	6.473	6.456	0.016
4	7	6.479	6.466	0.013
10	144	6.611	6.270	0.341
10	145	6.740	6.386	0.354
10	146	6.673	6.496	0.177
10	149	6.693	6.532	0.161
10	150	6.520	6.271	0.249
11	8	6.497	6.463	0.034
11	11	6.696	6.664	0.032
11	14	6.542	6.496	0.047
11	15	6.624	6.593	0.031
11	19	6.499	6.463	0.036
30	151	6.607	6.423	0.185
30	153	6.605	6.423	0.181
30	154	6.549	6.336	0.213
30	155	6.391	6.168	0.223
30	156	6.584	6.414	0.169
31	22	6.468	6.370	0.098
31	23	6.620	6.534	0.087
31	31	6.614	6.519	0.095
31	37	6.648	6.563	0.085
31	42	6.659	6.562	0.097
50	173	6.689	6.563	0.126
50	174	6.558	6.444	0.115
50	175	6.572	6.455	0.116
50	183	6.658	6.540	0.119
50	187	6.515	6.406	0.108
51	43	6.580	6.446	0.133
51	45	6.542	6.364	0.178
51	48	6.719	6.595	0.124
51	49	6.633	6.488	0.145
51	50	6.548	6.413	0.135
100	191	6.689	6.538	0.151
100	195	6.558	6.420	0.138
100	199	6.572	6.399	0.172
100	203	6.658	6.505	0.154
100	207	6.515	6.356	0.159
101	69	6.646	6.407	0.239
101	70	6.663	6.454	0.210
101	71	6.448	6.167	0.281
101	74	6.493	6.307	0.186
101	76	6.609	6.365	0.244
101	81	6.621	6.419	0.202
101	82	6.437	6.174	0.263
101	85	6.534	6.345	0.189
101	94	6.516	6.295	0.220
101	95	6.689	6.475	0.214
101	99	6.595	6.378	0.217
101	103	6.648	6.320	0.328
101	109	6.709	6.456	0.253
101	110	6.490	6.188	0.301
101	112	6.568	6.364	0.204
101	115	6.608	6.411	0.197
101	117	6.665	6.490	0.174
101	118	6.650	6.470	0.180
101	122	6.690	6.520	0.170
101	125	6.660	6.463	0.197
101	126	6.513	6.311	0.202
101	129	6.697	6.424	0.272
	Max	6.740	6.674	0.354
	Average	6.595	6.443	0.152
	Min	6.391	6.167	-0.017
	Std Dev	0.081	0.116	0.088



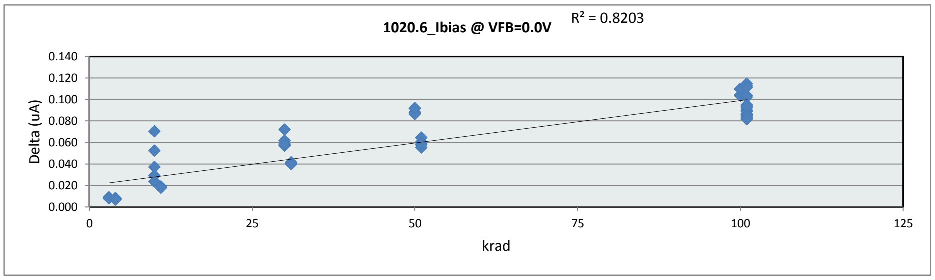
	1020.5_Isink	
Test Site		
Tester		
Test Number		
Max Limit	20	mA
Min Limit	4.7	mA

krad	3 biased	3 unbiased	10 biased	10 unbiased	30 biased	30 unbiased	50 biased	50 unbiased	100 biased	100 unbiased
LL	4.700	4.700	4.700	4.700	4.700	4.700	4.700	4.700	4.700	4.700
Min	6.511	6.456	6.270	6.463	6.168	6.370	6.406	6.364	6.356	6.167
Average	6.580	6.535	6.391	6.536	6.353	6.510	6.482	6.461	6.444	6.373
Max	6.674	6.662	6.532	6.664	6.423	6.563	6.563	6.595	6.538	6.520
UL	20.000	20.000	20.000	20.000	20.000	20.000	20.000	20.000	20.000	20.000

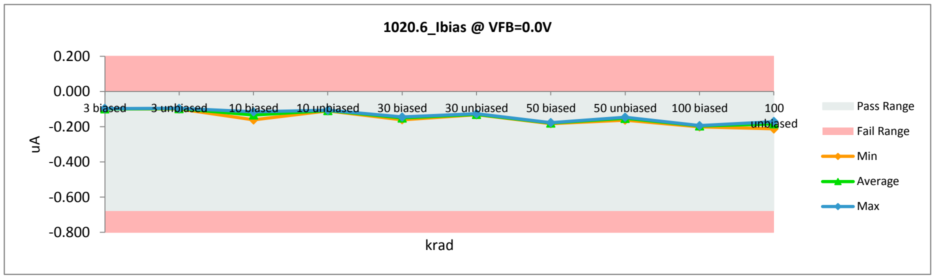


TID Report
Device Name

		1020.6_Ibias @ VFB=		
Test Site				
Tester				
Test Number				
Unit		uA	uA	
Max Limit		-0.001	-0.001	
Min Limit		-0.675	-0.675	
krad	Serial #	Pre	Post	Delta
3	135	-0.090	-0.098	0.008
3	136	-0.090	-0.099	0.008
3	138	-0.090	-0.099	0.009
3	139	-0.089	-0.097	0.008
3	143	-0.092	-0.100	0.008
4	1	-0.090	-0.097	0.007
4	2	-0.091	-0.100	0.008
4	3	-0.091	-0.099	0.008
4	5	-0.088	-0.096	0.008
4	7	-0.089	-0.097	0.007
10	144	-0.090	-0.128	0.037
10	145	-0.093	-0.116	0.024
10	146	-0.090	-0.142	0.052
10	149	-0.091	-0.161	0.070
10	150	-0.092	-0.121	0.029
11	8	-0.090	-0.109	0.019
11	11	-0.091	-0.110	0.019
11	14	-0.089	-0.108	0.019
11	15	-0.090	-0.108	0.019
11	19	-0.089	-0.107	0.018
30	151	-0.088	-0.145	0.057
30	153	-0.090	-0.149	0.059
30	154	-0.090	-0.152	0.062
30	155	-0.089	-0.161	0.072
30	156	-0.089	-0.146	0.058
31	22	-0.086	-0.127	0.040
31	23	-0.090	-0.131	0.041
31	31	-0.091	-0.132	0.041
31	37	-0.091	-0.131	0.040
31	42	-0.089	-0.129	0.040
50	173	-0.090	-0.178	0.088
50	174	-0.091	-0.183	0.092
50	175	-0.091	-0.178	0.087
50	183	-0.091	-0.177	0.086
50	187	-0.087	-0.179	0.092
51	43	-0.095	-0.153	0.058
51	45	-0.099	-0.163	0.064
51	48	-0.091	-0.146	0.055
51	49	-0.091	-0.152	0.060
51	50	-0.091	-0.149	0.058
100	191	-0.090	-0.194	0.104
100	195	-0.091	-0.201	0.110
100	199	-0.091	-0.194	0.104
100	203	-0.091	-0.194	0.103
100	207	-0.087	-0.197	0.110
101	69	-0.091	-0.193	0.102
101	70	-0.089	-0.175	0.086
101	71	-0.088	-0.201	0.113
101	74	-0.089	-0.175	0.086
101	76	-0.088	-0.177	0.089
101	81	-0.089	-0.172	0.083
101	82	-0.087	-0.191	0.104
101	85	-0.088	-0.174	0.087
101	94	-0.090	-0.185	0.095
101	95	-0.091	-0.180	0.089
101	99	-0.089	-0.178	0.090
101	103	-0.091	-0.206	0.115
101	109	-0.092	-0.186	0.095
101	110	-0.101	-0.213	0.111
101	112	-0.094	-0.187	0.092
101	115	-0.091	-0.176	0.086
101	117	-0.089	-0.171	0.082
101	118	-0.090	-0.174	0.084
101	122	-0.090	-0.172	0.082
101	125	-0.090	-0.183	0.094
101	126	-0.087	-0.181	0.094
101	129	-0.091	-0.203	0.111
	Max	-0.086	-0.096	0.115
	Average	-0.090	-0.154	0.063
	Min	-0.101	-0.213	0.007
	Std Dev	0.002	0.036	0.035

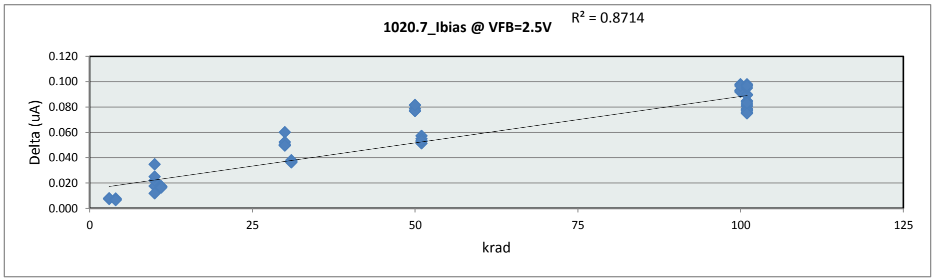


	1020.6_Ibias @ VFB=0.0V									
Test Site										
Tester										
Test Number										
Max Limit	-0.001 uA									
Min Limit	-0.675 uA									
krad	3 biased	3 unbiased	10 biased	10 unbiased	30 biased	30 unbiased	50 biased	50 unbiased	100 biased	100 unbiased
LL	-0.675	-0.675	-0.675	-0.675	-0.675	-0.675	-0.675	-0.675	-0.675	-0.675
Min	-0.100	-0.100	-0.161	-0.110	-0.161	-0.132	-0.183	-0.163	-0.201	-0.213
Average	-0.099	-0.098	-0.134	-0.109	-0.151	-0.130	-0.179	-0.153	-0.196	-0.184
Max	-0.097	-0.096	-0.116	-0.107	-0.145	-0.127	-0.177	-0.146	-0.194	-0.171
UL	-0.001	-0.001	-0.001	-0.001	-0.001	-0.001	-0.001	-0.001	-0.001	-0.001



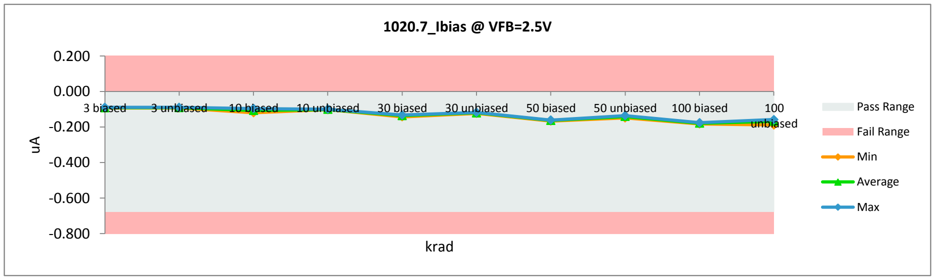
TID Report
Device Name

		1020.7_Ibias @ VFB=		
	Test Site			
	Tester			
	Test Number			
	Unit	uA	uA	
	Max Limit	-0.001	-0.001	
	Min Limit	-0.675	-0.675	
krad	Serial #	Pre	Post	Delta
3	135	-0.083	-0.091	0.008
3	136	-0.084	-0.091	0.008
3	138	-0.084	-0.092	0.008
3	139	-0.082	-0.089	0.008
3	143	-0.085	-0.092	0.008
4	1	-0.083	-0.090	0.007
4	2	-0.084	-0.092	0.008
4	3	-0.084	-0.092	0.007
4	5	-0.082	-0.089	0.007
4	7	-0.083	-0.089	0.007
10	144	-0.084	-0.101	0.018
10	145	-0.086	-0.108	0.022
10	146	-0.084	-0.096	0.012
10	149	-0.084	-0.119	0.035
10	150	-0.085	-0.110	0.025
11	8	-0.083	-0.101	0.017
11	11	-0.084	-0.102	0.017
11	14	-0.082	-0.100	0.017
11	15	-0.083	-0.100	0.017
11	19	-0.082	-0.099	0.016
30	151	-0.082	-0.132	0.050
30	153	-0.083	-0.134	0.050
30	154	-0.084	-0.137	0.052
30	155	-0.082	-0.142	0.060
30	156	-0.082	-0.132	0.050
31	22	-0.080	-0.117	0.037
31	23	-0.084	-0.121	0.037
31	31	-0.084	-0.122	0.038
31	37	-0.084	-0.121	0.037
31	42	-0.083	-0.119	0.036
50	173	-0.084	-0.160	0.077
50	174	-0.084	-0.166	0.081
50	175	-0.084	-0.162	0.079
50	183	-0.084	-0.161	0.077
50	187	-0.081	-0.163	0.081
51	43	-0.088	-0.141	0.053
51	45	-0.091	-0.148	0.057
51	48	-0.084	-0.135	0.051
51	49	-0.085	-0.140	0.055
51	50	-0.084	-0.137	0.053
100	191	-0.084	-0.176	0.092
100	195	-0.084	-0.182	0.098
100	199	-0.084	-0.177	0.093
100	203	-0.084	-0.177	0.093
100	207	-0.081	-0.178	0.097
101	69	-0.084	-0.174	0.089
101	70	-0.082	-0.159	0.077
101	71	-0.081	-0.178	0.097
101	74	-0.082	-0.160	0.079
101	76	-0.081	-0.160	0.078
101	81	-0.083	-0.158	0.075
101	82	-0.081	-0.170	0.090
101	85	-0.081	-0.159	0.079
101	94	-0.084	-0.168	0.085
101	95	-0.084	-0.164	0.080
101	99	-0.082	-0.163	0.081
101	103	-0.084	-0.182	0.098
101	109	-0.085	-0.170	0.085
101	110	-0.094	-0.189	0.095
101	112	-0.087	-0.170	0.082
101	115	-0.083	-0.161	0.078
101	117	-0.083	-0.158	0.075
101	118	-0.083	-0.160	0.077
101	122	-0.083	-0.158	0.075
101	125	-0.083	-0.168	0.084
101	126	-0.081	-0.164	0.083
101	129	-0.085	-0.181	0.097
	Max	-0.080	-0.089	0.098
	Average	-0.084	-0.139	0.055
	Min	-0.094	-0.189	0.007
	Std Dev	0.002	0.032	0.032



	1020.7_Ibias @ VFB=2.5V
Test Site	
Tester	
Test Number	
Max Limit	-0.001 uA
Min Limit	-0.675 uA

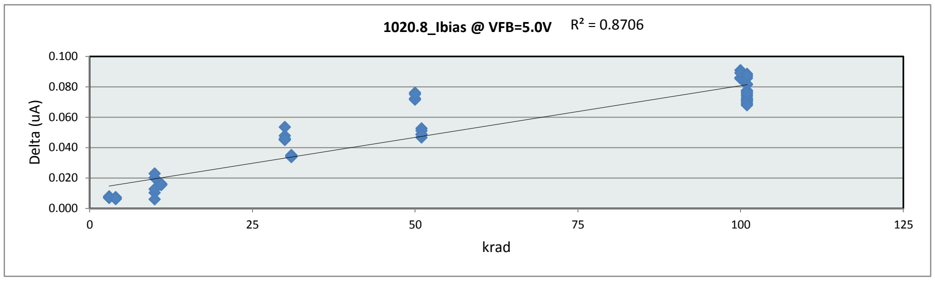
krad	3 biased	3 unbiased	10 biased	10 unbiased	30 biased	30 unbiased	50 biased	50 unbiased	100 biased	100 unbiased
LL	-0.675	-0.675	-0.675	-0.675	-0.675	-0.675	-0.675	-0.675	-0.675	-0.675
Min	-0.092	-0.092	-0.119	-0.102	-0.142	-0.122	-0.166	-0.148	-0.182	-0.189
Average	-0.091	-0.090	-0.107	-0.100	-0.135	-0.120	-0.162	-0.140	-0.178	-0.167
Max	-0.089	-0.089	-0.096	-0.099	-0.132	-0.117	-0.160	-0.136	-0.176	-0.158
UL	-0.001	-0.001	-0.001	-0.001	-0.001	-0.001	-0.001	-0.001	-0.001	-0.001



TID Report
Device Name

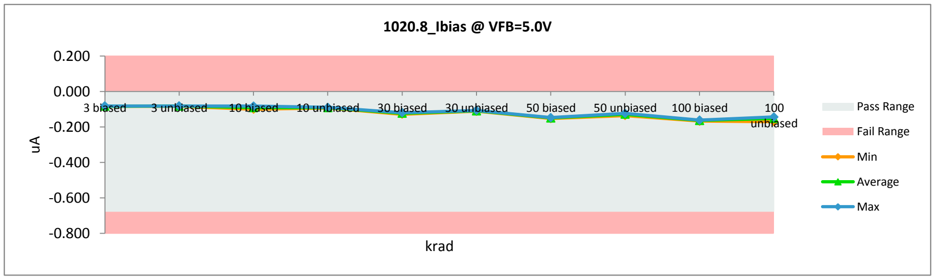
	1020.8_Ibias @ VFB=5	
Test Site		
Tester		
Test Number		
Unit	uA	uA
Max Limit	-0.001	-0.001
Min Limit	-0.675	-0.675

krad	Serial #	Pre	Post	Delta
3	135	-0.076	-0.083	0.007
3	136	-0.076	-0.083	0.007
3	138	-0.076	-0.084	0.008
3	139	-0.075	-0.081	0.007
3	143	-0.077	-0.084	0.007
4	1	-0.076	-0.082	0.006
4	2	-0.077	-0.083	0.006
4	3	-0.076	-0.084	0.007
4	5	-0.075	-0.082	0.007
4	7	-0.075	-0.082	0.006
10	144	-0.076	-0.086	0.010
10	145	-0.078	-0.098	0.020
10	146	-0.076	-0.089	0.013
10	149	-0.077	-0.082	0.006
10	150	-0.077	-0.100	0.023
11	8	-0.076	-0.091	0.016
11	11	-0.077	-0.093	0.016
11	14	-0.075	-0.091	0.016
11	15	-0.076	-0.091	0.016
11	19	-0.075	-0.090	0.015
30	151	-0.075	-0.119	0.045
30	153	-0.076	-0.122	0.046
30	154	-0.076	-0.124	0.048
30	155	-0.075	-0.128	0.053
30	156	-0.075	-0.120	0.046
31	22	-0.073	-0.107	0.034
31	23	-0.076	-0.110	0.034
31	31	-0.077	-0.112	0.035
31	37	-0.076	-0.110	0.034
31	42	-0.075	-0.108	0.034
50	173	-0.076	-0.148	0.071
50	174	-0.077	-0.153	0.076
50	175	-0.076	-0.149	0.072
50	183	-0.076	-0.148	0.072
50	187	-0.074	-0.149	0.075
51	43	-0.080	-0.128	0.049
51	45	-0.083	-0.135	0.052
51	48	-0.077	-0.123	0.046
51	49	-0.077	-0.128	0.051
51	50	-0.077	-0.125	0.049
100	191	-0.076	-0.162	0.085
100	195	-0.077	-0.168	0.091
100	199	-0.076	-0.162	0.086
100	203	-0.076	-0.162	0.086
100	207	-0.074	-0.163	0.089
101	69	-0.076	-0.158	0.081
101	70	-0.075	-0.146	0.071
101	71	-0.074	-0.161	0.087
101	74	-0.074	-0.146	0.072
101	76	-0.074	-0.146	0.072
101	81	-0.075	-0.144	0.069
101	82	-0.073	-0.155	0.082
101	85	-0.074	-0.146	0.072
101	94	-0.076	-0.153	0.077
101	95	-0.076	-0.150	0.074
101	99	-0.075	-0.149	0.074
101	103	-0.077	-0.165	0.088
101	109	-0.077	-0.154	0.077
101	110	-0.085	-0.170	0.086
101	112	-0.080	-0.155	0.075
101	115	-0.076	-0.147	0.071
101	117	-0.075	-0.144	0.069
101	118	-0.076	-0.146	0.070
101	122	-0.076	-0.144	0.068
101	125	-0.076	-0.153	0.077
101	126	-0.074	-0.150	0.076
101	129	-0.077	-0.164	0.087
	Max	-0.073	-0.081	0.091
	Average	-0.076	-0.126	0.050
	Min	-0.085	-0.170	0.006
	Std Dev	0.002	0.030	0.030



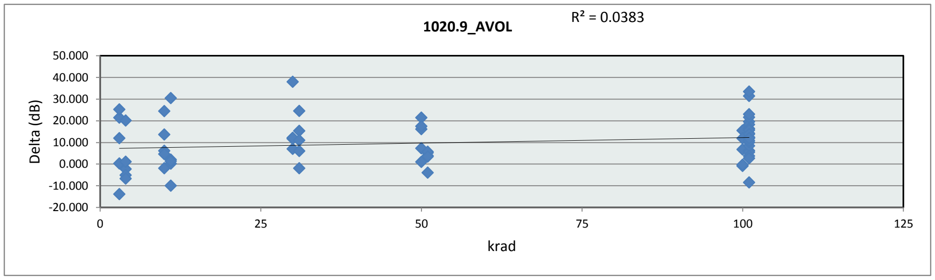
	1020.8_Ibias @ VFB=5.0V	
Test Site		
Tester		
Test Number		
Max Limit	-0.001	uA
Min Limit	-0.675	uA

krad	3 biased	3 unbiased	10 biased	10 unbiased	30 biased	30 unbiased	50 biased	50 unbiased	100 biased	100 unbiased
LL	-0.675	-0.675	-0.675	-0.675	-0.675	-0.675	-0.675	-0.675	-0.675	-0.675
Min	-0.084	-0.084	-0.100	-0.093	-0.128	-0.112	-0.153	-0.135	-0.168	-0.170
Average	-0.083	-0.082	-0.091	-0.091	-0.123	-0.110	-0.149	-0.128	-0.163	-0.152
Max	-0.081	-0.082	-0.082	-0.090	-0.120	-0.107	-0.148	-0.124	-0.162	-0.144
UL	-0.001	-0.001	-0.001	-0.001	-0.001	-0.001	-0.001	-0.001	-0.001	-0.001

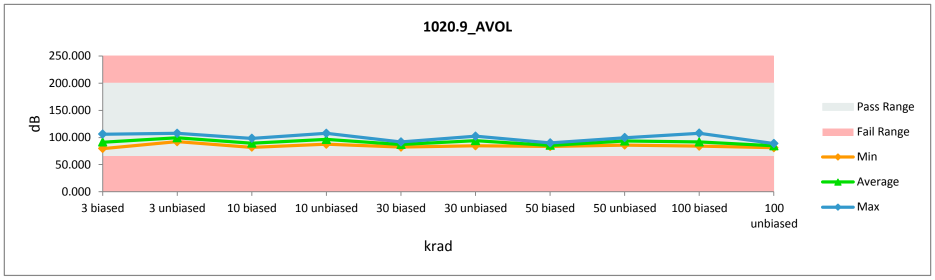


TID Report
Device Name

		1020.9_AVOL		
	Test Site			
	Tester			
	Test Number			
	Unit	dB	dB	
	Max Limit	200	200	
	Min Limit	66	66	
krad	Serial #	Pre	Post	Delta
3	135	121.031	99.580	21.451
3	136	88.435	88.180	0.256
3	138	95.645	83.727	11.918
3	139	104.834	79.620	25.214
3	143	92.316	106.224	-13.907
4	1	105.145	107.456	-2.311
4	2	96.307	101.435	-5.128
4	3	93.199	92.102	1.098
4	5	117.776	97.722	20.054
4	7	92.088	98.752	-6.664
10	144	106.442	82.039	24.403
10	145	95.969	89.828	6.141
10	146	92.978	94.912	-1.934
10	149	102.969	98.395	4.574
10	150	95.560	81.951	13.610
11	8	102.630	100.607	2.023
11	11	120.645	90.240	30.405
11	14	97.642	107.623	-9.981
11	15	87.699	87.522	0.177
11	19	96.875	95.519	1.356
30	151	99.284	87.251	12.033
30	153	122.304	84.311	37.993
30	154	103.219	91.568	11.652
30	155	101.477	89.415	12.062
30	156	89.240	82.204	7.036
31	22	109.189	84.646	24.543
31	23	100.203	102.123	-1.920
31	31	109.394	94.076	15.318
31	37	96.753	90.685	6.069
31	42	109.291	98.308	10.983
50	173	85.196	84.180	1.016
50	174	99.382	83.296	16.086
50	175	106.741	85.279	21.462
50	183	107.373	89.905	17.468
50	187	92.287	85.007	7.281
51	43	103.373	99.580	3.793
51	45	91.040	85.817	5.223
51	48	103.797	98.165	5.632
51	49	95.752	92.259	3.493
51	50	87.648	91.621	-3.973
100	191	85.196	86.025	-0.829
100	195	99.382	83.857	15.525
100	199	106.741	94.912	11.829
100	203	107.373	107.707	-0.334
100	207	92.287	85.567	6.720
101	69	102.168	82.578	19.590
101	70	91.015	84.834	6.181
101	71	102.213	83.973	18.241
101	74	100.836	84.492	16.344
101	76	75.560	84.039	-8.479
101	81	93.151	87.682	5.470
101	82	95.312	81.174	14.137
101	85	95.230	86.787	8.443
101	94	94.147	84.123	10.023
101	95	96.399	84.346	12.053
101	99	92.259	81.427	10.832
101	103	99.156	83.493	15.663
101	109	97.199	84.840	12.359
101	110	115.414	84.011	31.403
101	112	116.058	82.602	33.456
101	115	92.596	88.862	3.734
101	117	96.080	83.852	12.229
101	118	107.967	86.354	21.613
101	122	100.312	86.538	13.773
101	125	88.252	85.554	2.698
101	126	95.353	83.441	11.912
101	129	106.895	83.884	23.011
	Max	122.304	107.707	37.993
	Average	99.458	89.553	9.904
	Min	75.560	79.620	-13.907
	Std Dev	9.146	7.363	10.657



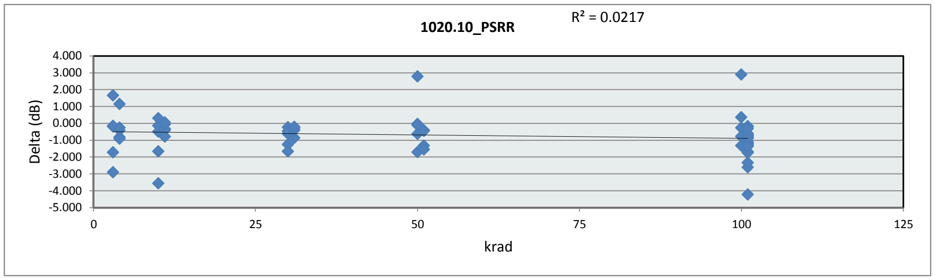
	1020.9_AVOL									
Test Site										
Tester										
Test Number										
Max Limit	200	dB								
Min Limit	66	dB								
krad	3 biased	3 unbiased	10 biased	10 unbiased	30 biased	30 unbiased	50 biased	50 unbiased	100 biased	100 unbiased
LL	66.000	66.000	66.000	66.000	66.000	66.000	66.000	66.000	66.000	66.000
Min	79.620	92.102	81.951	87.522	82.204	84.646	83.296	85.817	83.857	81.174
Average	91.466	99.493	89.425	96.302	86.950	93.968	85.533	93.488	91.614	84.495
Max	106.224	107.456	98.395	107.623	91.568	102.123	89.905	99.580	107.707	88.862
UL	200.000	200.000	200.000	200.000	200.000	200.000	200.000	200.000	200.000	200.000



TID Report
Device Name

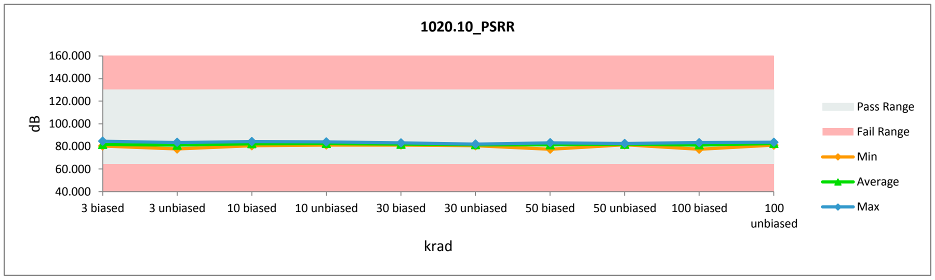
	1020.10_PSRR	
Test Site		
Tester		
Test Number		
Unit	dB	dB
Max Limit	130	130
Min Limit	64.65	64.65

krad	Serial #	Pre	Post	Delta
3	135	81.068	81.222	-0.154
3	136	79.598	81.324	-1.726
3	138	80.619	80.805	-0.186
3	139	82.047	80.392	1.656
3	143	81.680	84.586	-2.906
4	1	78.827	77.685	1.142
4	2	80.657	81.478	-0.821
4	3	82.604	83.521	-0.917
4	5	81.335	81.745	-0.410
4	7	80.642	80.897	-0.255
10	144	82.801	82.947	-0.146
10	145	80.739	84.307	-3.568
10	146	81.232	81.728	-0.496
10	149	81.172	82.842	-1.670
10	150	80.830	80.524	0.306
11	8	81.590	81.992	-0.402
11	11	80.924	81.257	-0.334
11	14	83.484	83.549	-0.065
11	15	81.164	81.958	-0.794
11	19	84.033	83.983	0.051
30	151	82.441	83.061	-0.620
30	153	81.603	82.862	-1.259
30	154	79.680	81.343	-1.663
30	155	80.923	81.156	-0.233
30	156	80.894	81.359	-0.465
31	22	81.483	81.754	-0.270
31	23	80.114	80.520	-0.406
31	31	81.179	82.047	-0.869
31	37	81.475	81.864	-0.389
31	42	81.094	81.309	-0.214
50	173	81.251	81.291	-0.040
50	174	81.150	82.865	-1.715
50	175	80.309	77.529	2.779
50	183	82.558	83.192	-0.634
50	187	82.257	82.367	-0.110
51	43	81.589	82.000	-0.411
51	45	81.195	82.522	-1.327
51	48	81.367	81.789	-0.422
51	49	80.651	82.197	-1.547
51	50	80.917	81.363	-0.446
100	191	81.251	81.512	-0.261
100	195	81.150	82.477	-1.327
100	199	80.309	77.411	2.898
100	203	82.558	83.341	-0.783
100	207	82.257	81.894	0.363
101	69	80.959	82.275	-1.316
101	70	82.470	83.364	-0.894
101	71	80.189	81.876	-1.687
101	74	82.706	83.539	-0.833
101	76	77.843	82.062	-4.219
101	81	82.898	83.636	-0.738
101	82	82.638	83.298	-0.660
101	85	81.050	82.221	-1.171
101	94	81.576	81.764	-0.188
101	95	80.562	81.300	-0.738
101	99	82.483	83.592	-1.110
101	103	81.067	83.671	-2.604
101	109	81.911	83.068	-1.157
101	110	79.730	82.066	-2.337
101	112	80.993	82.233	-1.240
101	115	81.710	81.884	-0.174
101	117	80.931	81.128	-0.196
101	118	81.866	82.474	-0.608
101	122	80.867	81.733	-0.866
101	125	82.521	82.828	-0.307
101	126	81.387	83.132	-1.744
101	129	82.213	83.579	-1.367
	Max	84.033	84.586	2.898
	Average	81.332	82.037	-0.705
	Min	77.843	77.411	-4.219
	Std Dev	1.035	1.374	1.122



	1020.10_ PSRR	
Test Site		
Tester		
Test Number		
Max Limit	130	dB
Min Limit	64.65	dB

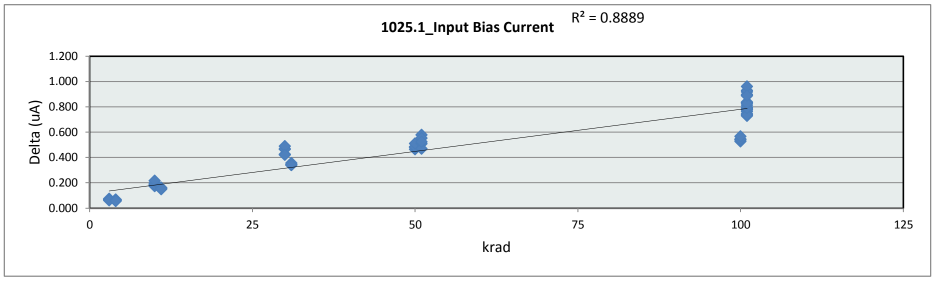
krad	3 biased	3 unbiased	10 biased	10 unbiased	30 biased	30 unbiased	50 biased	50 unbiased	100 biased	100 unbiased
LL	64.650	64.650	64.650	64.650	64.650	64.650	64.650	64.650	64.650	64.650
Min	80.392	77.685	80.524	81.257	81.156	80.520	77.529	81.363	77.411	81.128
Average	81.666	81.065	82.470	82.548	81.956	81.499	81.449	81.974	81.327	82.578
Max	84.586	83.521	84.307	83.983	83.061	82.047	83.192	82.522	83.342	83.671
UL	130.000	130.000	130.000	130.000	130.000	130.000	130.000	130.000	130.000	130.000



TID Report
Device Name

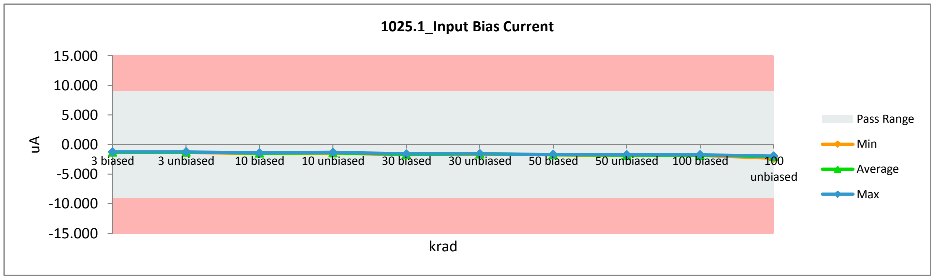
	1025.1_Input Bias Cu	
Test Site		
Tester		
Test Number		
Unit	uA	uA
Max Limit	9	9
Min Limit	-9	-9

krad	Serial #	Pre	Post	Delta
3	135	-1.156	-1.223	0.067
3	136	-1.208	-1.275	0.067
3	138	-1.224	-1.297	0.073
3	139	-1.261	-1.330	0.069
3	143	-1.204	-1.265	0.061
4	1	-1.189	-1.246	0.057
4	2	-1.275	-1.342	0.067
4	3	-1.235	-1.298	0.062
4	5	-1.198	-1.264	0.066
4	7	-1.182	-1.238	0.056
10	144	-1.251	-1.430	0.179
10	145	-1.224	-1.397	0.173
10	146	-1.231	-1.427	0.196
10	149	-1.238	-1.423	0.185
10	150	-1.286	-1.502	0.216
11	8	-1.237	-1.392	0.156
11	11	-1.235	-1.396	0.161
11	14	-1.228	-1.387	0.160
11	15	-1.176	-1.326	0.150
11	19	-1.287	-1.440	0.153
30	151	-1.167	-1.592	0.425
30	153	-1.290	-1.755	0.465
30	154	-1.210	-1.678	0.468
30	155	-1.183	-1.672	0.489
30	156	-1.170	-1.591	0.421
31	22	-1.198	-1.554	0.356
31	23	-1.267	-1.608	0.341
31	31	-1.245	-1.586	0.341
31	37	-1.223	-1.566	0.343
31	42	-1.266	-1.606	0.339
50	173	-1.197	-1.662	0.464
50	174	-1.232	-1.714	0.481
50	175	-1.226	-1.709	0.483
50	183	-1.277	-1.759	0.482
50	187	-1.207	-1.717	0.510
51	43	-1.245	-1.754	0.509
51	45	-1.233	-1.812	0.578
51	48	-1.251	-1.720	0.469
51	49	-1.325	-1.877	0.552
51	50	-1.220	-1.744	0.524
100	191	-1.197	-1.724	0.527
100	195	-1.232	-1.770	0.538
100	199	-1.226	-1.768	0.542
100	203	-1.277	-1.822	0.545
100	207	-1.207	-1.773	0.566
101	69	-1.227	-2.115	0.888
101	70	-1.196	-1.977	0.781
101	71	-1.201	-2.119	0.918
101	74	-1.212	-2.010	0.798
101	76	-1.230	-2.062	0.832
101	81	-1.221	-1.966	0.745
101	82	-1.215	-2.112	0.897
101	85	-1.202	-1.965	0.763
101	94	-1.230	-2.066	0.837
101	95	-1.205	-1.981	0.776
101	99	-1.183	-1.976	0.793
101	103	-1.217	-2.145	0.929
101	109	-1.219	-2.053	0.834
101	110	-1.385	-2.346	0.960
101	112	-1.238	-2.051	0.813
101	115	-1.236	-2.017	0.780
101	117	-1.245	-1.973	0.728
101	118	-1.195	-1.933	0.738
101	122	-1.233	-1.966	0.734
101	125	-1.193	-1.982	0.789
101	126	-1.208	-2.034	0.827
101	129	-1.200	-2.088	0.888
	Max	-1.156	-1.223	0.960
	Average	-1.227	-1.707	0.480
	Min	-1.385	-2.346	0.056
	Std Dev	0.038	0.291	0.288



	1025.1_Input Bias Current	
Test Site		
Tester		
Test Number		
Max Limit	9	uA
Min Limit	-9	uA

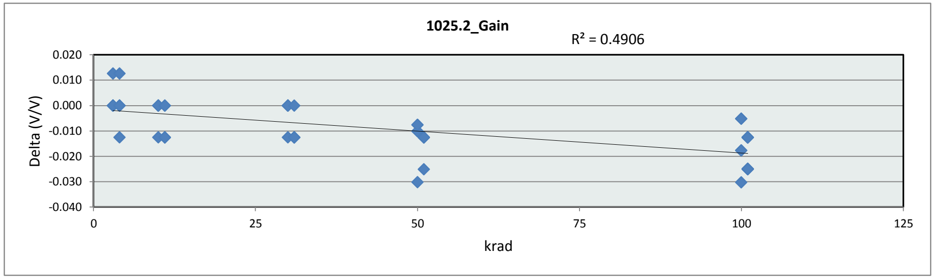
krad	3 biased	3 unbiased	10 biased	10 unbiased	30 biased	30 unbiased	50 biased	50 unbiased	100 biased	100 unbiased
LL	-9.000	-9.000	-9.000	-9.000	-9.000	-9.000	-9.000	-9.000	-9.000	-9.000
Min	-1.330	-1.342	-1.502	-1.440	-1.755	-1.608	-1.759	-1.877	-1.822	-2.346
Average	-1.278	-1.278	-1.436	-1.388	-1.657	-1.584	-1.712	-1.781	-1.772	-2.043
Max	-1.223	-1.239	-1.397	-1.326	-1.591	-1.554	-1.662	-1.720	-1.724	-1.933
UL	9.000	9.000	9.000	9.000	9.000	9.000	9.000	9.000	9.000	9.000



TID Report
Device Name

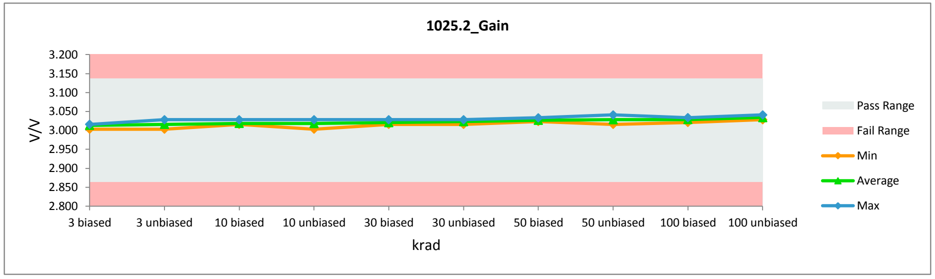
	1025.2_Gain	
Test Site		
Tester		
Test Number		
Unit	V/V	V/V
Max Limit	3.136	3.136
Min Limit	2.864	2.864

krad	Serial #	Pre	Post	Delta
3	135	3.016	3.016	0.000
3	136	3.016	3.003	0.013
3	138	3.016	3.016	0.000
3	139	3.016	3.016	0.000
3	143	3.016	3.016	0.000
4	1	3.016	3.016	0.000
4	2	3.016	3.003	0.013
4	3	3.016	3.016	0.000
4	5	3.016	3.028	-0.013
4	7	3.016	3.016	0.000
10	144	3.016	3.016	0.000
10	145	3.016	3.016	0.000
10	146	3.016	3.028	-0.013
10	149	3.016	3.016	0.000
10	150	3.016	3.016	0.000
11	8	3.016	3.028	-0.013
11	11	3.003	3.003	0.000
11	14	3.016	3.028	-0.013
11	15	3.003	3.016	-0.013
11	19	3.016	3.016	0.000
30	151	3.016	3.016	0.000
30	153	3.016	3.016	0.000
30	154	3.016	3.028	-0.013
30	155	3.016	3.016	0.000
30	156	3.028	3.028	0.000
31	22	3.016	3.028	-0.013
31	23	3.016	3.016	0.000
31	31	3.016	3.028	-0.013
31	37	3.016	3.028	-0.013
31	42	3.003	3.016	-0.013
50	173	3.016	3.026	-0.010
50	174	3.016	3.026	-0.010
50	175	3.016	3.023	-0.008
50	183	3.003	3.033	-0.030
50	187	3.016	3.023	-0.008
51	43	3.003	3.028	-0.025
51	45	3.028	3.041	-0.013
51	48	3.003	3.016	-0.013
51	49	3.016	3.028	-0.013
51	50	3.016	3.028	-0.013
100	191	3.016	3.021	-0.005
100	195	3.016	3.033	-0.018
100	199	3.016	3.033	-0.018
100	203	3.003	3.033	-0.030
100	207	3.016	3.021	-0.005
101	69	3.016	3.028	-0.013
101	70	3.016	3.028	-0.013
101	71	3.016	3.041	-0.025
101	74	3.016	3.028	-0.013
101	76	3.016	3.028	-0.013
101	81	3.003	3.028	-0.025
101	82	3.016	3.041	-0.025
101	85	3.016	3.041	-0.025
101	94	3.016	3.028	-0.013
101	95	3.016	3.041	-0.025
101	99	3.016	3.028	-0.013
101	103	3.016	3.041	-0.025
101	109	3.016	3.028	-0.013
101	110	3.016	3.041	-0.025
101	112	3.016	3.028	-0.013
101	115	3.016	3.028	-0.013
101	117	3.016	3.028	-0.013
101	118	3.016	3.041	-0.025
101	122	3.016	3.028	-0.013
101	125	3.016	3.041	-0.025
101	126	3.016	3.041	-0.025
101	129	3.016	3.041	-0.025
	Max	3.028	3.041	0.013
	Average	3.015	3.026	-0.011
	Min	3.003	3.003	-0.030
	Std Dev	0.005	0.010	0.010



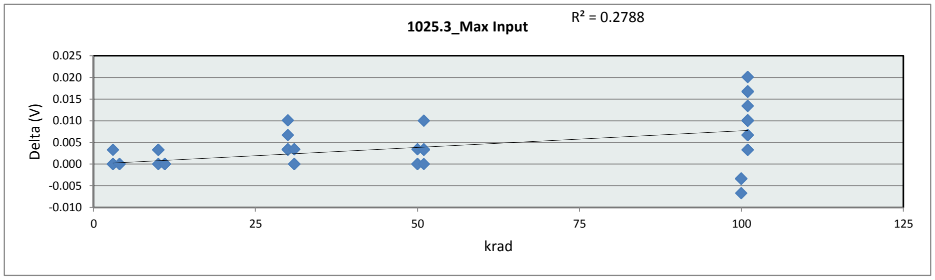
	1025.2_Gain	
Test Site		
Tester		
Test Number		
Max Limit	3.136	V/V
Min Limit	2.864	V/V

krad	3 biased	3 unbiased	10 biased	10 unbiased	30 biased	30 unbiased	50 biased	50 unbiased	100 biased	100 unbiased
LL	2.864	2.864	2.864	2.864	2.864	2.864	2.864	2.864	2.864	2.864
Min	3.003	3.003	3.016	3.003	3.016	3.016	3.023	3.016	3.021	3.028
Average	3.013	3.016	3.018	3.018	3.021	3.023	3.026	3.028	3.028	3.034
Max	3.016	3.028	3.028	3.028	3.028	3.028	3.033	3.041	3.033	3.041
UL	3.136	3.136	3.136	3.136	3.136	3.136	3.136	3.136	3.136	3.136

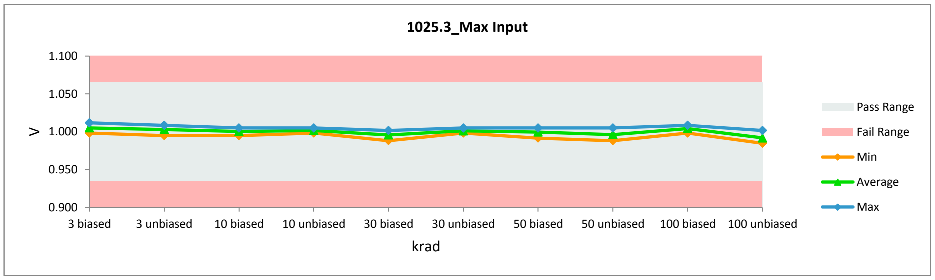


TID Report
Device Name

		1025.3_Max Input		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	1.065	1.065	
	Min Limit	0.935	0.935	
krad	Serial #	Pre	Post	Delta
3	135	1.012	1.012	0.000
3	136	1.012	1.012	0.000
3	138	1.005	1.002	0.003
3	139	1.002	1.002	0.000
3	143	0.998	0.998	0.000
4	1	1.005	1.005	0.000
4	2	1.005	1.005	0.000
4	3	1.002	1.002	0.000
4	5	0.995	0.995	0.000
4	7	1.008	1.008	0.000
10	144	1.005	1.002	0.003
10	145	1.005	1.005	0.000
10	146	0.998	0.995	0.003
10	149	0.998	0.998	0.000
10	150	1.005	1.002	0.003
11	8	1.002	1.002	0.000
11	11	1.002	1.002	0.000
11	14	1.005	1.005	0.000
11	15	0.998	0.998	0.000
11	19	1.002	1.002	0.000
30	151	1.002	0.998	0.003
30	153	1.002	0.998	0.003
30	154	0.995	0.988	0.007
30	155	1.002	0.992	0.010
30	156	1.005	1.002	0.003
31	22	1.002	0.998	0.003
31	23	1.008	1.005	0.003
31	31	1.002	1.002	0.000
31	37	0.998	0.998	0.000
31	42	1.002	1.002	0.000
50	173	0.998	0.998	0.000
50	174	0.998	0.998	0.000
50	175	1.005	1.005	0.000
50	183	1.005	1.005	0.000
50	187	0.995	0.992	0.003
51	43	1.005	1.002	0.003
51	45	0.998	0.988	0.010
51	48	1.005	1.005	0.000
51	49	1.002	0.998	0.003
51	50	0.992	0.988	0.003
100	191	0.998	1.002	-0.003
100	195	0.998	1.005	-0.007
100	199	1.005	1.008	-0.003
100	203	1.005	1.008	-0.003
100	207	0.995	0.998	-0.003
101	69	1.002	0.988	0.013
101	70	0.995	0.988	0.007
101	71	1.005	0.985	0.020
101	74	0.998	0.992	0.007
101	76	0.995	0.985	0.010
101	81	0.998	0.995	0.003
101	82	1.005	0.988	0.017
101	85	1.005	0.995	0.010
101	94	1.002	0.992	0.010
101	95	0.998	0.988	0.010
101	99	0.998	0.988	0.010
101	103	1.002	0.985	0.017
101	109	1.005	0.995	0.010
101	110	1.012	0.992	0.020
101	112	1.002	0.988	0.013
101	115	1.008	1.002	0.007
101	117	1.005	1.002	0.003
101	118	0.998	0.995	0.003
101	122	1.005	0.998	0.007
101	125	1.008	0.998	0.010
101	126	1.002	0.992	0.010
101	129	1.005	0.988	0.017
	Max	1.012	1.012	0.020
	Average	1.002	0.998	0.004
	Min	0.992	0.985	-0.007
	Std Dev	0.004	0.007	0.006



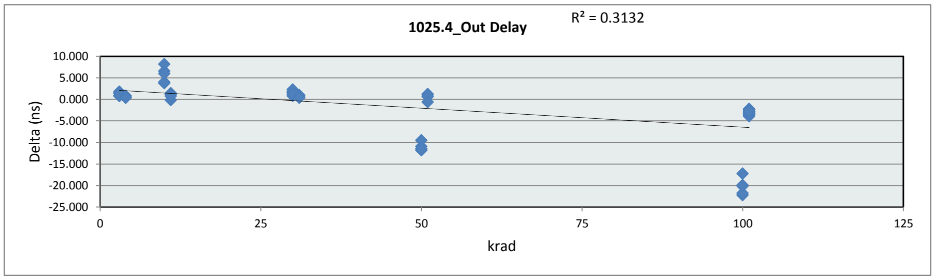
	1025.3_Max Input									
Test Site										
Tester										
Test Number										
Max Limit	1.065 V									
Min Limit	0.935 V									
krad	3 biased	3 unbiased	10 biased	10 unbiased	30 biased	30 unbiased	50 biased	50 unbiased	100 biased	100 unbiased
LL	0.935	0.935	0.935	0.935	0.935	0.935	0.935	0.935	0.935	0.935
Min	0.998	0.995	0.995	0.998	0.988	0.998	0.992	0.988	0.998	0.985
Average	1.005	1.003	1.000	1.002	0.996	1.001	1.000	0.996	1.004	0.992
Max	1.012	1.008	1.005	1.005	1.002	1.005	1.005	1.005	1.008	1.002
UL	1.065	1.065	1.065	1.065	1.065	1.065	1.065	1.065	1.065	1.065



TID Report
Device Name

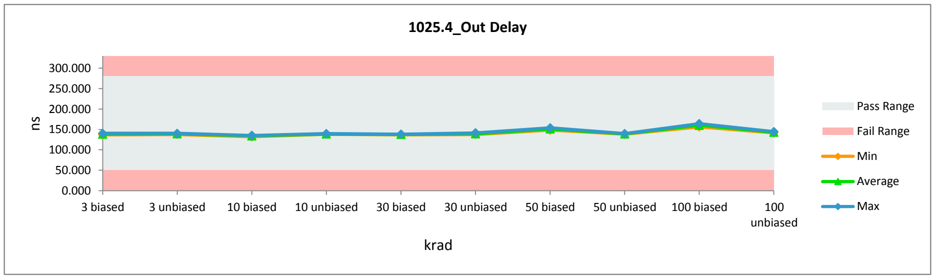
	1025.4_Out Delay	
Test Site		
Tester		
Test Number		
Unit	ns	ns
Max Limit	280	280
Min Limit	50	50

krad	Serial #	Pre	Post	Delta
3	135	139.843	138.936	0.908
3	136	139.616	137.843	1.773
3	138	141.302	140.530	0.772
3	139	138.667	137.171	1.496
3	143	140.132	138.756	1.376
4	1	140.814	140.379	0.435
4	2	138.791	138.053	0.738
4	3	141.171	140.307	0.863
4	5	138.181	137.839	0.342
4	7	139.695	139.281	0.414
10	144	140.067	133.486	6.581
10	145	140.154	131.984	8.170
10	146	138.952	135.193	3.759
10	149	139.608	135.598	4.011
10	150	141.070	135.087	5.983
11	8	139.803	138.376	1.427
11	11	138.514	138.676	-0.161
11	14	139.323	138.224	1.100
11	15	140.872	139.725	1.146
11	19	139.215	138.437	0.778
30	151	139.354	137.096	2.258
30	153	140.109	138.552	1.556
30	154	139.849	138.073	1.776
30	155	139.163	138.350	0.812
30	156	138.690	137.430	1.260
31	22	140.365	139.540	0.825
31	23	138.827	137.864	0.963
31	31	139.543	139.072	0.471
31	37	139.333	138.815	0.518
31	42	141.947	141.599	0.348
50	173	138.926	148.420	-9.494
50	174	140.046	151.849	-11.803
50	175	140.298	151.245	-10.947
50	183	142.396	153.846	-11.451
50	187	138.669	150.219	-11.549
51	43	141.044	139.824	1.219
51	45	138.733	137.982	0.752
51	48	139.616	138.420	1.196
51	49	139.625	139.021	0.603
51	50	138.734	139.363	-0.629
100	191	138.926	156.137	-17.210
100	195	140.046	162.277	-22.231
100	199	140.298	160.197	-19.899
100	203	142.396	164.158	-21.762
100	207	138.669	158.792	-20.122
101	69	140.883	144.352	-3.469
101	70	139.939	143.650	-3.711
101	71	139.058	142.212	-3.155
101	74	139.630	142.909	-3.279
101	76	140.021	143.666	-3.645
101	81	140.713	143.882	-3.169
101	82	139.775	142.091	-2.315
101	85	141.011	143.387	-2.376
101	94	140.368	142.593	-2.225
101	95	141.174	143.986	-2.812
101	99	141.611	143.888	-2.276
101	103	141.680	144.142	-2.462
101	109	139.581	142.448	-2.868
101	110	140.429	143.233	-2.804
101	112	140.019	142.475	-2.456
101	115	139.437	142.739	-3.302
101	117	139.859	143.131	-3.272
101	118	139.672	143.050	-3.379
101	122	140.145	144.050	-3.905
101	125	139.909	142.969	-3.061
101	126	138.278	141.590	-3.312
101	129	140.786	143.601	-2.814
	Max	142.396	164.158	8.170
	Average	139.931	142.419	-2.488
	Min	138.181	131.984	-22.231
	Std Dev	0.972	6.545	6.371



	1025.4_Out Delay	
Test Site		
Tester		
Test Number		
Max Limit	280	ns
Min Limit	50	ns

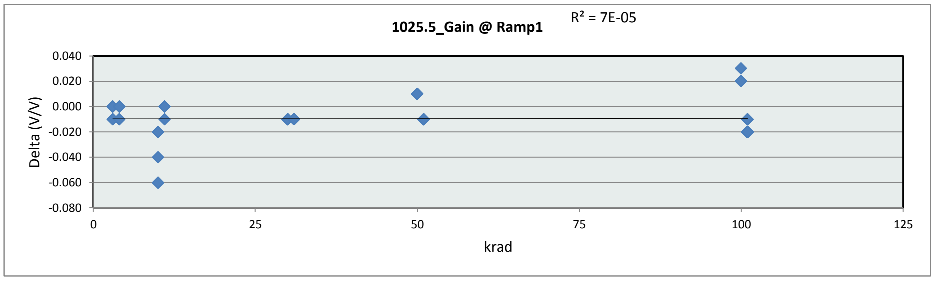
krad	3 biased	3 unbiased	10 biased	10 unbiased	30 biased	30 unbiased	50 biased	50 unbiased	100 biased	100 unbiased
LL	50.000	50.000	50.000	50.000	50.000	50.000	50.000	50.000	50.000	50.000
Min	137.171	137.839	131.985	138.224	137.096	137.864	148.420	137.982	156.137	141.590
Average	138.647	139.172	134.269	138.688	137.900	139.378	151.116	138.922	160.312	143.184
Max	140.530	140.379	135.598	139.725	138.552	141.599	153.846	139.824	164.158	144.352
UL	280.000	280.000	280.000	280.000	280.000	280.000	280.000	280.000	280.000	280.000



TID Report
Device Name

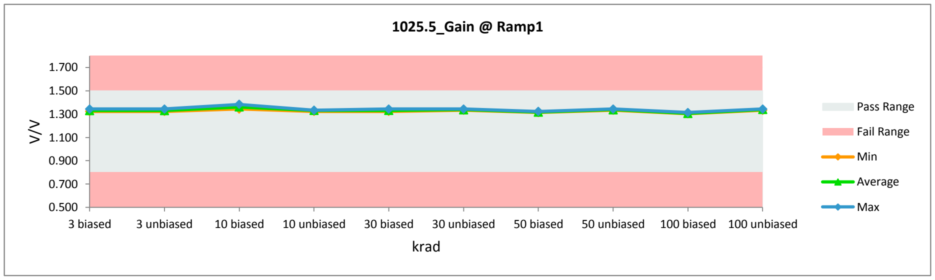
	1025.5_Gain @ Ramp1	
Test Site		
Tester		
Test Number		
Unit	V/V	V/V
Max Limit	1.5	1.5
Min Limit	0.8	0.8

krad	Serial #	Pre	Post	Delta
3	135	1.324	1.324	0.000
3	136	1.324	1.334	-0.010
3	138	1.324	1.324	0.000
3	139	1.334	1.344	-0.010
3	143	1.324	1.324	0.000
4	1	1.324	1.324	0.000
4	2	1.334	1.344	-0.010
4	3	1.324	1.334	-0.010
4	5	1.324	1.324	0.000
4	7	1.324	1.324	0.000
10	144	1.324	1.384	-0.060
10	145	1.314	1.374	-0.060
10	146	1.324	1.344	-0.020
10	149	1.324	1.344	-0.020
10	150	1.324	1.364	-0.040
11	8	1.334	1.334	0.000
11	11	1.334	1.334	0.000
11	14	1.334	1.334	0.000
11	15	1.324	1.324	0.000
11	19	1.324	1.334	-0.010
30	151	1.314	1.324	-0.010
30	153	1.334	1.344	-0.010
30	154	1.324	1.334	-0.010
30	155	1.324	1.334	-0.010
30	156	1.314	1.324	-0.010
31	22	1.324	1.334	-0.010
31	23	1.334	1.344	-0.010
31	31	1.324	1.334	-0.010
31	37	1.324	1.334	-0.010
31	42	1.334	1.344	-0.010
50	173	1.324	1.314	0.010
50	174	1.324	1.314	0.010
50	175	1.324	1.314	0.010
50	183	1.334	1.324	0.010
50	187	1.334	1.324	0.010
51	43	1.324	1.334	-0.010
51	45	1.324	1.334	-0.010
51	48	1.334	1.344	-0.010
51	49	1.334	1.344	-0.010
51	50	1.324	1.334	-0.010
100	191	1.324	1.304	0.020
100	195	1.324	1.304	0.020
100	199	1.324	1.304	0.020
100	203	1.334	1.304	0.030
100	207	1.334	1.314	0.020
101	69	1.324	1.344	-0.020
101	70	1.324	1.344	-0.020
101	71	1.324	1.344	-0.020
101	74	1.334	1.344	-0.010
101	76	1.324	1.344	-0.020
101	81	1.324	1.344	-0.020
101	82	1.324	1.344	-0.020
101	85	1.314	1.334	-0.020
101	94	1.324	1.344	-0.020
101	95	1.314	1.334	-0.020
101	99	1.314	1.334	-0.020
101	103	1.314	1.334	-0.020
101	109	1.324	1.344	-0.020
101	110	1.324	1.344	-0.020
101	112	1.324	1.344	-0.020
101	115	1.324	1.344	-0.020
101	117	1.324	1.344	-0.020
101	118	1.324	1.334	-0.010
101	122	1.324	1.344	-0.020
101	125	1.324	1.334	-0.010
101	126	1.324	1.334	-0.010
101	129	1.314	1.334	-0.020
	Max	1.334	1.384	0.030
	Average	1.325	1.334	-0.010
	Min	1.314	1.304	-0.060
	Std Dev	0.006	0.014	0.016



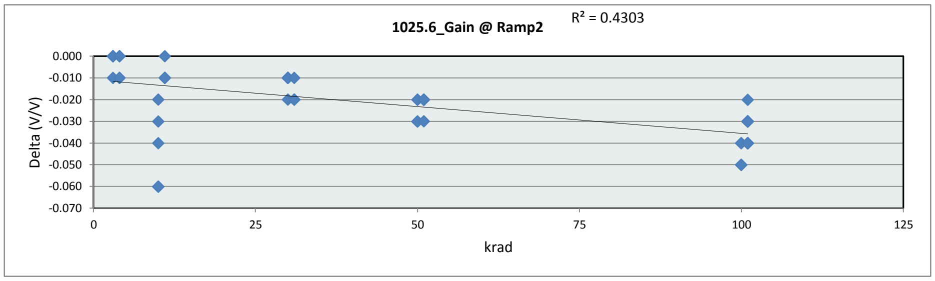
	1025.5_Gain @ Ramp1	
Test Site		
Tester		
Test Number		
Max Limit	1.5	V/V
Min Limit	0.8	V/V

krad	3 biased	3 unbiased	10 biased	10 unbiased	30 biased	30 unbiased	50 biased	50 unbiased	100 biased	100 unbiased
LL	0.800	0.800	0.800	0.800	0.800	0.800	0.800	0.800	0.800	0.800
Min	1.324	1.324	1.344	1.324	1.324	1.334	1.314	1.334	1.304	1.334
Average	1.330	1.330	1.362	1.332	1.332	1.338	1.318	1.338	1.306	1.340
Max	1.344	1.344	1.384	1.334	1.344	1.344	1.324	1.344	1.314	1.344
UL	1.500	1.500	1.500	1.500	1.500	1.500	1.500	1.500	1.500	1.500

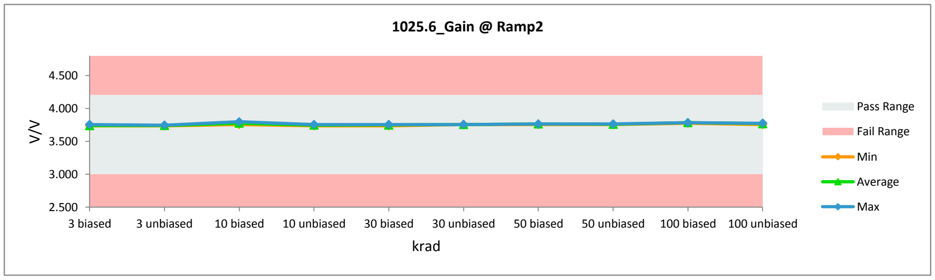


TID Report
Device Name

		1025.6_Gain @ Ramp2		
	Test Site			
	Tester			
	Test Number			
	Unit	V/V	V/V	
	Max Limit	4.2	4.2	
	Min Limit	3	3	
krad	Serial #	Pre	Post	Delta
3	135	3.736	3.736	0.000
3	136	3.736	3.736	0.000
3	138	3.736	3.736	0.000
3	139	3.746	3.756	-0.010
3	143	3.736	3.736	0.000
4	1	3.736	3.736	0.000
4	2	3.746	3.746	0.000
4	3	3.736	3.746	-0.010
4	5	3.736	3.746	-0.010
4	7	3.736	3.736	0.000
10	144	3.736	3.797	-0.060
10	145	3.726	3.786	-0.060
10	146	3.736	3.766	-0.030
10	149	3.736	3.756	-0.020
10	150	3.736	3.776	-0.040
11	8	3.746	3.756	-0.010
11	11	3.736	3.736	0.000
11	14	3.746	3.756	-0.010
11	15	3.726	3.736	-0.010
11	19	3.736	3.746	-0.010
30	151	3.726	3.736	-0.010
30	153	3.746	3.756	-0.010
30	154	3.736	3.756	-0.020
30	155	3.736	3.746	-0.010
30	156	3.736	3.746	-0.010
31	22	3.736	3.756	-0.020
31	23	3.746	3.756	-0.010
31	31	3.736	3.756	-0.020
31	37	3.736	3.756	-0.020
31	42	3.736	3.756	-0.020
50	173	3.736	3.766	-0.030
50	174	3.736	3.766	-0.030
50	175	3.736	3.756	-0.020
50	183	3.736	3.766	-0.030
50	187	3.746	3.766	-0.020
51	43	3.726	3.756	-0.030
51	45	3.746	3.766	-0.020
51	48	3.736	3.756	-0.020
51	49	3.746	3.766	-0.020
51	50	3.736	3.756	-0.020
100	191	3.736	3.776	-0.040
100	195	3.736	3.786	-0.050
100	199	3.736	3.786	-0.050
100	203	3.736	3.786	-0.050
100	207	3.746	3.786	-0.040
101	69	3.736	3.766	-0.030
101	70	3.736	3.766	-0.030
101	71	3.736	3.776	-0.040
101	74	3.746	3.766	-0.020
101	76	3.736	3.766	-0.030
101	81	3.726	3.766	-0.040
101	82	3.736	3.776	-0.040
101	85	3.726	3.766	-0.040
101	94	3.736	3.766	-0.030
101	95	3.726	3.766	-0.040
101	99	3.726	3.756	-0.030
101	103	3.726	3.766	-0.040
101	109	3.736	3.766	-0.030
101	110	3.736	3.776	-0.040
101	112	3.736	3.766	-0.030
101	115	3.736	3.766	-0.030
101	117	3.736	3.766	-0.030
101	118	3.736	3.766	-0.030
101	122	3.736	3.766	-0.030
101	125	3.736	3.766	-0.030
101	126	3.736	3.766	-0.030
101	129	3.726	3.766	-0.040
	Max	3.746	3.797	0.000
	Average	3.737	3.761	-0.024
	Min	3.726	3.736	-0.060
	Std Dev	0.006	0.014	0.015



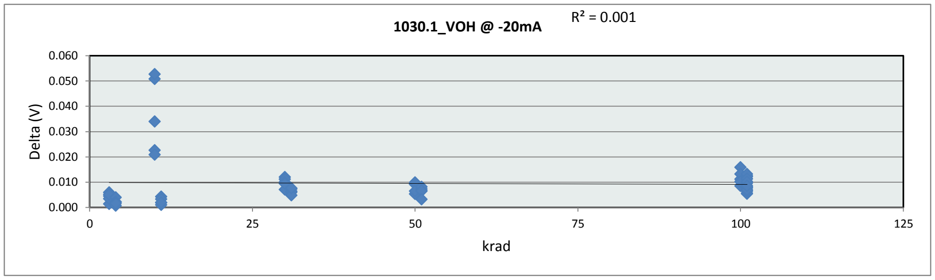
	1025.6_Gain @ Ramp2									
Test Site										
Tester										
Test Number										
Max Limit	4.2 V/V									
Min Limit	3 V/V									
krad	3 biased	3 unbiased	10 biased	10 unbiased	30 biased	30 unbiased	50 biased	50 unbiased	100 biased	100 unbiased
LL	3.000	3.000	3.000	3.000	3.000	3.000	3.000	3.000	3.000	3.000
Min	3.736	3.736	3.756	3.736	3.736	3.756	3.756	3.756	3.777	3.756
Average	3.740	3.742	3.777	3.746	3.748	3.756	3.764	3.760	3.785	3.767
Max	3.756	3.746	3.797	3.756	3.756	3.756	3.767	3.767	3.787	3.777
UL	4.200	4.200	4.200	4.200	4.200	4.200	4.200	4.200	4.200	4.200



TID Report
Device Name

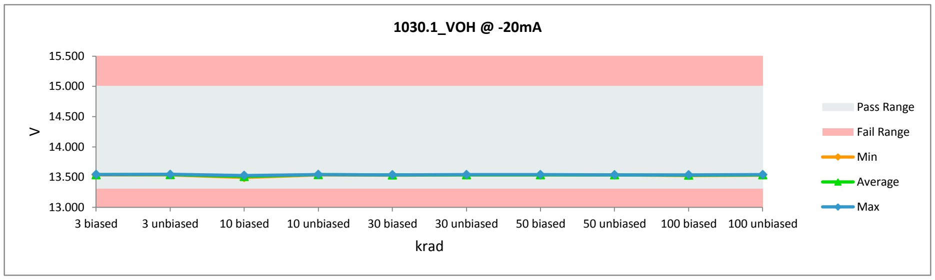
	1030.1_VOH @ -20mA	
Test Site		
Tester		
Test Number		
Unit	V	V
Max Limit	15	15
Min Limit	13.31	13.31

krad	Serial #	Pre	Post	Delta
3	135	13.545	13.543	0.001
3	136	13.540	13.536	0.005
3	138	13.545	13.541	0.003
3	139	13.540	13.534	0.006
3	143	13.544	13.539	0.005
4	1	13.539	13.538	0.001
4	2	13.541	13.539	0.002
4	3	13.543	13.540	0.004
4	5	13.544	13.542	0.002
4	7	13.546	13.544	0.002
10	144	13.542	13.491	0.051
10	145	13.545	13.493	0.053
10	146	13.547	13.525	0.023
10	149	13.548	13.527	0.021
10	150	13.549	13.515	0.034
11	8	13.540	13.539	0.002
11	11	13.544	13.543	0.001
11	14	13.541	13.537	0.004
11	15	13.543	13.540	0.003
11	19	13.542	13.540	0.002
30	151	13.550	13.538	0.012
30	153	13.545	13.538	0.007
30	154	13.544	13.533	0.011
30	155	13.542	13.532	0.010
30	156	13.546	13.536	0.009
31	22	13.542	13.536	0.006
31	23	13.543	13.536	0.006
31	31	13.547	13.540	0.007
31	37	13.545	13.540	0.005
31	42	13.542	13.535	0.008
50	173	13.546	13.541	0.005
50	174	13.547	13.538	0.009
50	175	13.543	13.534	0.009
50	183	13.545	13.535	0.010
50	187	13.541	13.534	0.007
51	43	13.546	13.538	0.007
51	45	13.546	13.538	0.008
51	48	13.544	13.538	0.007
51	49	13.543	13.536	0.007
51	50	13.538	13.535	0.003
100	191	13.546	13.538	0.009
100	195	13.547	13.536	0.011
100	199	13.543	13.527	0.016
100	203	13.545	13.532	0.013
100	207	13.541	13.531	0.010
101	69	13.543	13.538	0.005
101	70	13.541	13.535	0.007
101	71	13.542	13.533	0.008
101	74	13.540	13.535	0.006
101	76	13.544	13.535	0.008
101	81	13.547	13.536	0.011
101	82	13.546	13.534	0.012
101	85	13.551	13.542	0.010
101	94	13.546	13.536	0.010
101	95	13.550	13.538	0.012
101	99	13.551	13.539	0.012
101	103	13.548	13.535	0.013
101	109	13.548	13.537	0.011
101	110	13.546	13.536	0.010
101	112	13.548	13.540	0.008
101	115	13.545	13.537	0.008
101	117	13.544	13.536	0.008
101	118	13.543	13.536	0.007
101	122	13.545	13.538	0.006
101	125	13.547	13.540	0.008
101	126	13.547	13.540	0.007
101	129	13.546	13.537	0.009
	Max	13.551	13.544	0.053
	Average	13.545	13.535	0.009
	Min	13.538	13.491	0.001
	Std Dev	0.003	0.009	0.009



	1030.1_VOH @ -20mA	
Test Site		
Tester		
Test Number		
Max Limit	15	V
Min Limit	13.31	V

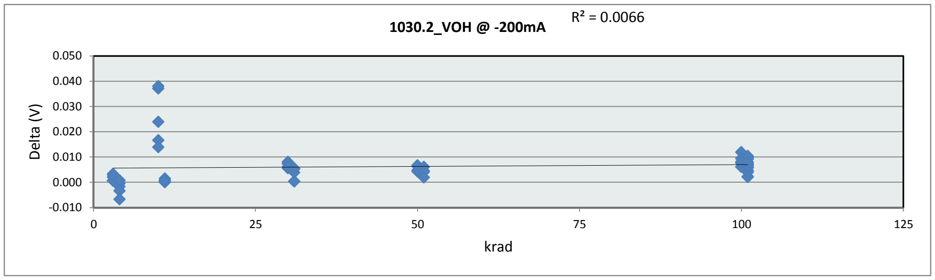
krad	3 biased	3 unbiased	10 biased	10 unbiased	30 biased	30 unbiased	50 biased	50 unbiased	100 biased	100 unbiased
LL	13.310	13.310	13.310	13.310	13.310	13.310	13.310	13.310	13.310	13.310
Min	13.534	13.538	13.491	13.537	13.532	13.535	13.534	13.535	13.527	13.533
Average	13.539	13.541	13.510	13.540	13.535	13.537	13.536	13.537	13.533	13.537
Max	13.543	13.544	13.527	13.543	13.538	13.540	13.541	13.538	13.538	13.542
UL	15.000	15.000	15.000	15.000	15.000	15.000	15.000	15.000	15.000	15.000



TID Report
Device Name

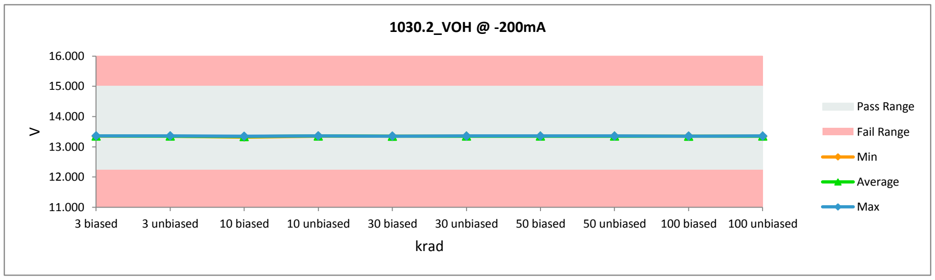
	1030.2_VOH @ -200m	
Test Site		
Tester		
Test Number		
Unit	V	V
Max Limit	15	15
Min Limit	12.24	12.24

krad	Serial #	Pre	Post	Delta
3	135	13.360	13.359	0.001
3	136	13.357	13.355	0.002
3	138	13.354	13.353	0.001
3	139	13.355	13.351	0.003
3	143	13.362	13.359	0.003
4	1	13.354	13.355	0.000
4	2	13.344	13.351	-0.007
4	3	13.356	13.358	-0.002
4	5	13.350	13.353	-0.003
4	7	13.356	13.355	0.001
10	144	13.359	13.322	0.037
10	145	13.362	13.324	0.038
10	146	13.364	13.348	0.017
10	149	13.363	13.349	0.014
10	150	13.357	13.333	0.024
11	8	13.354	13.353	0.001
11	11	13.359	13.359	0.000
11	14	13.355	13.353	0.002
11	15	13.358	13.358	0.001
11	19	13.354	13.353	0.000
30	151	13.362	13.354	0.008
30	153	13.359	13.354	0.006
30	154	13.358	13.351	0.007
30	155	13.352	13.344	0.008
30	156	13.358	13.352	0.006
31	22	13.353	13.349	0.004
31	23	13.355	13.355	0.000
31	31	13.361	13.356	0.006
31	37	13.356	13.356	0.000
31	42	13.359	13.354	0.005
50	173	13.360	13.356	0.004
50	174	13.357	13.351	0.006
50	175	13.359	13.352	0.007
50	183	13.362	13.355	0.006
50	187	13.354	13.349	0.005
51	43	13.357	13.352	0.005
51	45	13.354	13.348	0.006
51	48	13.362	13.358	0.004
51	49	13.359	13.354	0.004
51	50	13.354	13.352	0.002
100	191	13.360	13.354	0.006
100	195	13.357	13.349	0.008
100	199	13.359	13.347	0.012
100	203	13.362	13.352	0.009
100	207	13.354	13.347	0.008
101	69	13.359	13.353	0.006
101	70	13.358	13.354	0.005
101	71	13.352	13.345	0.007
101	74	13.352	13.348	0.004
101	76	13.359	13.352	0.007
101	81	13.362	13.353	0.010
101	82	13.356	13.345	0.010
101	85	13.360	13.354	0.007
101	94	13.358	13.348	0.009
101	95	13.364	13.354	0.010
101	99	13.361	13.352	0.009
101	103	13.361	13.351	0.010
101	109	13.362	13.354	0.008
101	110	13.349	13.347	0.002
101	112	13.354	13.352	0.002
101	115	13.359	13.354	0.004
101	117	13.361	13.355	0.006
101	118	13.360	13.354	0.006
101	122	13.361	13.355	0.006
101	125	13.362	13.355	0.007
101	126	13.358	13.352	0.007
101	129	13.361	13.353	0.008
	Max	13.364	13.359	0.038
	Average	13.358	13.351	0.006
	Min	13.344	13.322	-0.007
	Std Dev	0.004	0.006	0.007



	1030.2_VOH @ -200mA	
Test Site		
Tester		
Test Number		
Max Limit	15	V
Min Limit	12.24	V

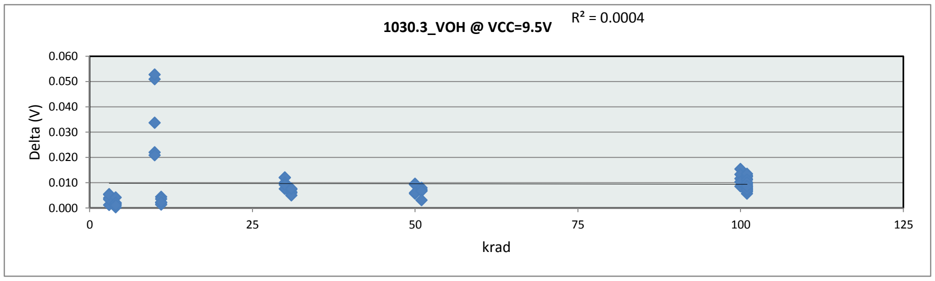
krad	3 biased	3 unbiased	10 biased	10 unbiased	30 biased	30 unbiased	50 biased	50 unbiased	100 biased	100 unbiased
LL	12.240	12.240	12.240	12.240	12.240	12.240	12.240	12.240	12.240	12.240
Min	13.351	13.351	13.322	13.353	13.344	13.349	13.350	13.348	13.347	13.345
Average	13.355	13.354	13.335	13.355	13.351	13.354	13.353	13.353	13.350	13.352
Max	13.359	13.358	13.349	13.359	13.354	13.356	13.356	13.358	13.354	13.355
UL	15.000	15.000	15.000	15.000	15.000	15.000	15.000	15.000	15.000	15.000



TID Report
Device Name

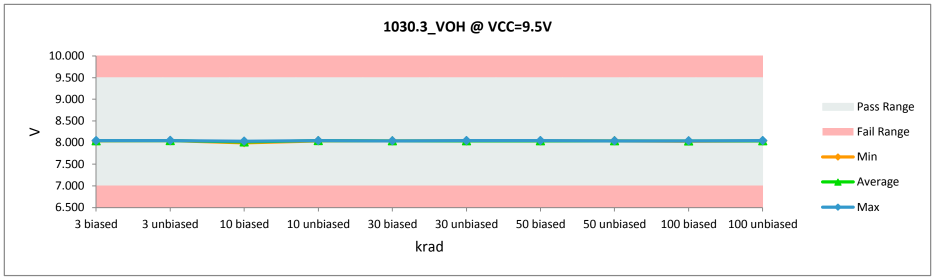
	1030.3_VOH @ VCC=9	
Test Site		
Tester		
Test Number		
Unit	V	V
Max Limit	9.5	9.5
Min Limit	7	7

krad	Serial #	Pre	Post	Delta
3	135	8.047	8.046	0.001
3	136	8.043	8.039	0.004
3	138	8.047	8.044	0.003
3	139	8.043	8.038	0.005
3	143	8.047	8.041	0.005
4	1	8.042	8.041	0.000
4	2	8.044	8.042	0.002
4	3	8.047	8.043	0.004
4	5	8.047	8.045	0.002
4	7	8.048	8.047	0.001
10	144	8.045	7.994	0.051
10	145	8.048	7.996	0.053
10	146	8.050	8.028	0.022
10	149	8.051	8.030	0.021
10	150	8.052	8.018	0.034
11	8	8.043	8.041	0.002
11	11	8.047	8.045	0.001
11	14	8.044	8.040	0.004
11	15	8.047	8.043	0.004
11	19	8.045	8.042	0.002
30	151	8.053	8.041	0.012
30	153	8.048	8.040	0.008
30	154	8.047	8.035	0.012
30	155	8.045	8.035	0.010
30	156	8.048	8.039	0.009
31	22	8.045	8.038	0.006
31	23	8.046	8.040	0.006
31	31	8.050	8.043	0.007
31	37	8.048	8.043	0.005
31	42	8.045	8.037	0.008
50	173	8.049	8.043	0.006
50	174	8.050	8.040	0.010
50	175	8.046	8.037	0.009
50	183	8.047	8.038	0.009
50	187	8.043	8.038	0.006
51	43	8.048	8.041	0.007
51	45	8.048	8.040	0.008
51	48	8.047	8.040	0.007
51	49	8.046	8.039	0.007
51	50	8.041	8.038	0.003
100	191	8.049	8.040	0.009
100	195	8.050	8.038	0.012
100	199	8.046	8.031	0.015
100	203	8.047	8.034	0.013
100	207	8.043	8.033	0.010
101	69	8.046	8.041	0.006
101	70	8.044	8.037	0.007
101	71	8.045	8.036	0.009
101	74	8.043	8.037	0.007
101	76	8.047	8.038	0.009
101	81	8.050	8.039	0.011
101	82	8.049	8.036	0.013
101	85	8.054	8.044	0.010
101	94	8.049	8.039	0.010
101	95	8.053	8.041	0.012
101	99	8.054	8.042	0.012
101	103	8.051	8.037	0.014
101	109	8.051	8.040	0.011
101	110	8.049	8.039	0.010
101	112	8.050	8.042	0.009
101	115	8.047	8.039	0.008
101	117	8.046	8.039	0.008
101	118	8.046	8.038	0.007
101	122	8.048	8.041	0.007
101	125	8.050	8.042	0.008
101	126	8.050	8.043	0.007
101	129	8.049	8.040	0.009
	Max	8.054	8.047	0.053
	Average	8.047	8.038	0.010
	Min	8.041	7.994	0.000
	Std Dev	0.003	0.009	0.009



	1030.3_VOH @ VCC=9.5V	
Test Site		
Tester		
Test Number		
Max Limit	9.5	V
Min Limit	7	V

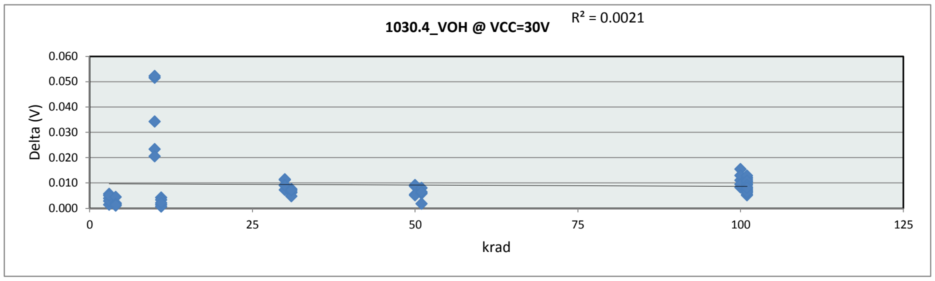
krad	3 biased	3 unbiased	10 biased	10 unbiased	30 biased	30 unbiased	50 biased	50 unbiased	100 biased	100 unbiased
LL	7.000	7.000	7.000	7.000	7.000	7.000	7.000	7.000	7.000	7.000
Min	8.038	8.041	7.994	8.040	8.035	8.037	8.037	8.038	8.031	8.036
Average	8.042	8.044	8.013	8.042	8.038	8.040	8.039	8.040	8.035	8.040
Max	8.046	8.047	8.030	8.045	8.041	8.043	8.043	8.041	8.041	8.044
UL	9.500	9.500	9.500	9.500	9.500	9.500	9.500	9.500	9.500	9.500



TID Report
Device Name

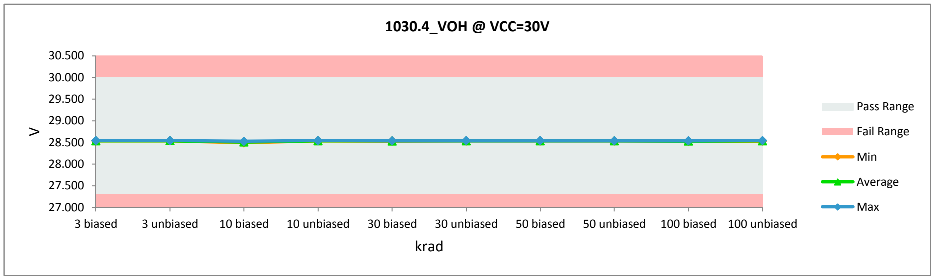
	1030.4_VOH @ VCC=3	
Test Site		
Tester		
Test Number		
Unit	V	V
Max Limit	30	30
Min Limit	27.31	27.31

krad	Serial #	Pre	Post	Delta
3	135	28.542	28.541	0.001
3	136	28.537	28.533	0.004
3	138	28.541	28.538	0.003
3	139	28.537	28.531	0.006
3	143	28.541	28.536	0.005
4	1	28.536	28.535	0.001
4	2	28.538	28.536	0.002
4	3	28.541	28.537	0.004
4	5	28.541	28.540	0.002
4	7	28.543	28.541	0.001
10	144	28.539	28.488	0.052
10	145	28.542	28.490	0.052
10	146	28.545	28.522	0.023
10	149	28.545	28.524	0.021
10	150	28.546	28.512	0.034
11	8	28.538	28.536	0.001
11	11	28.541	28.540	0.001
11	14	28.539	28.535	0.004
11	15	28.541	28.538	0.003
11	19	28.539	28.537	0.002
30	151	28.547	28.536	0.011
30	153	28.542	28.535	0.007
30	154	28.541	28.530	0.011
30	155	28.539	28.530	0.009
30	156	28.543	28.534	0.009
31	22	28.539	28.533	0.006
31	23	28.540	28.534	0.006
31	31	28.544	28.537	0.007
31	37	28.542	28.538	0.005
31	42	28.539	28.532	0.007
50	173	28.543	28.538	0.005
50	174	28.544	28.536	0.009
50	175	28.540	28.531	0.009
50	183	28.542	28.533	0.009
50	187	28.538	28.533	0.005
51	43	28.543	28.536	0.006
51	45	28.543	28.535	0.008
51	48	28.542	28.536	0.006
51	49	28.540	28.534	0.006
51	50	28.535	28.533	0.002
100	191	28.543	28.535	0.008
100	195	28.544	28.533	0.011
100	199	28.540	28.525	0.015
100	203	28.542	28.529	0.013
100	207	28.538	28.528	0.009
101	69	28.541	28.536	0.005
101	70	28.538	28.532	0.006
101	71	28.539	28.531	0.008
101	74	28.538	28.532	0.006
101	76	28.541	28.533	0.008
101	81	28.544	28.534	0.010
101	82	28.543	28.531	0.012
101	85	28.549	28.539	0.010
101	94	28.544	28.534	0.010
101	95	28.548	28.536	0.012
101	99	28.548	28.537	0.011
101	103	28.545	28.533	0.013
101	109	28.545	28.535	0.011
101	110	28.543	28.534	0.009
101	112	28.545	28.537	0.008
101	115	28.542	28.534	0.007
101	117	28.541	28.534	0.007
101	118	28.540	28.534	0.006
101	122	28.542	28.535	0.007
101	125	28.544	28.538	0.006
101	126	28.544	28.538	0.006
101	129	28.543	28.535	0.008
	Max	28.549	28.541	0.052
	Average	28.542	28.533	0.009
	Min	28.535	28.488	0.001
	Std Dev	0.003	0.009	0.009



	1030.4_VOH @ VCC=30V	
Test Site		
Tester		
Test Number		
Max Limit	30	V
Min Limit	27.31	V

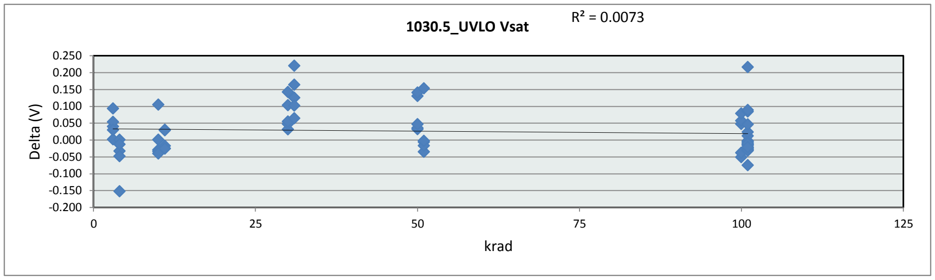
krad	3 biased	3 unbiased	10 biased	10 unbiased	30 biased	30 unbiased	50 biased	50 unbiased	100 biased	100 unbiased
LL	27.310	27.310	27.310	27.310	27.310	27.310	27.310	27.310	27.310	27.310
Min	28.532	28.535	28.488	28.535	28.530	28.532	28.531	28.533	28.525	28.531
Average	28.536	28.538	28.507	28.537	28.533	28.535	28.534	28.535	28.530	28.535
Max	28.541	28.541	28.524	28.540	28.536	28.538	28.538	28.536	28.535	28.539
UL	30.000	30.000	30.000	30.000	30.000	30.000	30.000	30.000	30.000	30.000



TID Report
Device Name

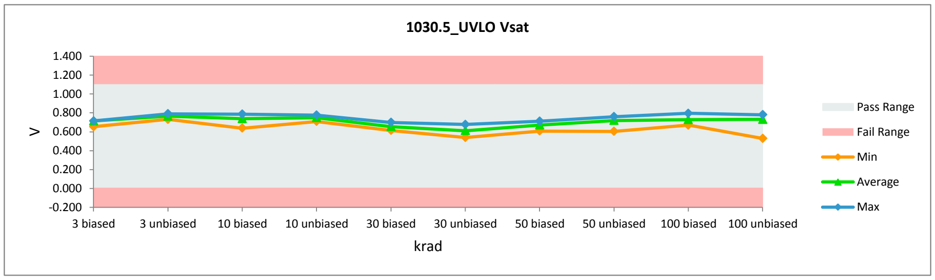
	1030.5_UVLO Vsat	
Test Site		
Tester		
Test Number		
Unit	V	V
Max Limit	1.1	1.1
Min Limit	0.005	0.005

krad	Serial #	Pre	Post	Delta
3	135	0.702	0.700	0.002
3	136	0.753	0.713	0.040
3	138	0.748	0.654	0.094
3	139	0.752	0.698	0.054
3	143	0.744	0.714	0.030
4	1	0.732	0.731	0.001
4	2	0.759	0.791	-0.033
4	3	0.630	0.782	-0.152
4	5	0.731	0.779	-0.048
4	7	0.725	0.738	-0.013
10	144	0.756	0.785	-0.029
10	145	0.739	0.773	-0.034
10	146	0.747	0.787	-0.040
10	149	0.744	0.639	0.105
10	150	0.713	0.712	0.001
11	8	0.752	0.770	-0.017
11	11	0.744	0.769	-0.025
11	14	0.752	0.778	-0.025
11	15	0.740	0.710	0.030
11	19	0.753	0.724	0.029
30	151	0.658	0.626	0.032
30	153	0.747	0.699	0.048
30	154	0.748	0.693	0.055
30	155	0.757	0.615	0.142
30	156	0.741	0.638	0.103
31	22	0.760	0.539	0.220
31	23	0.751	0.626	0.125
31	31	0.729	0.627	0.102
31	37	0.742	0.677	0.065
31	42	0.753	0.590	0.164
50	173	0.745	0.615	0.130
50	174	0.740	0.708	0.032
50	175	0.748	0.712	0.035
50	183	0.749	0.608	0.141
50	187	0.757	0.710	0.047
51	43	0.713	0.719	-0.006
51	45	0.725	0.760	-0.035
51	48	0.757	0.604	0.153
51	49	0.737	0.753	-0.017
51	50	0.757	0.760	-0.002
100	191	0.745	0.698	0.047
100	195	0.740	0.791	-0.051
100	199	0.748	0.691	0.057
100	203	0.749	0.670	0.079
100	207	0.757	0.795	-0.038
101	69	0.750	0.752	-0.002
101	70	0.751	0.756	-0.005
101	71	0.748	0.774	-0.026
101	74	0.759	0.746	0.012
101	76	0.752	0.758	-0.006
101	81	0.706	0.719	-0.013
101	82	0.701	0.776	-0.075
101	85	0.692	0.715	-0.023
101	94	0.742	0.763	-0.021
101	95	0.734	0.710	0.024
101	99	0.728	0.743	-0.016
101	103	0.740	0.768	-0.027
101	109	0.712	0.727	-0.015
101	110	0.749	0.781	-0.031
101	112	0.749	0.702	0.046
101	115	0.742	0.658	0.084
101	117	0.740	0.752	-0.012
101	118	0.753	0.664	0.089
101	122	0.746	0.530	0.216
101	125	0.717	0.747	-0.030
101	126	0.751	0.761	-0.011
101	129	0.749	0.770	-0.021
	Max	0.760	0.795	0.220
	Average	0.738	0.713	0.026
	Min	0.630	0.530	-0.152
	Std Dev	0.023	0.063	0.069



	1030.5_UVLO Vsat	
Test Site		
Tester		
Test Number		
Max Limit	1.1	V
Min Limit	0.005	V

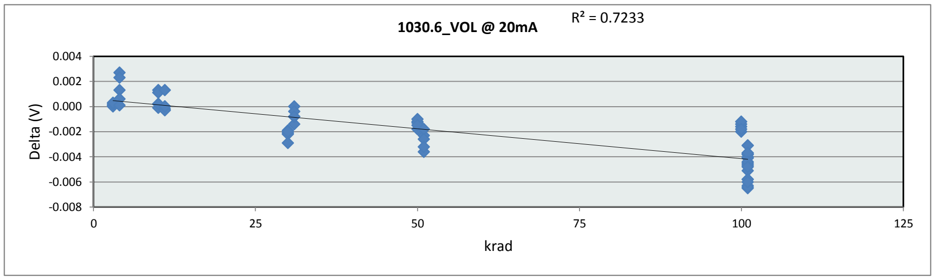
krad	3 biased	3 unbiased	10 biased	10 unbiased	30 biased	30 unbiased	50 biased	50 unbiased	100 biased	100 unbiased
LL	0.005	0.005	0.005	0.005	0.005	0.005	0.005	0.005	0.005	0.005
Min	0.654	0.731	0.639	0.710	0.615	0.539	0.608	0.604	0.670	0.530
Average	0.714	0.764	0.739	0.750	0.654	0.612	0.671	0.719	0.729	0.731
Max	0.714	0.791	0.787	0.778	0.699	0.677	0.712	0.760	0.795	0.781
UL	1.100	1.100	1.100	1.100	1.100	1.100	1.100	1.100	1.100	1.100



TID Report
Device Name

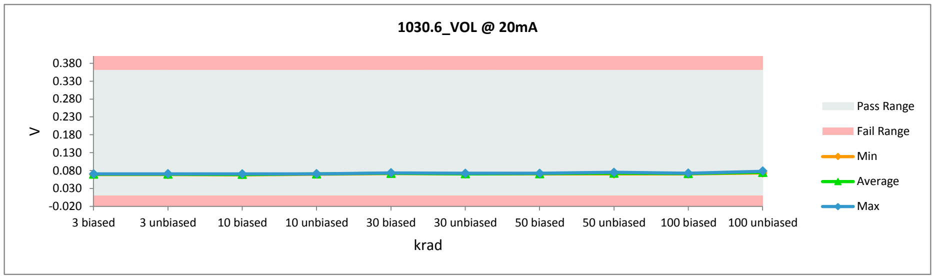
	1030.6_VOL @ 20mA	
Test Site		
Tester		
Test Number		
Unit	V	V
Max Limit	0.36	0.36
Min Limit	0.01	0.01

krad	Serial #	Pre	Post	Delta
3	135	0.070	0.070	0.000
3	136	0.070	0.069	0.000
3	138	0.071	0.071	0.000
3	139	0.070	0.070	0.000
3	143	0.069	0.069	0.000
4	1	0.072	0.070	0.003
4	2	0.073	0.071	0.002
4	3	0.070	0.069	0.001
4	5	0.071	0.071	0.001
4	7	0.070	0.070	0.000
10	144	0.070	0.069	0.001
10	145	0.069	0.068	0.001
10	146	0.069	0.069	0.000
10	149	0.070	0.070	0.000
10	150	0.071	0.070	0.000
11	8	0.071	0.071	0.000
11	11	0.070	0.070	0.000
11	14	0.071	0.071	0.000
11	15	0.071	0.070	0.001
11	19	0.071	0.071	0.000
30	151	0.070	0.072	-0.002
30	153	0.070	0.072	-0.002
30	154	0.070	0.072	-0.002
30	155	0.071	0.074	-0.003
30	156	0.070	0.072	-0.002
31	22	0.071	0.072	-0.001
31	23	0.071	0.071	0.000
31	31	0.070	0.071	-0.001
31	37	0.071	0.071	0.000
31	42	0.070	0.071	-0.001
50	173	0.070	0.072	-0.002
50	174	0.070	0.071	-0.001
50	175	0.070	0.071	-0.001
50	183	0.069	0.070	-0.001
50	187	0.071	0.072	-0.002
51	43	0.070	0.072	-0.002
51	45	0.071	0.075	-0.004
51	48	0.069	0.071	-0.002
51	49	0.069	0.072	-0.003
51	50	0.070	0.073	-0.003
100	191	0.070	0.072	-0.002
100	195	0.070	0.071	-0.002
100	199	0.070	0.071	-0.001
100	203	0.069	0.071	-0.001
100	207	0.071	0.072	-0.002
101	69	0.069	0.075	-0.006
101	70	0.070	0.074	-0.004
101	71	0.072	0.078	-0.006
101	74	0.071	0.075	-0.004
101	76	0.070	0.075	-0.005
101	81	0.070	0.074	-0.004
101	82	0.071	0.077	-0.006
101	85	0.070	0.074	-0.004
101	94	0.071	0.076	-0.005
101	95	0.071	0.074	-0.003
101	99	0.070	0.074	-0.004
101	103	0.070	0.076	-0.007
101	109	0.070	0.074	-0.005
101	110	0.072	0.078	-0.006
101	112	0.071	0.075	-0.004
101	115	0.070	0.074	-0.004
101	117	0.070	0.073	-0.003
101	118	0.070	0.073	-0.004
101	122	0.069	0.073	-0.004
101	125	0.070	0.074	-0.004
101	126	0.070	0.075	-0.005
101	129	0.070	0.076	-0.006
	Max	0.073	0.078	0.003
	Average	0.070	0.072	-0.002
	Min	0.069	0.068	-0.007
	Std Dev	0.001	0.002	0.002



	1030.6_VOL @ 20mA	
Test Site		
Tester		
Test Number		
Max Limit	0.36	V
Min Limit	0.01	V

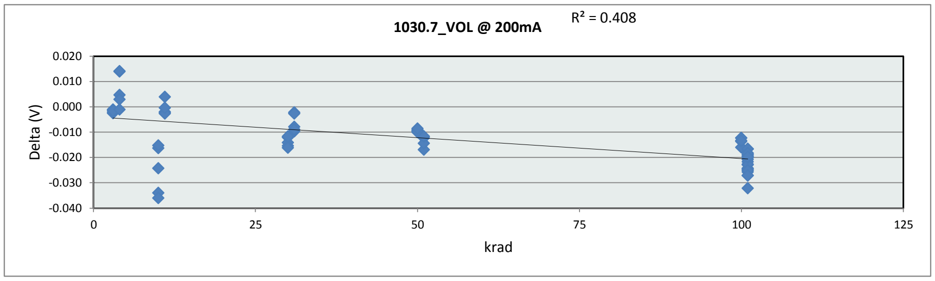
krad	3 biased	3 unbiased	10 biased	10 unbiased	30 biased	30 unbiased	50 biased	50 unbiased	100 biased	100 unbiased
LL	0.010	0.010	0.010	0.010	0.010	0.010	0.010	0.010	0.010	0.010
Min	0.069	0.069	0.068	0.070	0.072	0.071	0.070	0.071	0.071	0.073
Average	0.070	0.070	0.069	0.071	0.072	0.071	0.071	0.073	0.071	0.075
Max	0.071	0.071	0.070	0.071	0.074	0.072	0.072	0.075	0.073	0.078
UL	0.360	0.360	0.360	0.360	0.360	0.360	0.360	0.360	0.360	0.360



TID Report
Device Name

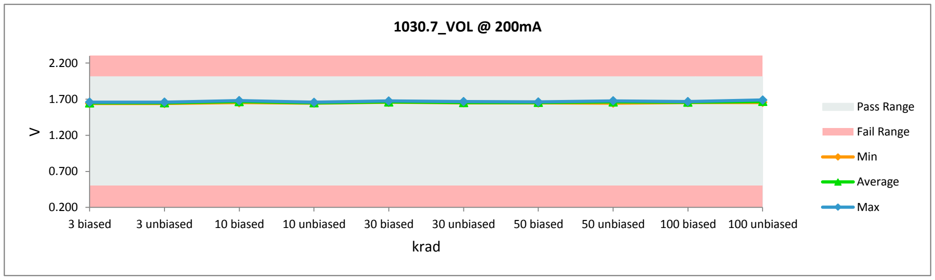
	1030.7_VOL @ 200mA	
Test Site		
Tester		
Test Number		
Unit	V	V
Max Limit	2.01	2.01
Min Limit	0.5	0.5

krad	Serial #	Pre	Post	Delta
3	135	1.646	1.647	-0.001
3	136	1.642	1.644	-0.002
3	138	1.658	1.659	-0.001
3	139	1.651	1.653	-0.003
3	143	1.638	1.640	-0.002
4	1	1.659	1.645	0.014
4	2	1.672	1.658	0.014
4	3	1.646	1.641	0.005
4	5	1.661	1.658	0.003
4	7	1.652	1.653	-0.001
10	144	1.645	1.679	-0.034
10	145	1.637	1.673	-0.036
10	146	1.635	1.651	-0.016
10	149	1.638	1.653	-0.015
10	150	1.655	1.680	-0.024
11	8	1.654	1.656	-0.002
11	11	1.643	1.645	-0.002
11	14	1.652	1.654	-0.003
11	15	1.649	1.645	0.004
11	19	1.655	1.656	0.000
30	151	1.646	1.660	-0.014
30	153	1.645	1.657	-0.012
30	154	1.643	1.659	-0.015
30	155	1.660	1.676	-0.016
30	156	1.649	1.661	-0.012
31	22	1.656	1.665	-0.010
31	23	1.649	1.651	-0.002
31	31	1.645	1.653	-0.008
31	37	1.650	1.653	-0.003
31	42	1.641	1.650	-0.009
50	173	1.641	1.650	-0.010
50	174	1.652	1.661	-0.009
50	175	1.645	1.655	-0.010
50	183	1.639	1.649	-0.010
50	187	1.653	1.662	-0.009
51	43	1.652	1.664	-0.012
51	45	1.660	1.677	-0.017
51	48	1.634	1.646	-0.012
51	49	1.640	1.655	-0.014
51	50	1.651	1.663	-0.012
100	191	1.641	1.653	-0.012
100	195	1.652	1.664	-0.012
100	199	1.645	1.661	-0.016
100	203	1.639	1.653	-0.014
100	207	1.653	1.667	-0.013
101	69	1.643	1.668	-0.025
101	70	1.640	1.661	-0.021
101	71	1.661	1.686	-0.024
101	74	1.656	1.672	-0.017
101	76	1.643	1.668	-0.024
101	81	1.641	1.663	-0.022
101	82	1.656	1.683	-0.027
101	85	1.650	1.669	-0.020
101	94	1.653	1.676	-0.023
101	95	1.644	1.663	-0.019
101	99	1.648	1.670	-0.023
101	103	1.641	1.673	-0.032
101	109	1.636	1.662	-0.026
101	110	1.663	1.688	-0.025
101	112	1.656	1.673	-0.017
101	115	1.640	1.659	-0.019
101	117	1.639	1.656	-0.017
101	118	1.640	1.659	-0.018
101	122	1.640	1.659	-0.018
101	125	1.645	1.665	-0.020
101	126	1.650	1.670	-0.020
101	129	1.641	1.669	-0.027
	Max	1.672	1.688	0.014
	Average	1.648	1.661	-0.013
	Min	1.634	1.640	-0.036
	Std Dev	0.008	0.011	0.010



	1030.7_VOL @ 200mA	
Test Site		
Tester		
Test Number		
Max Limit	2.01	V
Min Limit	0.5	V

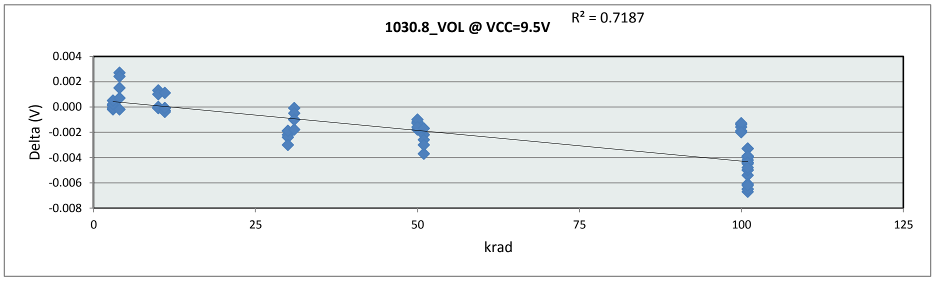
krad	3 biased	3 unbiased	10 biased	10 unbiased	30 biased	30 unbiased	50 biased	50 unbiased	100 biased	100 unbiased
LL	0.500	0.500	0.500	0.500	0.500	0.500	0.500	0.500	0.500	0.500
Min	1.640	1.641	1.652	1.645	1.657	1.650	1.649	1.646	1.653	1.656
Average	1.649	1.651	1.667	1.651	1.663	1.655	1.655	1.661	1.659	1.669
Max	1.659	1.658	1.680	1.656	1.676	1.665	1.662	1.677	1.667	1.688
UL	2.010	2.010	2.010	2.010	2.010	2.010	2.010	2.010	2.010	2.010



TID Report
Device Name

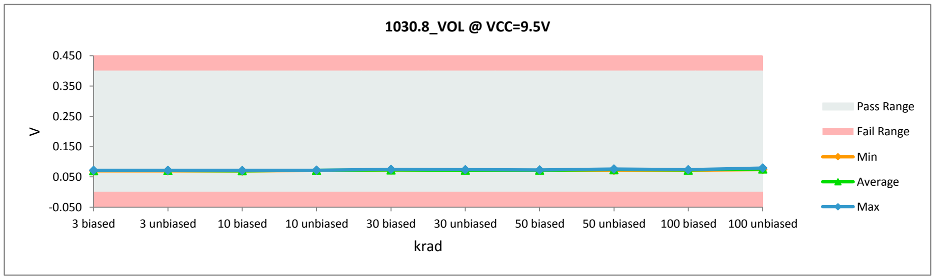
	1030.8_VOL @ VCC=9.	
Test Site		
Tester		
Test Number		
Unit	V	V
Max Limit	0.4	0.4
Min Limit	0	0

krad	Serial #	Pre	Post	Delta
3	135	0.070	0.071	0.000
3	136	0.071	0.071	0.000
3	138	0.071	0.072	0.000
3	139	0.071	0.071	0.000
3	143	0.070	0.070	0.001
4	1	0.073	0.071	0.003
4	2	0.074	0.072	0.002
4	3	0.071	0.070	0.002
4	5	0.072	0.072	0.001
4	7	0.071	0.071	0.000
10	144	0.071	0.070	0.001
10	145	0.070	0.069	0.001
10	146	0.070	0.070	0.000
10	149	0.071	0.071	0.000
10	150	0.071	0.071	0.000
11	8	0.072	0.072	0.000
11	11	0.071	0.071	0.000
11	14	0.072	0.072	0.000
11	15	0.072	0.071	0.001
11	19	0.072	0.072	0.000
30	151	0.071	0.073	-0.002
30	153	0.071	0.073	-0.002
30	154	0.071	0.073	-0.002
30	155	0.072	0.075	-0.003
30	156	0.071	0.073	-0.002
31	22	0.072	0.073	-0.002
31	23	0.072	0.072	0.000
31	31	0.071	0.072	-0.001
31	37	0.071	0.072	-0.001
31	42	0.071	0.072	-0.001
50	173	0.071	0.073	-0.002
50	174	0.071	0.072	-0.001
50	175	0.071	0.072	-0.001
50	183	0.070	0.071	-0.001
50	187	0.072	0.073	-0.002
51	43	0.071	0.073	-0.002
51	45	0.072	0.076	-0.004
51	48	0.070	0.072	-0.002
51	49	0.070	0.073	-0.003
51	50	0.071	0.074	-0.003
100	191	0.071	0.073	-0.002
100	195	0.071	0.072	-0.002
100	199	0.071	0.072	-0.001
100	203	0.070	0.072	-0.001
100	207	0.072	0.074	-0.002
101	69	0.070	0.076	-0.006
101	70	0.071	0.075	-0.005
101	71	0.073	0.079	-0.006
101	74	0.072	0.076	-0.004
101	76	0.071	0.076	-0.005
101	81	0.071	0.075	-0.004
101	82	0.072	0.078	-0.006
101	85	0.071	0.075	-0.004
101	94	0.072	0.077	-0.005
101	95	0.072	0.075	-0.003
101	99	0.071	0.076	-0.004
101	103	0.071	0.078	-0.007
101	109	0.070	0.075	-0.005
101	110	0.073	0.079	-0.007
101	112	0.072	0.076	-0.004
101	115	0.071	0.075	-0.004
101	117	0.071	0.074	-0.003
101	118	0.071	0.075	-0.004
101	122	0.070	0.074	-0.004
101	125	0.071	0.075	-0.004
101	126	0.071	0.076	-0.005
101	129	0.071	0.077	-0.006
	Max	0.074	0.079	0.003
	Average	0.071	0.073	-0.002
	Min	0.070	0.069	-0.007
	Std Dev	0.001	0.002	0.002



	1030.8_VOL @ VCC=9.5V	
Test Site		
Tester		
Test Number		
Max Limit	0.4	V
Min Limit	0	V

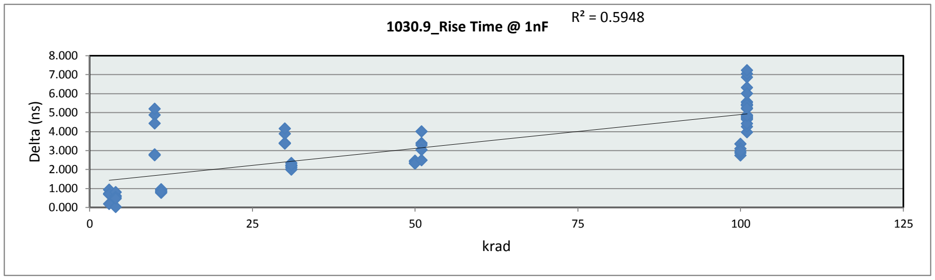
krad	3 biased	3 unbiased	10 biased	10 unbiased	30 biased	30 unbiased	50 biased	50 unbiased	100 biased	100 unbiased
LL	0.000	0.000	0.000	0.000	0.000	0.000	0.000	0.000	0.000	0.000
Min	0.070	0.070	0.069	0.071	0.073	0.072	0.071	0.072	0.072	0.074
Average	0.071	0.071	0.070	0.072	0.073	0.072	0.072	0.074	0.073	0.076
Max	0.072	0.072	0.071	0.072	0.075	0.074	0.073	0.076	0.074	0.079
UL	0.400	0.400	0.400	0.400	0.400	0.400	0.400	0.400	0.400	0.400



TID Report
Device Name

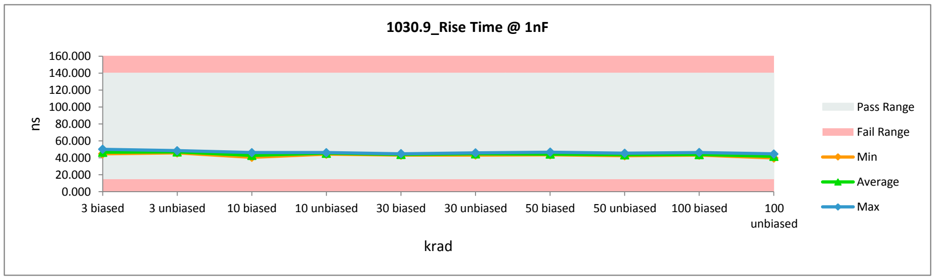
	1030.9_Rise Time @ 1	
Test Site		
Tester		
Test Number		
Unit	ns	ns
Max Limit	140	140
Min Limit	15	15

krad	Serial #	Pre	Post	Delta
3	135	47.447	47.264	0.183
3	136	45.345	44.654	0.691
3	138	50.684	49.956	0.728
3	139	46.282	45.354	0.928
3	143	45.407	44.701	0.706
4	1	45.836	45.808	0.028
4	2	47.671	47.063	0.608
4	3	46.462	45.665	0.797
4	5	48.372	47.821	0.552
4	7	48.701	48.236	0.465
10	144	46.075	41.199	4.876
10	145	45.778	40.574	5.204
10	146	45.647	42.849	2.798
10	149	46.085	43.336	2.749
10	150	50.411	45.978	4.434
11	8	46.971	46.064	0.907
11	11	45.396	44.556	0.840
11	14	46.517	45.560	0.957
11	15	45.042	44.273	0.769
11	19	46.492	45.667	0.826
30	151	47.142	43.768	3.374
30	153	47.158	43.758	3.400
30	154	46.901	43.018	3.883
30	155	48.917	44.757	4.160
30	156	47.318	43.950	3.368
31	22	48.186	45.850	2.336
31	23	46.231	44.138	2.093
31	31	47.181	45.000	2.182
31	37	46.455	44.465	1.990
31	42	45.521	43.291	2.230
50	173	45.859	43.535	2.324
50	174	49.071	46.643	2.428
50	175	46.360	43.896	2.464
50	183	46.617	44.204	2.413
50	187	46.036	43.723	2.313
51	43	48.760	45.370	3.390
51	45	47.902	43.899	4.003
51	48	44.839	42.351	2.489
51	49	46.136	42.847	3.290
51	50	45.560	42.527	3.033
100	191	45.859	43.120	2.739
100	195	49.071	46.200	2.871
100	199	46.360	43.007	3.352
100	203	46.617	43.516	3.100
100	207	46.036	43.077	2.960
101	69	47.042	41.482	5.560
101	70	44.464	39.819	4.645
101	71	47.771	40.906	6.865
101	74	47.715	42.971	4.744
101	76	46.335	40.939	5.395
101	81	45.955	41.154	4.801
101	82	48.186	41.868	6.318
101	85	49.336	44.470	4.866
101	94	48.283	42.741	5.542
101	95	47.581	42.374	5.207
101	99	49.290	43.860	5.430
101	103	46.741	39.695	7.046
101	109	45.672	40.294	5.378
101	110	49.211	41.977	7.234
101	112	48.477	43.075	5.402
101	115	45.596	40.901	4.694
101	117	44.234	40.270	3.964
101	118	44.997	40.734	4.263
101	122	46.310	41.891	4.419
101	125	47.193	42.354	4.838
101	126	48.401	43.164	5.237
101	129	45.912	39.906	6.007
	Max	50.684	49.956	7.234
	Average	46.917	43.632	3.285
	Min	44.234	39.695	0.028
	Std Dev	1.418	2.166	1.891



	1030.9_Rise Time @ 1nF	
Test Site		
Tester		
Test Number		
Max Limit	140	ns
Min Limit	15	ns

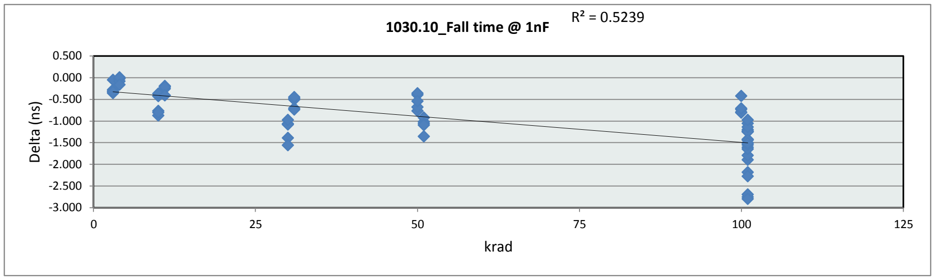
krad	3 biased	3 unbiased	10 biased	10 unbiased	30 biased	30 unbiased	50 biased	50 unbiased	100 biased	100 unbiased
LL	15.000	15.000	15.000	15.000	15.000	15.000	15.000	15.000	15.000	15.000
Min	44.654	45.665	40.574	44.273	43.018	43.291	43.535	42.351	43.007	39.695
Average	46.386	46.918	42.787	45.224	43.850	44.549	44.400	43.399	43.784	41.675
Max	49.956	48.236	45.978	46.064	44.757	45.850	46.643	45.370	46.200	44.470
UL	140.000	140.000	140.000	140.000	140.000	140.000	140.000	140.000	140.000	140.000



TID Report
Device Name

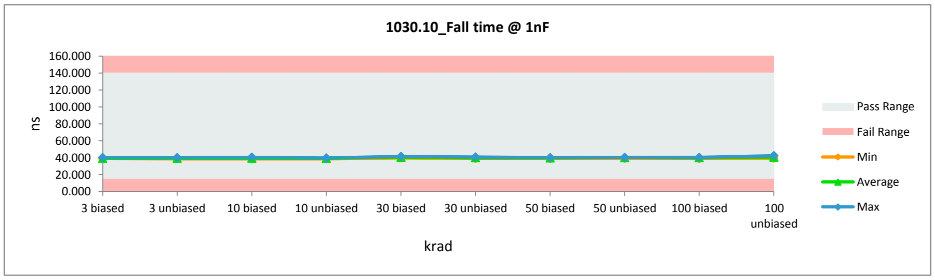
	1030.10_Fall time @ 1	
Test Site		
Tester		
Test Number		
Unit	ns	ns
Max Limit	140	140
Min Limit	15	15

krad	Serial #	Pre	Post	Delta
3	135	38.792	39.150	-0.358
3	136	38.923	38.975	-0.051
3	138	39.864	40.178	-0.313
3	139	39.414	39.697	-0.283
3	143	38.670	39.004	-0.333
4	1	40.193	40.217	-0.024
4	2	39.710	39.734	-0.024
4	3	39.204	39.290	-0.086
4	5	38.825	38.822	0.003
4	7	39.010	39.172	-0.163
10	144	39.810	40.687	-0.877
10	145	38.523	39.291	-0.768
10	146	38.287	38.716	-0.429
10	149	38.415	38.785	-0.370
10	150	39.445	40.250	-0.804
11	8	39.579	39.776	-0.197
11	11	38.549	38.765	-0.216
11	14	39.500	39.755	-0.255
11	15	39.082	39.298	-0.216
11	19	39.155	39.568	-0.413
30	151	38.685	39.751	-1.066
30	153	39.258	40.340	-1.082
30	154	39.277	40.669	-1.392
30	155	39.999	41.559	-1.560
30	156	38.781	39.759	-0.978
31	22	40.166	40.873	-0.707
31	23	39.194	39.678	-0.484
31	31	38.706	39.215	-0.509
31	37	38.799	39.251	-0.452
31	42	39.879	40.615	-0.737
50	173	38.142	38.914	-0.772
50	174	39.381	39.781	-0.400
50	175	39.583	39.945	-0.362
50	183	39.685	40.368	-0.683
50	187	39.457	40.002	-0.544
51	43	39.541	40.564	-1.024
51	45	39.209	40.568	-1.359
51	48	38.328	39.253	-0.925
51	49	38.478	39.540	-1.062
51	50	39.288	40.386	-1.098
100	191	38.142	38.938	-0.796
100	195	39.381	39.805	-0.424
100	199	39.583	40.317	-0.734
100	203	39.685	40.496	-0.811
100	207	39.457	40.168	-0.711
101	69	39.327	41.226	-1.898
101	70	38.810	40.421	-1.611
101	71	39.510	42.267	-2.757
101	74	39.969	41.393	-1.424
101	76	39.527	41.321	-1.795
101	81	38.945	40.178	-1.233
101	82	39.896	42.080	-2.184
101	85	38.949	40.150	-1.201
101	94	39.681	41.333	-1.652
101	95	39.043	40.480	-1.437
101	99	39.536	40.789	-1.253
101	103	39.235	41.935	-2.700
101	109	38.367	39.877	-1.510
101	110	39.630	42.432	-2.802
101	112	39.190	40.741	-1.551
101	115	38.648	39.900	-1.252
101	117	38.569	39.626	-1.057
101	118	38.595	39.735	-1.141
101	122	39.457	40.436	-0.979
101	125	38.768	40.210	-1.442
101	126	38.622	40.138	-1.516
101	129	38.879	41.155	-2.276
	Max	40.193	42.432	0.003
	Average	39.167	40.115	-0.948
	Min	38.142	38.716	-2.802
	Std Dev	0.514	0.877	0.674



	1030.10_ Fall time @ 1nF	
Test Site		
Tester		
Test Number		
Max Limit	140	ns
Min Limit	15	ns

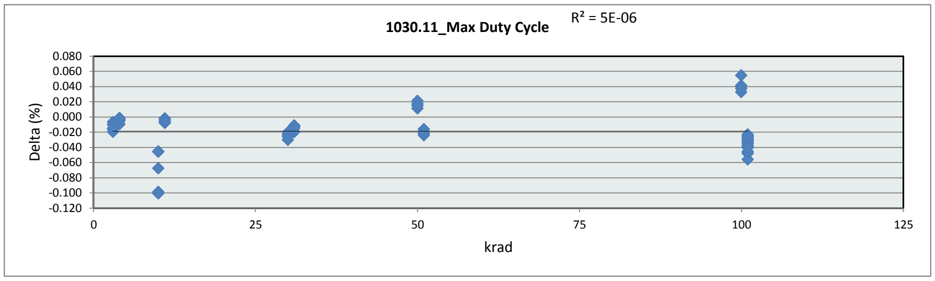
krad	3 biased	3 unbiased	10 biased	10 unbiased	30 biased	30 unbiased	50 biased	50 unbiased	100 biased	100 unbiased
LL	15.000	15.000	15.000	15.000	15.000	15.000	15.000	15.000	15.000	15.000
Min	38.975	38.822	38.716	38.765	39.751	39.215	38.914	39.253	38.938	39.626
Average	39.401	39.447	39.546	39.432	40.416	39.926	39.802	40.062	39.945	40.810
Max	40.178	40.217	40.687	39.776	41.559	40.873	40.368	40.568	40.496	42.432
UL	140.000	140.000	140.000	140.000	140.000	140.000	140.000	140.000	140.000	140.000



TID Report
Device Name

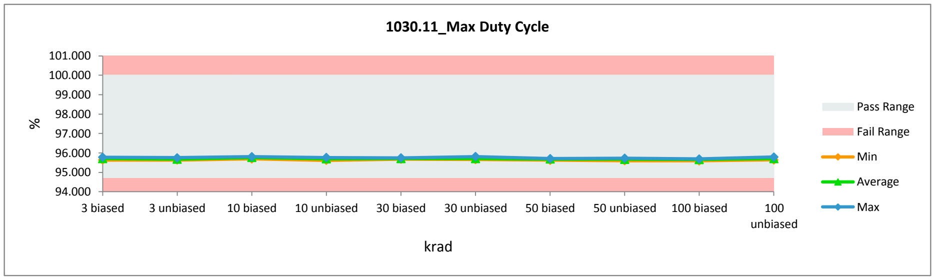
	1030.11_Max Duty Cy	
Test Site		
Tester		
Test Number		
Unit	%	%
Max Limit	100	100
Min Limit	94.7	94.7

krad	Serial #	Pre	Post	Delta
3	135	95.723	95.730	-0.007
3	136	95.708	95.718	-0.010
3	138	95.620	95.636	-0.016
3	139	95.657	95.676	-0.020
3	143	95.760	95.775	-0.015
4	1	95.751	95.752	-0.001
4	2	95.631	95.635	-0.005
4	3	95.714	95.724	-0.010
4	5	95.653	95.657	-0.003
4	7	95.652	95.654	-0.002
10	144	95.698	95.797	-0.099
10	145	95.703	95.804	-0.101
10	146	95.737	95.782	-0.046
10	149	95.720	95.765	-0.045
10	150	95.623	95.691	-0.068
11	8	95.704	95.707	-0.003
11	11	95.616	95.618	-0.002
11	14	95.732	95.740	-0.008
11	15	95.759	95.766	-0.007
11	19	95.647	95.653	-0.005
30	151	95.707	95.730	-0.023
30	153	95.685	95.708	-0.024
30	154	95.718	95.748	-0.030
30	155	95.685	95.705	-0.020
30	156	95.652	95.677	-0.026
31	22	95.664	95.676	-0.013
31	23	95.652	95.672	-0.020
31	31	95.652	95.663	-0.011
31	37	95.702	95.713	-0.011
31	42	95.799	95.814	-0.015
50	173	95.721	95.704	0.017
50	174	95.645	95.624	0.021
50	175	95.725	95.714	0.011
50	183	95.725	95.710	0.015
50	187	95.690	95.675	0.015
51	43	95.579	95.600	-0.021
51	45	95.658	95.682	-0.024
51	48	95.712	95.728	-0.016
51	49	95.628	95.650	-0.021
51	50	95.674	95.691	-0.016
100	191	95.721	95.681	0.040
100	195	95.645	95.590	0.055
100	199	95.725	95.693	0.033
100	203	95.725	95.684	0.041
100	207	95.690	95.653	0.037
101	69	95.720	95.752	-0.032
101	70	95.686	95.717	-0.031
101	71	95.701	95.747	-0.046
101	74	95.672	95.700	-0.028
101	76	95.720	95.759	-0.039
101	81	95.690	95.725	-0.035
101	82	95.695	95.743	-0.048
101	85	95.619	95.643	-0.023
101	94	95.643	95.681	-0.038
101	95	95.691	95.729	-0.038
101	99	95.607	95.642	-0.035
101	103	95.636	95.692	-0.056
101	109	95.667	95.707	-0.040
101	110	95.625	95.671	-0.046
101	112	95.611	95.642	-0.031
101	115	95.689	95.721	-0.033
101	117	95.703	95.734	-0.031
101	118	95.699	95.729	-0.030
101	122	95.652	95.678	-0.026
101	125	95.695	95.720	-0.025
101	126	95.652	95.677	-0.025
101	129	95.751	95.791	-0.040
	Max	95.799	95.814	0.055
	Average	95.684	95.702	-0.019
	Min	95.579	95.590	-0.101
	Std Dev	0.044	0.049	0.028



	1030.11_ Max Duty Cycle	
Test Site		
Tester		
Test Number		
Max Limit	100	%
Min Limit	94.7	%

krad	3 biased	3 unbiased	10 biased	10 unbiased	30 biased	30 unbiased	50 biased	50 unbiased	100 biased	100 unbiased
LL	94.700	94.700	94.700	94.700	94.700	94.700	94.700	94.700	94.700	94.700
Min	95.636	95.635	95.691	95.618	95.678	95.664	95.624	95.600	95.590	95.642
Average	95.707	95.684	95.768	95.697	95.714	95.708	95.685	95.670	95.660	95.709
Max	95.775	95.752	95.804	95.766	95.749	95.814	95.714	95.728	95.693	95.791
UL	100.000	100.000	100.000	100.000	100.000	100.000	100.000	100.000	100.000	100.000

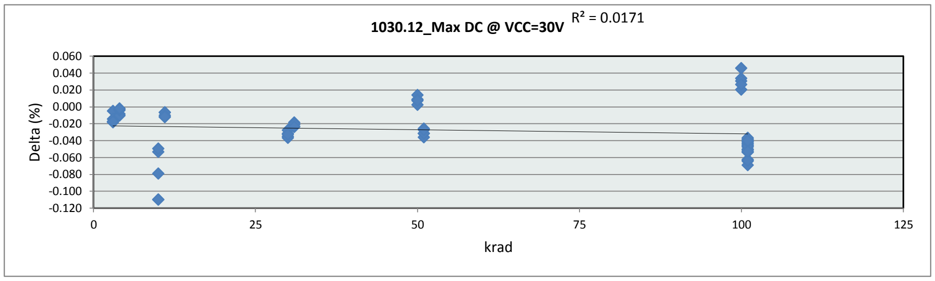


TID Report
Device Name

1030.12_Max DC @ VC

Test Site		
Tester		
Test Number		
Unit	%	%
Max Limit	100	100
Min Limit	94.7	94.7

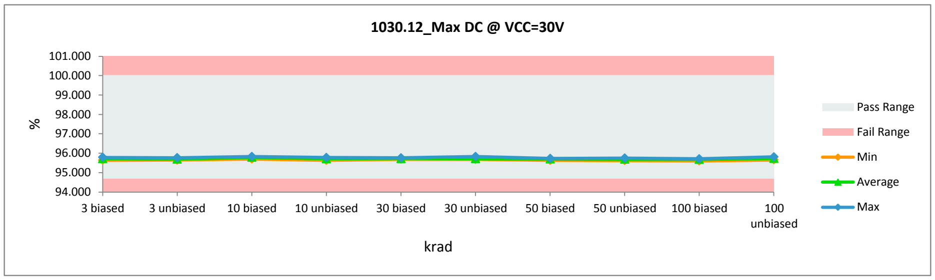
krad	Serial #	Pre	Post	Delta
3	135	95.725	95.730	-0.005
3	136	95.721	95.736	-0.014
3	138	95.619	95.637	-0.018
3	139	95.668	95.685	-0.017
3	143	95.768	95.786	-0.018
4	1	95.766	95.769	-0.003
4	2	95.633	95.642	-0.008
4	3	95.726	95.737	-0.010
4	5	95.650	95.654	-0.004
4	7	95.651	95.653	-0.002
10	144	95.710	95.820	-0.110
10	145	95.716	95.826	-0.110
10	146	95.745	95.799	-0.053
10	149	95.727	95.777	-0.049
10	150	95.619	95.698	-0.079
11	8	95.707	95.714	-0.007
11	11	95.627	95.633	-0.006
11	14	95.737	95.747	-0.010
11	15	95.765	95.777	-0.012
11	19	95.649	95.661	-0.012
30	151	95.705	95.740	-0.035
30	153	95.690	95.722	-0.032
30	154	95.726	95.763	-0.037
30	155	95.683	95.711	-0.028
30	156	95.652	95.685	-0.033
31	22	95.665	95.686	-0.021
31	23	95.665	95.688	-0.023
31	31	95.657	95.675	-0.019
31	37	95.705	95.725	-0.020
31	42	95.809	95.833	-0.024
50	173	95.727	95.718	0.009
50	174	95.646	95.632	0.014
50	175	95.733	95.731	0.002
50	183	95.736	95.728	0.009
50	187	95.695	95.688	0.007
51	43	95.586	95.617	-0.031
51	45	95.653	95.689	-0.036
51	48	95.723	95.749	-0.026
51	49	95.641	95.672	-0.031
51	50	95.683	95.710	-0.027
100	191	95.727	95.693	0.034
100	195	95.646	95.600	0.046
100	199	95.733	95.713	0.020
100	203	95.736	95.705	0.031
100	207	95.695	95.669	0.026
101	69	95.728	95.772	-0.045
101	70	95.698	95.741	-0.043
101	71	95.702	95.764	-0.062
101	74	95.675	95.718	-0.043
101	76	95.727	95.777	-0.050
101	81	95.699	95.746	-0.047
101	82	95.693	95.757	-0.064
101	85	95.618	95.656	-0.038
101	94	95.646	95.700	-0.054
101	95	95.699	95.750	-0.051
101	99	95.608	95.660	-0.051
101	103	95.646	95.715	-0.069
101	109	95.675	95.729	-0.053
101	110	95.621	95.685	-0.064
101	112	95.612	95.658	-0.046
101	115	95.699	95.745	-0.046
101	117	95.718	95.759	-0.041
101	118	95.711	95.752	-0.041
101	122	95.664	95.703	-0.039
101	125	95.699	95.736	-0.037
101	126	95.651	95.691	-0.040
101	129	95.760	95.813	-0.053
	Max	95.809	95.833	0.046
	Average	95.690	95.717	-0.028
	Min	95.586	95.600	-0.110
	Std Dev	0.046	0.052	0.030



1030.12_ Max DC @ VCC=30V

Test Site		
Tester		
Test Number		
Max Limit	100	%
Min Limit	94.7	%

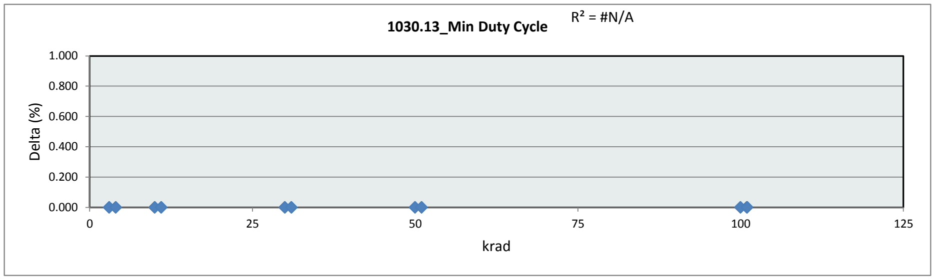
krad	3 biased	3 unbiased	10 biased	10 unbiased	30 biased	30 unbiased	50 biased	50 unbiased	100 biased	100 unbiased
LL	94.700	94.700	94.700	94.700	94.700	94.700	94.700	94.700	94.700	94.700
Min	95.638	95.642	95.698	95.633	95.685	95.676	95.632	95.617	95.600	95.656
Average	95.715	95.691	95.784	95.707	95.724	95.722	95.699	95.687	95.676	95.729
Max	95.786	95.769	95.826	95.777	95.763	95.833	95.731	95.749	95.713	95.813
UL	100.000	100.000	100.000	100.000	100.000	100.000	100.000	100.000	100.000	100.000



TID Report
Device Name

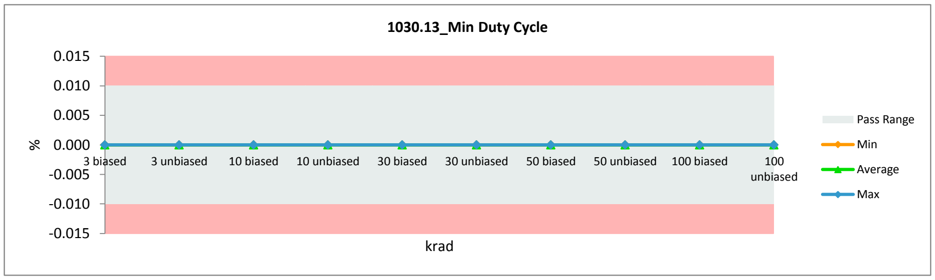
	1030.13_Min Duty Cyc	
Test Site		
Tester		
Test Number		
Unit	%	%
Max Limit	0.01	0.01
Min Limit	-0.01	-0.01

krad	Serial #	Pre	Post	Delta
3	135	0.000	0.000	0.000
3	136	0.000	0.000	0.000
3	138	0.000	0.000	0.000
3	139	0.000	0.000	0.000
3	143	0.000	0.000	0.000
4	1	0.000	0.000	0.000
4	2	0.000	0.000	0.000
4	3	0.000	0.000	0.000
4	5	0.000	0.000	0.000
4	7	0.000	0.000	0.000
10	144	0.000	0.000	0.000
10	145	0.000	0.000	0.000
10	146	0.000	0.000	0.000
10	149	0.000	0.000	0.000
10	150	0.000	0.000	0.000
11	8	0.000	0.000	0.000
11	11	0.000	0.000	0.000
11	14	0.000	0.000	0.000
11	15	0.000	0.000	0.000
11	19	0.000	0.000	0.000
30	151	0.000	0.000	0.000
30	153	0.000	0.000	0.000
30	154	0.000	0.000	0.000
30	155	0.000	0.000	0.000
30	156	0.000	0.000	0.000
31	22	0.000	0.000	0.000
31	23	0.000	0.000	0.000
31	31	0.000	0.000	0.000
31	37	0.000	0.000	0.000
31	42	0.000	0.000	0.000
50	173	0.000	0.000	0.000
50	174	0.000	0.000	0.000
50	175	0.000	0.000	0.000
50	183	0.000	0.000	0.000
50	187	0.000	0.000	0.000
51	43	0.000	0.000	0.000
51	45	0.000	0.000	0.000
51	48	0.000	0.000	0.000
51	49	0.000	0.000	0.000
51	50	0.000	0.000	0.000
100	191	0.000	0.000	0.000
100	195	0.000	0.000	0.000
100	199	0.000	0.000	0.000
100	203	0.000	0.000	0.000
100	207	0.000	0.000	0.000
101	69	0.000	0.000	0.000
101	70	0.000	0.000	0.000
101	71	0.000	0.000	0.000
101	74	0.000	0.000	0.000
101	76	0.000	0.000	0.000
101	81	0.000	0.000	0.000
101	82	0.000	0.000	0.000
101	85	0.000	0.000	0.000
101	94	0.000	0.000	0.000
101	95	0.000	0.000	0.000
101	99	0.000	0.000	0.000
101	103	0.000	0.000	0.000
101	109	0.000	0.000	0.000
101	110	0.000	0.000	0.000
101	112	0.000	0.000	0.000
101	115	0.000	0.000	0.000
101	117	0.000	0.000	0.000
101	118	0.000	0.000	0.000
101	122	0.000	0.000	0.000
101	125	0.000	0.000	0.000
101	126	0.000	0.000	0.000
101	129	0.000	0.000	0.000
	Max	0.000	0.000	0.000
	Average	0.000	0.000	0.000
	Min	0.000	0.000	0.000
	Std Dev	0.000	0.000	0.000



	1030.13_ Min Duty Cycle	
Test Site		
Tester		
Test Number		
Max Limit	0.01	%
Min Limit	-0.01	%

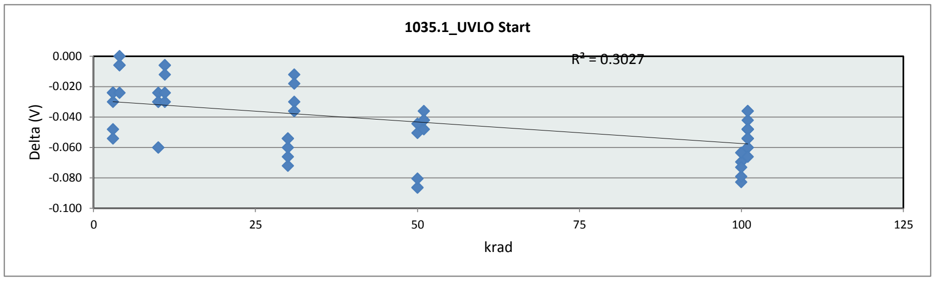
krad	3 biased	3 unbiased	10 biased	10 unbiased	30 biased	30 unbiased	50 biased	50 unbiased	100 biased	100 unbiased
LL	-0.010	-0.010	-0.010	-0.010	-0.010	-0.010	-0.010	-0.010	-0.010	-0.010
Min	0.000	0.000	0.000	0.000	0.000	0.000	0.000	0.000	0.000	0.000
Average	0.000	0.000	0.000	0.000	0.000	0.000	0.000	0.000	0.000	0.000
Max	0.000	0.000	0.000	0.000	0.000	0.000	0.000	0.000	0.000	0.000
UL	0.010	0.010	0.010	0.010	0.010	0.010	0.010	0.010	0.010	0.010



TID Report
Device Name

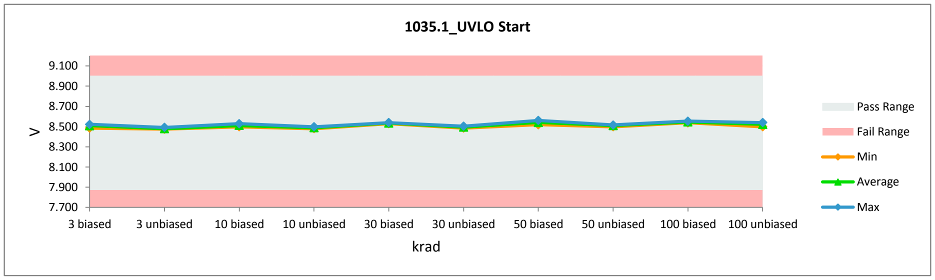
	1035.1_UVLO Start	
Test Site		
Tester		
Test Number		
Unit	V	V
Max Limit	8.93	8.93
Min Limit	7.87	7.87

krad	Serial #	Pre	Post	Delta
3	135	8.456	8.486	-0.030
3	136	8.486	8.510	-0.024
3	138	8.474	8.522	-0.048
3	139	8.480	8.504	-0.024
3	143	8.468	8.522	-0.054
4	1	8.468	8.492	-0.024
4	2	8.474	8.480	-0.006
4	3	8.468	8.474	-0.006
4	5	8.468	8.474	-0.006
4	7	8.474	8.474	0.000
10	144	8.474	8.498	-0.024
10	145	8.474	8.504	-0.030
10	146	8.468	8.498	-0.030
10	149	8.468	8.528	-0.060
10	150	8.468	8.528	-0.060
11	8	8.480	8.486	-0.006
11	11	8.468	8.498	-0.030
11	14	8.474	8.480	-0.006
11	15	8.462	8.486	-0.024
11	19	8.480	8.492	-0.012
30	151	8.468	8.540	-0.072
30	153	8.474	8.540	-0.066
30	154	8.474	8.534	-0.060
30	155	8.474	8.528	-0.054
30	156	8.480	8.534	-0.054
31	22	8.474	8.486	-0.012
31	23	8.474	8.492	-0.018
31	31	8.462	8.498	-0.036
31	37	8.462	8.492	-0.030
31	42	8.468	8.504	-0.036
50	173	8.468	8.554	-0.086
50	174	8.468	8.555	-0.087
50	175	8.474	8.518	-0.044
50	183	8.480	8.560	-0.081
50	187	8.468	8.518	-0.050
51	43	8.462	8.504	-0.042
51	45	8.468	8.516	-0.048
51	48	8.480	8.516	-0.036
51	49	8.474	8.516	-0.042
51	50	8.456	8.498	-0.042
100	191	8.468	8.551	-0.083
100	195	8.468	8.538	-0.070
100	199	8.474	8.553	-0.079
100	203	8.480	8.543	-0.064
100	207	8.468	8.541	-0.073
101	69	8.462	8.522	-0.060
101	70	8.474	8.528	-0.054
101	71	8.480	8.528	-0.048
101	74	8.462	8.498	-0.036
101	76	8.474	8.516	-0.042
101	81	8.474	8.522	-0.048
101	82	8.468	8.516	-0.048
101	85	8.480	8.534	-0.054
101	94	8.474	8.510	-0.036
101	95	8.474	8.522	-0.048
101	99	8.468	8.522	-0.054
101	103	8.468	8.528	-0.060
101	109	8.480	8.534	-0.054
101	110	8.492	8.540	-0.048
101	112	8.468	8.522	-0.054
101	115	8.468	8.516	-0.048
101	117	8.462	8.510	-0.048
101	118	8.462	8.516	-0.054
101	122	8.468	8.516	-0.048
101	125	8.468	8.522	-0.054
101	126	8.474	8.528	-0.054
101	129	8.468	8.534	-0.066
	Max	8.492	8.560	0.000
	Average	8.471	8.516	-0.045
	Min	8.456	8.474	-0.087
	Std Dev	0.007	0.022	0.021



	1035.1_UVLO Start	
Test Site		
Tester		
Test Number		
Max Limit	8.93	V
Min Limit	7.87	V

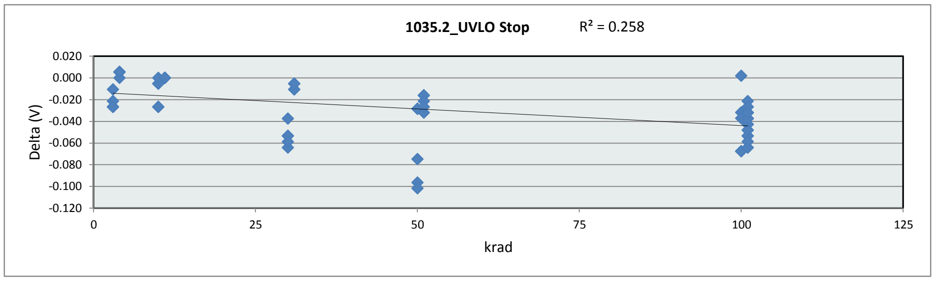
krad	3 biased	3 unbiased	10 biased	10 unbiased	30 biased	30 unbiased	50 biased	50 unbiased	100 biased	100 unbiased
LL	7.870	7.870	7.870	7.870	7.870	7.870	7.870	7.870	7.870	7.870
Min	8.486	8.474	8.498	8.480	8.528	8.486	8.518	8.498	8.538	8.498
Average	8.509	8.479	8.511	8.488	8.535	8.494	8.541	8.510	8.545	8.522
Max	8.522	8.492	8.528	8.498	8.540	8.504	8.560	8.516	8.553	8.540
UL	9.000	9.000	9.000	9.000	9.000	9.000	9.000	9.000	9.000	9.000



TID Report
Device Name

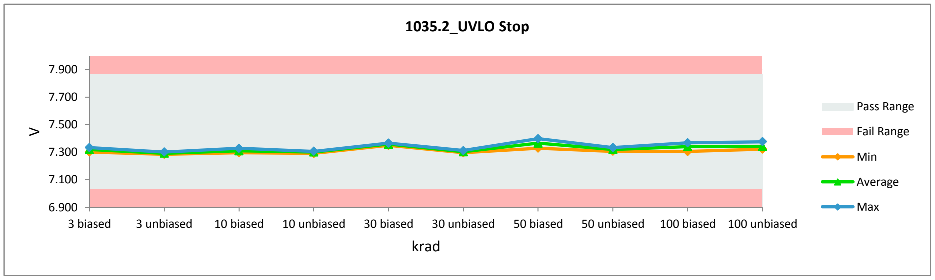
	1035.2_UVLO Stop	
Test Site		
Tester		
Test Number		
Unit	V	V
Max Limit	7.865	7.865
Min Limit	7.035	7.035

krad	Serial #	Pre	Post	Delta
3	135	7.280	7.301	-0.021
3	136	7.296	7.323	-0.027
3	138	7.301	7.328	-0.027
3	139	7.301	7.312	-0.011
3	143	7.307	7.333	-0.027
4	1	7.307	7.301	0.005
4	2	7.296	7.296	0.000
4	3	7.291	7.285	0.005
4	5	7.296	7.291	0.005
4	7	7.296	7.291	0.005
10	144	7.291	7.296	-0.005
10	145	7.296	7.301	-0.005
10	146	7.296	7.296	0.000
10	149	7.301	7.328	-0.027
10	150	7.301	7.328	-0.027
11	8	7.301	7.301	0.000
11	11	7.301	7.301	0.000
11	14	7.291	7.291	0.000
11	15	7.307	7.307	0.000
11	19	7.307	7.307	0.000
30	151	7.296	7.350	-0.054
30	153	7.301	7.366	-0.064
30	154	7.307	7.360	-0.053
30	155	7.307	7.366	-0.059
30	156	7.312	7.350	-0.038
31	22	7.296	7.307	-0.011
31	23	7.296	7.301	-0.005
31	31	7.291	7.296	-0.005
31	37	7.291	7.301	-0.011
31	42	7.307	7.312	-0.005
50	173	7.307	7.382	-0.075
50	174	7.301	7.330	-0.028
50	175	7.301	7.398	-0.096
50	183	7.301	7.330	-0.028
50	187	7.291	7.392	-0.102
51	43	7.291	7.307	-0.016
51	45	7.301	7.333	-0.032
51	48	7.301	7.317	-0.016
51	49	7.301	7.323	-0.021
51	50	7.296	7.323	-0.027
100	191	7.307	7.305	0.002
100	195	7.301	7.333	-0.032
100	199	7.301	7.369	-0.068
100	203	7.301	7.339	-0.037
100	207	7.291	7.358	-0.068
101	69	7.296	7.344	-0.048
101	70	7.307	7.350	-0.043
101	71	7.301	7.366	-0.064
101	74	7.291	7.328	-0.038
101	76	7.307	7.344	-0.037
101	81	7.307	7.339	-0.032
101	82	7.291	7.344	-0.054
101	85	7.301	7.339	-0.037
101	94	7.296	7.339	-0.043
101	95	7.307	7.339	-0.032
101	99	7.301	7.339	-0.037
101	103	7.301	7.355	-0.054
101	109	7.307	7.344	-0.037
101	110	7.312	7.376	-0.064
101	112	7.307	7.344	-0.037
101	115	7.301	7.333	-0.032
101	117	7.307	7.328	-0.021
101	118	7.296	7.323	-0.027
101	122	7.296	7.323	-0.027
101	125	7.296	7.328	-0.032
101	126	7.301	7.350	-0.048
101	129	7.296	7.355	-0.059
	Max	7.312	7.398	0.005
	Average	7.300	7.330	-0.030
	Min	7.280	7.285	-0.102
	Std Dev	0.006	0.026	0.025



	1035.2_UVLO Stop	
Test Site		
Tester		
Test Number		
Max Limit	7.865	V
Min Limit	7.035	V

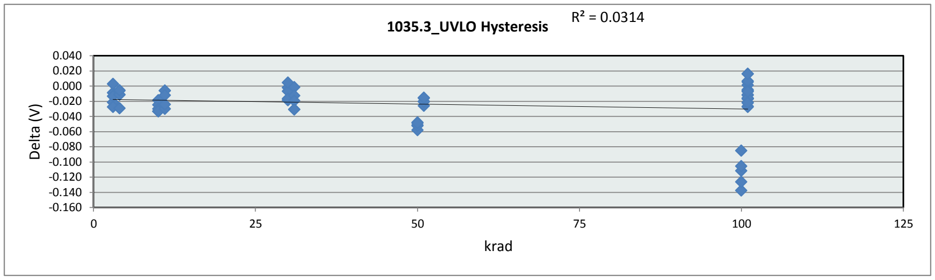
krad	3 biased	3 unbiased	10 biased	10 unbiased	30 biased	30 unbiased	50 biased	50 unbiased	100 biased	100 unbiased
LL	7.035	7.035	7.035	7.035	7.035	7.035	7.035	7.035	7.035	7.035
Min	7.301	7.285	7.296	7.291	7.350	7.296	7.330	7.307	7.305	7.323
Average	7.320	7.293	7.310	7.301	7.358	7.303	7.366	7.321	7.341	7.342
Max	7.333	7.301	7.328	7.307	7.366	7.312	7.398	7.333	7.369	7.376
UL	7.865	7.865	7.865	7.865	7.865	7.865	7.865	7.865	7.865	7.865



TID Report
Device Name

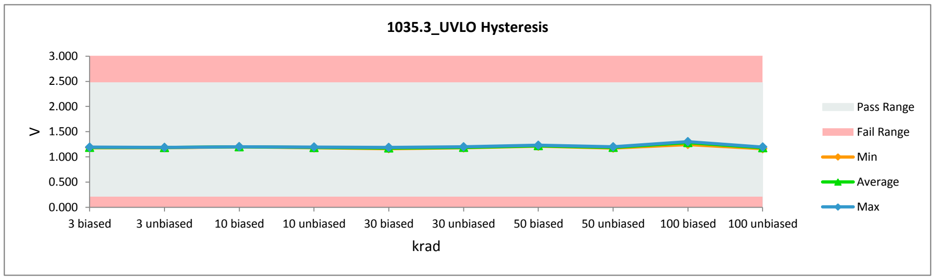
	1035.3_UVLO Hysteres	
Test Site		
Tester		
Test Number		
Unit	V	V
Max Limit	2.475	2.475
Min Limit	0.21	0.21

krad	Serial #	Pre	Post	Delta
3	135	1.176	1.185	-0.009
3	136	1.190	1.187	0.003
3	138	1.173	1.194	-0.021
3	139	1.179	1.192	-0.013
3	143	1.161	1.189	-0.027
4	1	1.161	1.191	-0.029
4	2	1.178	1.184	-0.006
4	3	1.177	1.189	-0.011
4	5	1.172	1.183	-0.011
4	7	1.178	1.183	-0.005
10	144	1.183	1.202	-0.019
10	145	1.178	1.203	-0.025
10	146	1.172	1.202	-0.030
10	149	1.167	1.200	-0.033
10	150	1.167	1.200	-0.033
11	8	1.179	1.185	-0.006
11	11	1.167	1.197	-0.030
11	14	1.183	1.189	-0.006
11	15	1.155	1.179	-0.024
11	19	1.173	1.185	-0.012
30	151	1.172	1.191	-0.019
30	153	1.173	1.175	-0.002
30	154	1.167	1.174	-0.007
30	155	1.167	1.163	0.005
30	156	1.168	1.185	-0.017
31	22	1.178	1.179	-0.001
31	23	1.178	1.191	-0.013
31	31	1.171	1.202	-0.031
31	37	1.171	1.191	-0.019
31	42	1.161	1.192	-0.031
50	173	1.161	1.213	-0.051
50	174	1.167	1.225	-0.058
50	175	1.173	1.221	-0.048
50	183	1.179	1.231	-0.052
50	187	1.177	1.226	-0.049
51	43	1.171	1.197	-0.026
51	45	1.167	1.183	-0.016
51	48	1.179	1.199	-0.020
51	49	1.173	1.193	-0.021
51	50	1.160	1.175	-0.015
100	191	1.161	1.246	-0.085
100	195	1.167	1.304	-0.138
100	199	1.173	1.284	-0.112
100	203	1.179	1.305	-0.126
100	207	1.177	1.283	-0.106
101	69	1.166	1.178	-0.012
101	70	1.167	1.179	-0.011
101	71	1.179	1.163	0.016
101	74	1.171	1.170	0.001
101	76	1.167	1.172	-0.005
101	81	1.167	1.183	-0.016
101	82	1.177	1.172	0.005
101	85	1.179	1.195	-0.017
101	94	1.178	1.171	0.007
101	95	1.167	1.183	-0.016
101	99	1.167	1.183	-0.017
101	103	1.167	1.173	-0.007
101	109	1.173	1.190	-0.017
101	110	1.180	1.164	0.016
101	112	1.161	1.178	-0.017
101	115	1.167	1.183	-0.016
101	117	1.155	1.182	-0.027
101	118	1.166	1.193	-0.027
101	122	1.172	1.193	-0.021
101	125	1.172	1.194	-0.022
101	126	1.173	1.179	-0.006
101	129	1.172	1.179	-0.007
	Max	1.190	1.305	0.016
	Average	1.171	1.196	-0.024
	Min	1.155	1.163	-0.138
	Std Dev	0.007	0.030	0.030



	1035.3_UVLO Hysteresis	
Test Site		
Tester		
Test Number		
Max Limit	2.475	V
Min Limit	0.21	V

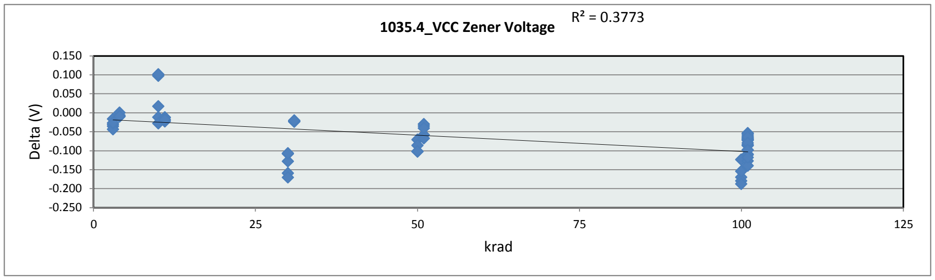
krad	3 biased	3 unbiased	10 biased	10 unbiased	30 biased	30 unbiased	50 biased	50 unbiased	100 biased	100 unbiased
LL	0.210	0.210	0.210	0.210	0.210	0.210	0.210	0.210	0.210	0.210
Min	1.185	1.183	1.200	1.179	1.163	1.179	1.213	1.175	1.246	1.163
Average	1.189	1.186	1.201	1.187	1.177	1.191	1.223	1.189	1.285	1.180
Max	1.194	1.191	1.203	1.197	1.191	1.202	1.231	1.199	1.305	1.195
UL	2.475	2.475	2.475	2.475	2.475	2.475	2.475	2.475	2.475	2.475



TID Report
Device Name

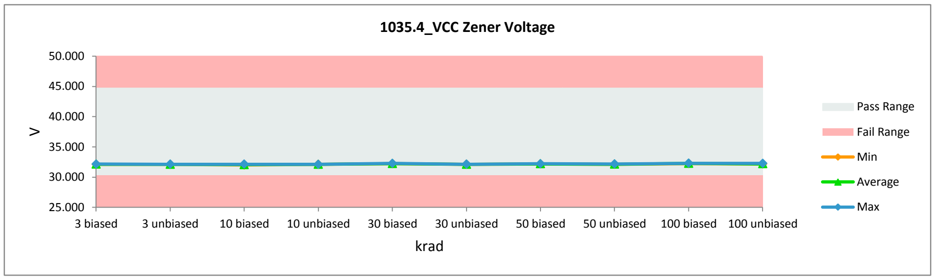
	1035.4_VCC Zener Vol	
Test Site		
Tester		
Test Number		
Unit	V	V
Max Limit	44.7	44.7
Min Limit	30.3	30.3

krad	Serial #	Pre	Post	Delta
3	135	32.078	32.114	-0.036
3	136	32.100	32.131	-0.031
3	138	32.113	32.156	-0.043
3	139	32.110	32.126	-0.017
3	143	32.094	32.121	-0.027
4	1	32.127	32.137	-0.010
4	2	32.115	32.122	-0.007
4	3	32.095	32.094	0.000
4	5	32.093	32.103	-0.010
4	7	32.087	32.096	-0.009
10	144	32.095	31.998	0.097
10	145	32.096	31.995	0.101
10	146	32.093	32.105	-0.012
10	149	32.103	32.131	-0.028
10	150	32.109	32.092	0.017
11	8	32.092	32.111	-0.020
11	11	32.102	32.125	-0.023
11	14	32.092	32.104	-0.012
11	15	32.101	32.113	-0.012
11	19	32.102	32.120	-0.018
30	151	32.104	32.212	-0.108
30	153	32.105	32.265	-0.160
30	154	32.094	32.222	-0.128
30	155	32.112	32.283	-0.170
30	156	32.093	32.200	-0.107
31	22	32.090	32.113	-0.023
31	23	32.096	32.119	-0.024
31	31	32.096	32.117	-0.021
31	37	32.089	32.112	-0.023
31	42	32.110	32.131	-0.020
50	173	32.097	32.200	-0.102
50	174	32.102	32.204	-0.102
50	175	32.104	32.175	-0.071
50	183	32.096	32.182	-0.086
50	187	32.101	32.202	-0.102
51	43	32.097	32.132	-0.035
51	45	32.108	32.167	-0.058
51	48	32.096	32.126	-0.030
51	49	32.100	32.141	-0.041
51	50	32.083	32.150	-0.067
100	191	32.097	32.268	-0.170
100	195	32.102	32.281	-0.180
100	199	32.104	32.228	-0.124
100	203	32.096	32.250	-0.154
100	207	32.101	32.289	-0.188
101	69	32.084	32.195	-0.111
101	70	32.116	32.202	-0.086
101	71	32.105	32.232	-0.127
101	74	32.096	32.168	-0.072
101	76	32.115	32.213	-0.098
101	81	32.117	32.171	-0.054
101	82	32.116	32.202	-0.086
101	85	32.118	32.184	-0.066
101	94	32.112	32.181	-0.069
101	95	32.125	32.186	-0.061
101	99	32.117	32.171	-0.054
101	103	32.112	32.222	-0.110
101	109	32.122	32.207	-0.084
101	110	32.140	32.280	-0.140
101	112	32.112	32.184	-0.072
101	115	32.102	32.172	-0.070
101	117	32.104	32.161	-0.057
101	118	32.097	32.166	-0.069
101	122	32.103	32.167	-0.064
101	125	32.094	32.174	-0.080
101	126	32.096	32.194	-0.098
101	129	32.096	32.214	-0.118
	Max	32.140	32.289	0.101
	Average	32.102	32.166	-0.063
	Min	32.078	31.995	-0.188
	Std Dev	0.011	0.060	0.057



	1035.4_VCC Zener Voltage	
Test Site		
Tester		
Test Number		
Max Limit	44.7	V
Min Limit	30.3	V

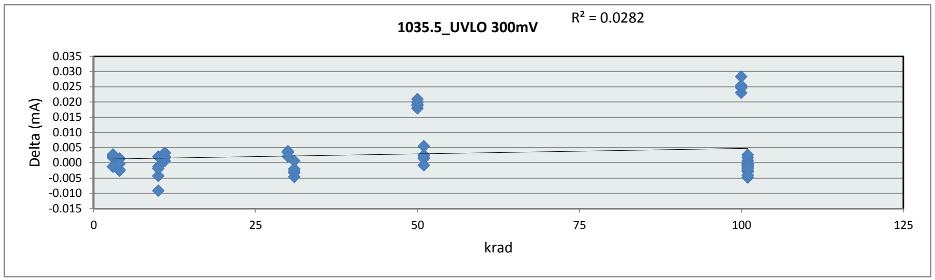
krad	3 biased	3 unbiased	10 biased	10 unbiased	30 biased	30 unbiased	50 biased	50 unbiased	100 biased	100 unbiased
LL	30.300	30.300	30.300	30.300	30.300	30.300	30.300	30.300	30.300	30.300
Min	32.114	32.094	31.995	32.104	32.200	32.112	32.175	32.126	32.228	32.161
Average	32.130	32.110	32.064	32.115	32.236	32.118	32.193	32.143	32.263	32.193
Max	32.156	32.137	32.131	32.125	32.283	32.131	32.204	32.167	32.289	32.280
UL	44.700	44.700	44.700	44.700	44.700	44.700	44.700	44.700	44.700	44.700



TID Report
Device Name

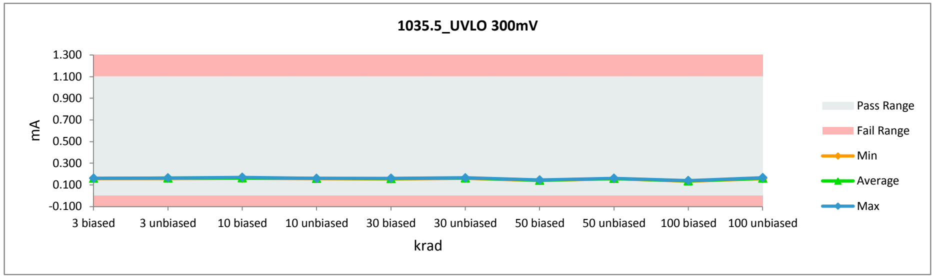
	1035.5_UVLO 300mV		
Test Site			
Tester			
Test Number			
Unit	mA	mA	
Max Limit	1.1	1.1	
Min Limit	0	0	

krad	Serial #	Pre	Post	Delta
3	135	0.162	0.161	0.002
3	136	0.161	0.159	0.002
3	138	0.164	0.161	0.003
3	139	0.160	0.161	-0.001
3	143	0.160	0.161	-0.001
4	1	0.159	0.162	-0.003
4	2	0.160	0.163	-0.002
4	3	0.160	0.159	0.001
4	5	0.165	0.163	0.001
4	7	0.164	0.164	0.000
10	144	0.160	0.165	-0.004
10	145	0.161	0.170	-0.009
10	146	0.162	0.163	-0.001
10	149	0.162	0.160	0.002
10	150	0.164	0.166	-0.002
11	8	0.161	0.158	0.003
11	11	0.161	0.159	0.002
11	14	0.163	0.160	0.003
11	15	0.158	0.158	0.001
11	19	0.161	0.160	0.002
30	151	0.162	0.159	0.003
30	153	0.160	0.156	0.003
30	154	0.159	0.155	0.004
30	155	0.162	0.158	0.003
30	156	0.163	0.161	0.002
31	22	0.161	0.164	-0.003
31	23	0.158	0.162	-0.003
31	31	0.160	0.165	-0.005
31	37	0.163	0.163	0.001
31	42	0.157	0.159	-0.002
50	173	0.164	0.146	0.018
50	174	0.164	0.143	0.021
50	175	0.160	0.140	0.019
50	183	0.161	0.142	0.019
50	187	0.159	0.139	0.020
51	43	0.162	0.161	0.001
51	45	0.164	0.158	0.005
51	48	0.159	0.160	-0.001
51	49	0.161	0.159	0.002
51	50	0.159	0.156	0.002
100	191	0.164	0.141	0.023
100	195	0.164	0.135	0.028
100	199	0.160	0.135	0.025
100	203	0.161	0.135	0.025
100	207	0.159	0.134	0.025
101	69	0.159	0.162	-0.003
101	70	0.159	0.160	0.000
101	71	0.160	0.161	-0.001
101	74	0.157	0.158	-0.001
101	76	0.159	0.159	0.000
101	81	0.160	0.162	-0.002
101	82	0.160	0.161	-0.001
101	85	0.162	0.166	-0.004
101	94	0.161	0.162	-0.001
101	95	0.162	0.164	-0.003
101	99	0.163	0.164	-0.002
101	103	0.158	0.159	-0.001
101	109	0.157	0.162	-0.005
101	110	0.160	0.161	-0.001
101	112	0.164	0.163	0.001
101	115	0.161	0.161	0.000
101	117	0.159	0.160	-0.001
101	118	0.158	0.160	-0.002
101	122	0.161	0.162	-0.002
101	125	0.166	0.164	0.002
101	126	0.162	0.166	-0.004
101	129	0.161	0.158	0.003
	Max	0.166	0.170	0.028
	Average	0.161	0.158	0.003
	Min	0.157	0.134	-0.009
	Std Dev	0.002	0.008	0.009



	1035.5_UVLO 300mV	
Test Site		
Tester		
Test Number		
Max Limit	1.1	mA
Min Limit	0	mA

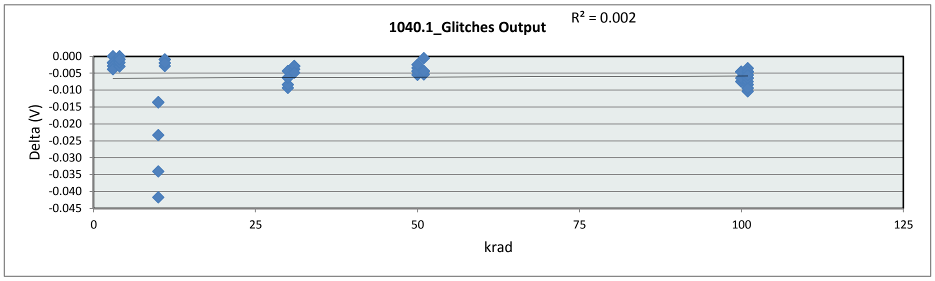
krad	3 biased	3 unbiased	10 biased	10 unbiased	30 biased	30 unbiased	50 biased	50 unbiased	100 biased	100 unbiased
LL	0.000	0.000	0.000	0.000	0.000	0.000	0.000	0.000	0.000	0.000
Min	0.159	0.159	0.160	0.158	0.156	0.159	0.139	0.156	0.134	0.158
Average	0.160	0.162	0.165	0.159	0.158	0.162	0.142	0.159	0.136	0.162
Max	0.161	0.164	0.171	0.160	0.161	0.165	0.146	0.161	0.141	0.166
UL	1.100	1.100	1.100	1.100	1.100	1.100	1.100	1.100	1.100	1.100



TID Report
Device Name

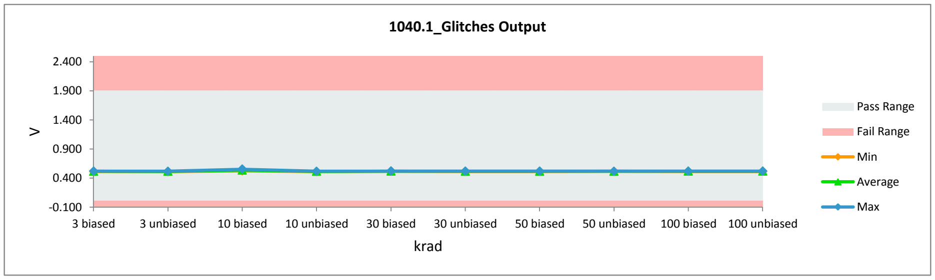
	1040.1_Glitches Outpu	
Test Site		
Tester		
Test Number		
Unit	V	V
Max Limit	1.9	1.9
Min Limit	0.01	0.01

krad	Serial #	Pre	Post	Delta
3	135	0.515	0.515	0.000
3	136	0.516	0.518	-0.002
3	138	0.514	0.516	-0.002
3	139	0.517	0.520	-0.003
3	143	0.514	0.518	-0.004
4	1	0.517	0.517	0.000
4	2	0.515	0.516	-0.001
4	3	0.514	0.517	-0.003
4	5	0.513	0.515	-0.002
4	7	0.513	0.514	-0.001
10	144	0.515	0.549	-0.034
10	145	0.513	0.555	-0.042
10	146	0.513	0.527	-0.014
10	149	0.511	0.525	-0.014
10	150	0.511	0.534	-0.023
11	8	0.516	0.517	-0.001
11	11	0.514	0.515	-0.001
11	14	0.515	0.518	-0.003
11	15	0.514	0.516	-0.002
11	19	0.514	0.516	-0.002
30	151	0.511	0.520	-0.009
30	153	0.513	0.517	-0.004
30	154	0.514	0.522	-0.008
30	155	0.515	0.521	-0.006
30	156	0.513	0.519	-0.006
31	22	0.515	0.518	-0.003
31	23	0.514	0.517	-0.003
31	31	0.512	0.516	-0.004
31	37	0.513	0.516	-0.003
31	42	0.514	0.519	-0.005
50	173	0.512	0.516	-0.003
50	174	0.512	0.516	-0.004
50	175	0.514	0.519	-0.006
50	183	0.513	0.517	-0.004
50	187	0.516	0.518	-0.002
51	43	0.513	0.517	-0.004
51	45	0.513	0.518	-0.005
51	48	0.513	0.517	-0.004
51	49	0.514	0.518	-0.005
51	50	0.518	0.518	-0.001
100	191	0.512	0.517	-0.005
100	195	0.512	0.517	-0.005
100	199	0.514	0.521	-0.007
100	203	0.513	0.520	-0.007
100	207	0.516	0.521	-0.005
101	69	0.514	0.518	-0.005
101	70	0.515	0.520	-0.005
101	71	0.515	0.521	-0.006
101	74	0.515	0.520	-0.005
101	76	0.513	0.520	-0.007
101	81	0.512	0.518	-0.006
101	82	0.512	0.521	-0.009
101	85	0.510	0.516	-0.006
101	94	0.512	0.518	-0.006
101	95	0.509	0.517	-0.008
101	99	0.509	0.517	-0.008
101	103	0.511	0.521	-0.010
101	109	0.511	0.518	-0.007
101	110	0.511	0.521	-0.010
101	112	0.511	0.517	-0.007
101	115	0.513	0.518	-0.005
101	117	0.514	0.518	-0.005
101	118	0.514	0.517	-0.004
101	122	0.514	0.517	-0.004
101	125	0.512	0.517	-0.005
101	126	0.512	0.517	-0.005
101	129	0.514	0.520	-0.006
	Max	0.518	0.555	0.000
	Average	0.513	0.519	-0.006
	Min	0.509	0.514	-0.042
	Std Dev	0.002	0.006	0.007



	1040.1_Glitches Output	
Test Site		
Tester		
Test Number		
Max Limit	1.9	V
Min Limit	0.01	V

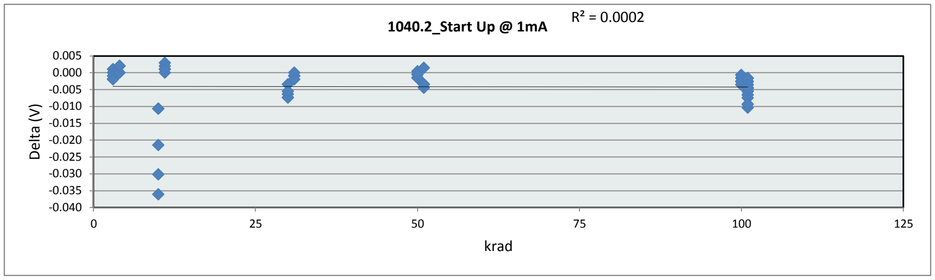
krad	3 biased	3 unbiased	10 biased	10 unbiased	30 biased	30 unbiased	50 biased	50 unbiased	100 biased	100 unbiased
LL	0.010	0.010	0.010	0.010	0.010	0.010	0.010	0.010	0.010	0.010
Min	0.515	0.514	0.525	0.515	0.517	0.516	0.516	0.517	0.517	0.516
Average	0.517	0.516	0.538	0.516	0.520	0.517	0.517	0.518	0.519	0.519
Max	0.520	0.517	0.555	0.518	0.522	0.519	0.519	0.518	0.521	0.521
UL	1.900	1.900	1.900	1.900	1.900	1.900	1.900	1.900	1.900	1.900



TID Report
Device Name

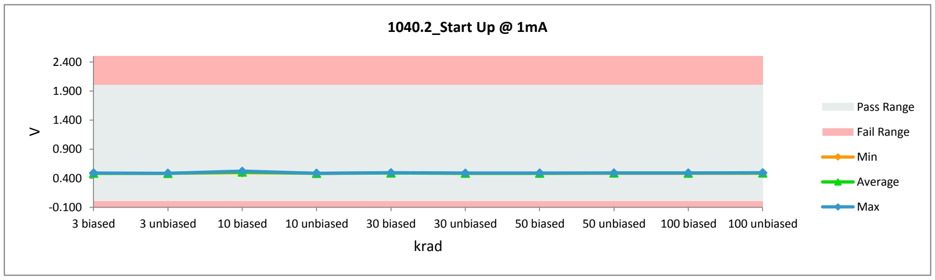
	1040.2_Start Up @ 1m	
Test Site		
Tester		
Test Number		
Unit	V	V
Max Limit	2	2
Min Limit	0	0

krad	Serial #	Pre	Post	Delta
3	135	0.486	0.485	0.001
3	136	0.486	0.488	-0.002
3	138	0.484	0.484	0.000
3	139	0.488	0.489	-0.001
3	143	0.485	0.487	-0.002
4	1	0.487	0.485	0.002
4	2	0.486	0.484	0.002
4	3	0.484	0.484	0.000
4	5	0.483	0.483	0.000
4	7	0.484	0.482	0.002
10	144	0.486	0.516	-0.030
10	145	0.484	0.520	-0.036
10	146	0.483	0.493	-0.011
10	149	0.483	0.493	-0.011
10	150	0.480	0.501	-0.021
11	8	0.486	0.483	0.003
11	11	0.484	0.482	0.002
11	14	0.486	0.485	0.001
11	15	0.484	0.484	0.000
11	19	0.486	0.485	0.001
30	151	0.482	0.488	-0.006
30	153	0.484	0.487	-0.003
30	154	0.484	0.491	-0.007
30	155	0.485	0.492	-0.007
30	156	0.484	0.489	-0.005
31	22	0.485	0.486	-0.001
31	23	0.484	0.485	-0.001
31	31	0.482	0.483	-0.001
31	37	0.484	0.484	0.000
31	42	0.485	0.487	-0.002
50	173	0.484	0.483	0.000
50	174	0.483	0.484	-0.001
50	175	0.486	0.486	-0.001
50	183	0.485	0.486	-0.002
50	187	0.487	0.487	0.000
51	43	0.482	0.486	-0.005
51	45	0.485	0.488	-0.004
51	48	0.484	0.487	-0.003
51	49	0.485	0.488	-0.004
51	50	0.489	0.487	0.001
100	191	0.484	0.484	-0.001
100	195	0.483	0.484	-0.002
100	199	0.486	0.488	-0.003
100	203	0.485	0.488	-0.004
100	207	0.487	0.489	-0.003
101	69	0.485	0.489	-0.005
101	70	0.486	0.487	-0.002
101	71	0.485	0.492	-0.007
101	74	0.486	0.488	-0.003
101	76	0.484	0.488	-0.005
101	81	0.484	0.487	-0.004
101	82	0.482	0.492	-0.010
101	85	0.480	0.485	-0.006
101	94	0.483	0.488	-0.005
101	95	0.480	0.486	-0.007
101	99	0.480	0.486	-0.007
101	103	0.482	0.491	-0.009
101	109	0.482	0.487	-0.006
101	110	0.483	0.492	-0.009
101	112	0.483	0.487	-0.005
101	115	0.484	0.486	-0.003
101	117	0.484	0.488	-0.005
101	118	0.485	0.487	-0.003
101	122	0.485	0.486	-0.002
101	125	0.483	0.486	-0.004
101	126	0.483	0.487	-0.005
101	129	0.485	0.489	-0.005
	Max	0.489	0.520	0.003
	Average	0.484	0.488	-0.004
	Min	0.480	0.482	-0.036
	Std Dev	0.002	0.006	0.007



	1040.2_Start Up @ 1mA	
Test Site		
Tester		
Test Number		
Max Limit	2	V
Min Limit	0	V

krad	3 biased	3 unbiased	10 biased	10 unbiased	30 biased	30 unbiased	50 biased	50 unbiased	100 biased	100 unbiased
LL	0.000	0.000	0.000	0.000	0.000	0.000	0.000	0.000	0.000	0.000
Min	0.484	0.482	0.494	0.482	0.487	0.483	0.483	0.486	0.484	0.485
Average	0.486	0.483	0.505	0.484	0.490	0.485	0.485	0.487	0.487	0.488
Max	0.489	0.485	0.520	0.485	0.492	0.487	0.487	0.488	0.489	0.492
UL	2.000	2.000	2.000	2.000	2.000	2.000	2.000	2.000	2.000	2.000



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